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MEASUREMENT REPORT
FCC Part 22, 24 LTE

Applicant Name:
Samsung Electronics, Co. Ltd.
129, Samsung-ro, Maetan dong,
Yeongtong-gu, Suwon-si
Gyeonggi-do 443-742, Korea

Date of Testing:
02/08 - 02/14/2014
Test Site/Location:
PCTEST Lab., Columbia, MD, USA
Test Report Serial No.:
0Y1402030278.A3L

FCC ID : A3LSMG900F

APPLICANT: SAMSUNG ELECTRONICS, CO. LTD.

Application Type: Certification
Model(s): SM-G900F, SM-G900FQ
EUT Type: Portable Handset
FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)
FCC Rule Part(s): §2; §22; §24
Test Procedure(s): ANSI/TIA-603-C-2004, KDB 971168 v02r01
Test Device Serial No.: *identical prototype* [S/N: 15E9F]

Mode	Tx Frequency (MHz)	Emission Designator	Modulation	ERP/EIRP	
				Max. Power (W)	Max. Power (dBm)
LTE Band 5	824.7 - 848.3	1M11G7D	QPSK	0.115	20.59
LTE Band 5	824.7 - 848.3	1M12W7D	16QAM	0.093	19.70
LTE Band 5	825.5 - 847.5	2M74G7D	QPSK	0.120	20.80
LTE Band 5	825.5 - 847.5	2M73W7D	16QAM	0.094	19.73
LTE Band 5	826.5 - 846.5	4M50G7D	QPSK	0.098	19.90
LTE Band 5	826.5 - 846.5	4M51W7D	16QAM	0.078	18.89
LTE Band 5	829 - 844	8M98G7D	QPSK	0.112	20.50
LTE Band 5	829 - 844	8M98W7D	16QAM	0.094	19.72
LTE Band 2	1850.7 - 1909.3	1M11G7D	QPSK	0.146	21.65
LTE Band 2	1850.7 - 1909.3	1M12W7D	16QAM	0.116	20.63
LTE Band 2	1851.5 - 1908.5	2M74G7D	QPSK	0.240	23.81
LTE Band 2	1851.5 - 1908.5	2M72W7D	16QAM	0.196	22.92
LTE Band 2	1852.5 - 1907.5	4M51G7D	QPSK	0.218	23.39
LTE Band 2	1852.5 - 1907.5	4M52W7D	16QAM	0.171	22.32
LTE Band 2	1855 - 1905	8M97G7D	QPSK	0.229	23.59
LTE Band 2	1855 - 1905	8M99W7D	16QAM	0.179	22.53
LTE Band 2	1857.5 - 1902.5	13M5G7D	QPSK	0.138	21.39
LTE Band 2	1857.5 - 1902.5	13M5W7D	16QAM	0.112	20.49
LTE Band 2	1860 - 1900	18M0G7D	QPSK	0.136	21.35
LTE Band 2	1860 - 1900	17M9W7D	16QAM	0.112	20.48

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested. I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez
President

ACCREDITED
TESTING LABORATORY
CERTIFICATE #2041.01

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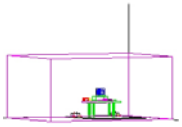

MEASUREMENT REPORT
FCC Part 22, 24

§2.1033 General Information

APPLICANT:	Samsung Electronics, Co. Ltd.
APPLICANT ADDRESS:	129, Samsung-ro, Maetan dong,
	Yeongtong-gu, Suwon-si, Gyeonggi-do 443-742, Korea
TEST SITE:	PCTEST ENGINEERING LABORATORY, INC.
TEST SITE ADDRESS:	7185 Oakland Mills Road, Columbia, MD 21045 USA
FCC RULE PART(S):	§2; §22; §24
BASE MODEL:	SM-G900F
FCC ID:	A3LSMG900F
FCC CLASSIFICATION:	PCS Licensed Transmitter Held to Ear (PCE)
FREQUENCY TOLERANCE:	±0.00025 % (2.5 ppm)
Test Device Serial No.:	15E9F ☐ Production ☒ Pre-Production ☐ Engineering
DATE(S) OF TEST:	02/08 - 02/14/2014
TEST REPORT S/N:	0Y1402030278.A3L

Test Facility / Accreditations

Measurements were performed at PCTEST Engineering Lab located in Columbia, MD 21046, U.S.A.

- PCTEST facility is an FCC registered (PCTEST Reg. No. 159966) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (2451B-1).
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST Lab is accredited to ISO 17025-2005 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, Hearing Aid Compatibility (HAC) testing, CTIA Test Plans, and wireless testing for FCC and Industry Canada Rules.
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and Industry Canada Standards (RSS).
- PCTEST facility is an IC registered (2451B-1) test laboratory with the site description on file at Industry Canada.
- PCTEST is a CTIA Authorized Test Laboratory (CATL) for AMPS, CDMA, and EvDO wireless devices and for Over-the-Air (OTA) Antenna Performance testing for AMPS, CDMA, GSM, GPRS, EGPRS, UMTS (W-CDMA), CDMA 1xEVDO, and CDMA 1xRTT.

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1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EME) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Industry Canada Certification and Engineering Bureau.

1.2 Testing Facility

The map below shows the location of the PCTEST LABORATORY, its proximity to the FCC Laboratory, the Columbia vicinity, the Baltimore-Washington Internt'l (BWI) airport, the city of Baltimore and the Washington, DC area. (*See Figure 1-1*).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The site coordinates are 39° 10'23" N latitude and 76° 49'50" W longitude. The facility is 0.4 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2003 on February 15, 2012.

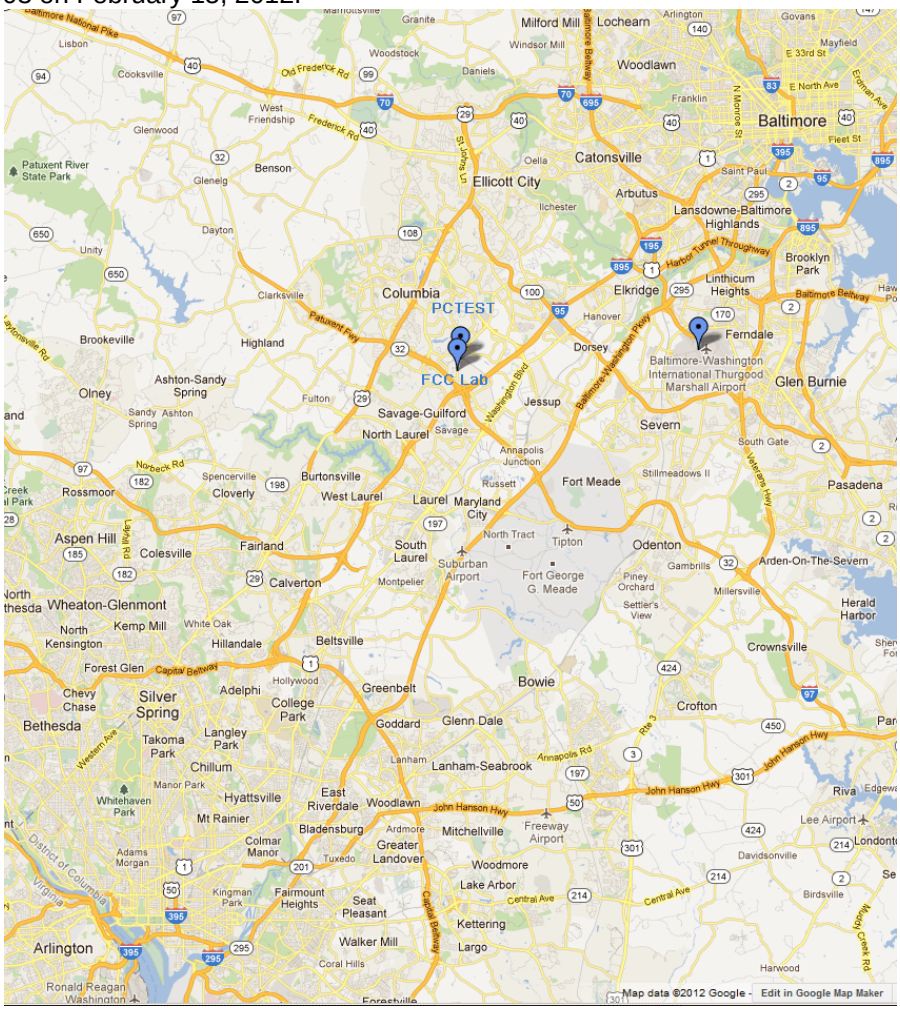

Figure 1-1. Map of the Greater Baltimore and Metropolitan Washington, D.C. area

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2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSMG900F**. The test data contained in this report pertains only to the emissions due to the EUT's LTE function.

2.2 Device Capabilities

This device contains the following capabilities:

850/1900 GSM/GPRS/EDGE, 850/1900 WCDMA/HSPA, Band 2 LTE (1.4, 3, 5, 10, 15, 20MHz BW), Band 5 LTE (1.4, 3, 5, 10MHz BW), 802.11a/b/g/n/ac WLAN (DTS/NII), Bluetooth (1x,EDR, LE), NFC, ANT+

2.3 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

2.4 Labeling Requirements

Per 2.925

The FCC identifier shall be permanently affixed to the equipment and shall be readily visible to the purchaser at the time of purchase.

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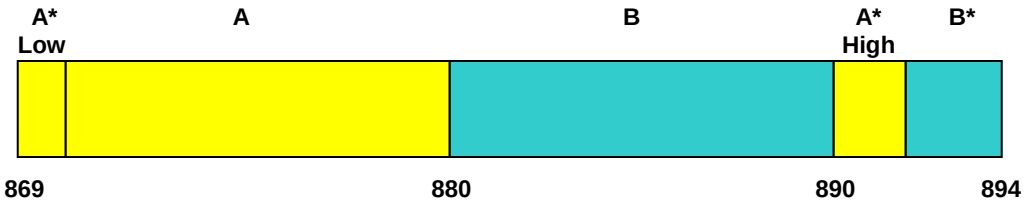
3.0 DESCRIPTION OF TESTS

3.1 Measurement Procedure

The measurement procedures described in the document titled "Land Mobile FM or PM – Communications Equipment – Measurements and Performance Standards" (ANSI/TIA-603-C-2004) and "Procedures for Compliance Measurement of the Fundamental Emission Power of Licensed Wideband (> 1 MHz) Digital Transmission Systems" (KDB 971168) were used in the measurement of the **Samsung Portable Handset FCC ID: A3LSMG900F.**

3.2 Cellular - Base Frequency Blocks

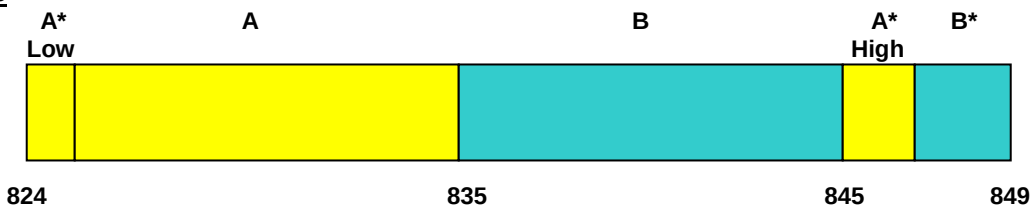
§22.905



BLOCK 1: 869 – 880 MHz (A* Low + A)
BLOCK 2: 880 – 890 MHz (B)
BLOCK 3: 890 – 891.5 MHz (A* High)
BLOCK 4: 891.5 – 894 MHz (B*)

3.3 Cellular - Mobile Frequency Blocks

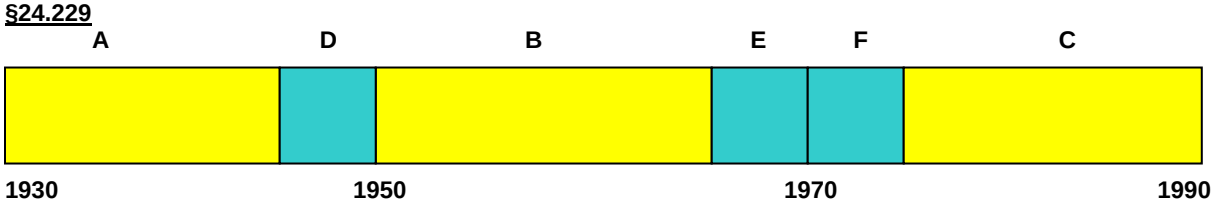
§22.905



BLOCK 1: 824 – 835 MHz (A* Low + A)
BLOCK 2: 835 – 845 MHz (B)
BLOCK 3: 845 – 846.5 MHz (A* High)
BLOCK 4: 846.5 – 849 MHz (B*)

3.4 PCS - Base Frequency Blocks

§24.229



BLOCK 1: 1930 – 1945 MHz (A)
BLOCK 2: 1945 – 1950 MHz (D)
BLOCK 3: 1950 – 1965 MHz (B)
BLOCK 4: 1965 – 1970 MHz (E)
BLOCK 5: 1970 – 1975 MHz (F)
BLOCK 6: 1975 – 1990 MHz (C)

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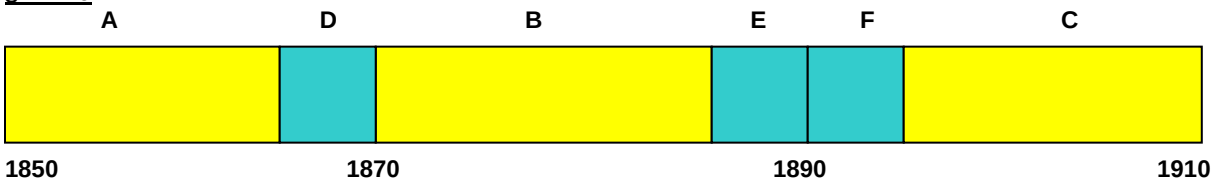
3.5 PCS - Mobile Frequency Blocks

§24.229



BLOCK 1: 1850 – 1865 MHz (A)
BLOCK 2: 1865 – 1870 MHz (D)
BLOCK 3: 1870 – 1885 MHz (B)
BLOCK 4: 1885 – 1890 MHz (E)
BLOCK 5: 1890 – 1895 MHz (F)
BLOCK 6: 1895 – 1910 MHz (C)

3.6 Occupied Bandwidth

§2.1049 RSS-Gen(4.6.1) RSS-133(2.3)

The implementation of this test is performed by the spectrum analyzer's occupied bandwidth function. The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured.

3.7 Spurious and Harmonic Emissions at Antenna Terminal

§2.1051 §22.917(a)(b) §24.238(a)(b) RSS-132(4.5.1) RSS-133(6.5.1)

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. On any frequency outside a licensee's frequency block, the power of any emission shall be attenuated below the transmitter power (P) by at least 43 + 10 log(P) dB. Compliance with these provisions is based on the use of measurement instrumentation employing a resolution bandwidth of 100 kHz or greater for Cell band, or 1 MHz or greater for PCS band,. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed for PCS band,. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

3.8 Peak-Average Ratio

§24.232(d) RSS-132(5.4) RSS-133(6.4)

A peak to average ratio measurement is performed at the conducted port of the EUT. For LTE signals, the spectrum analyzers Complementary Cumulative Distribution Function (CCDF) measurement profile is used to determine the largest deviation between the average and the peak power of the EUT in a given bandwidth. The CCDF curve shows how much time the peak waveform spends at or above a given average power level. The percent of time the signal spends at or above the level defines the probability for that particular power level.

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3.9 Radiated Power and Radiated Spurious Emissions

§2.1053 §22.913(a.2) §22.917(a) §24.232(c) §24.238(a) RSS-132(4.4) RSS-132(4.5.1) RSS-133(6.4) RSS-133(6.5.1)

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. For measurements above 1GHz absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections. For measurements below 1GHz, the absorbers are removed. An ETS Lindgren Model 2188 raised turntable is used for radiated measurement. It is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. A 78cm high PVC support structure is placed on top of the turntable. A ¾" (~1.9cm) sheet of high density polyethylene is used as the table top and is placed on top of the PVC supports to bring the total height of the table to 80cm.

The equipment under test was transmitting while connected to its integral antenna and is placed on a wooden turntable 80cm above the ground plane and 3 meters from the receive antenna. The receive antenna height is adjusted between 1 and 4 meter height, the turntable is rotated through 360 degrees, and the EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer. Radiated power levels are also investigated with the receive antenna horizontally and vertically polarized. The maximized power level is recorded using the spectrum analyzer "Channel Power" function with the integration band set to the emissions' occupied bandwidth, a RMS detector, RBW = 100kHz, VBW = 300kHz, and a 1 second sweep time over a minimum of 10 sweeps, per the guidelines of KDB 971168.

Per the guidance of ANSI/TIA-603-C-2004, a half-wave dipole is then substituted in place of the EUT. For emissions above 1GHz, a horn antenna is substituted in place of the EUT. The substitute antenna is driven by a signal generator with the level of the signal generator being adjusted to obtain the same receive spectrum analyzer level previously recorded from the spurious emission from the EUT. The power of the emission is calculated using the following formula:

$$P_{d\ [dBm]} = P_{g\ [dBm]} - \text{cable loss}_{\ [dB]} + \text{antenna gain}_{\ [dBd/dBi]}$$

Where, P_d is the dipole equivalent power, P_g is the generator output into the substitution antenna, and the antenna gain is the gain of the substitute antenna used relative to either a half-wave dipole (dBd) or an isotropic source (dBi). The substitute level is equal to $P_{g\ [dBm]}$ – cable loss $_{[dB]}$.

The calculated P_d levels are then compared to the absolute spurious emission limit of -13dBm which is equivalent to the required minimum attenuation of 43 + $10\log_{10}$(Power $_{[Watts]}$) specified in 22.917(a) and 24.238(a).

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3.10 Frequency Stability / Temperature Variation

§2.1055 §22.863 §22.905 §24.229 §24.235 RSS-132(4.3) RSS-133(6.3)

The frequency stability of the transmitter is measured by:

a.) **Temperature:** The temperature is varied from -30°C to +50°C in 10°C increments using an environmental chamber.

b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

Specification – The frequency stability shall be sufficient to ensure that the fundamental emission stays within the authorized frequency block for Part 24 and 27. The frequency stability of the transmitter shall be maintained within ±0.00025% (±2.5 ppm) of the center frequency for Part 22.

Time Period and Procedure:

1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).

2. The equipment is turned on in a "standby" condition for one minute before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.

3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A sufficient stabilization period at each temperature shall be used prior to each frequency requirement.

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4.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST).

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	LTx1	Licensed Transmitter Cable Set	1/29/2014	Annual	1/29/2015	N/A
-	RE1	Radiated Emissions Cable Set (UHF/EHF)	3/29/2013	Annual	3/29/2014	N/A
-	RE2	Radiated Emissions Cable Set (VHF/UHF)	3/29/2013	Annual	3/29/2014	N/A
Agilent	8447D	Broadband Amplifier	5/31/2013	Annual	5/31/2014	2443A01900
Agilent	E8267C	Vector Signal Generator	10/31/2013	Biennial	10/31/2015	US42340152
Agilent	N9020A	MXA Signal Analyzer	10/29/2013	Annual	10/29/2014	US46470561
Com-Power	AL-130	9kHz - 30MHz Loop Antenna	6/26/2013	Annual	6/26/2014	121034
Espec	ESX-2CA	Environmental Chamber	4/16/2013	Annual	4/16/2014	17620
ETS Lindgren	3117	1-18 GHz DRG Horn (Medium)	7/24/2013	Biennial	7/24/2015	125518
ETS Lindgren	3160-09	18-26.5 GHz Standard Gain Horn	5/30/2012	Biennial	5/30/2014	135427
ETS Lindgren	3164-08	Quad Ridge Horn Antenna	11/7/2012	Biennial	11/7/2014	128338
Mini-Circuits	VHF-1200+	High Pass Filter	1/27/2014	Annual	1/27/2015	30923
Mini-Circuits	VHF-3100+	High Pass Filter	1/27/2014	Annual	1/27/2015	30841
Mini-Circuits	SSG-4000HP	USB Synthesized Signal Generator	N/A			11208010032
Mini-Circuits	PWR-SENS-4RMS	USB Power Sensor	4/17/2013	Annual	4/17/2014	11210140001
Mini-Circuits	TVA-11-422	RF Power Amp	N/A			QA1303002
Rohde & Schwarz	CMU200	Base Station Simulator	N/A			836536/0005
Rohde & Schwarz	CMW500	LTE Radio Communication Tester	10/16/2013	Annual	10/16/2014	100976
Rohde & Schwarz	TS-PR18	1-18 GHz Pre-Amplifier	5/31/2013	Annual	5/31/2014	100071
Rohde & Schwarz	TS-PR26	18-26.5 GHz Pre-Amplifier	5/31/2013	Annual	5/31/2014	100040
Rohde & Schwarz	ESU26	EMI Test Receiver (26.5GHz)	1/27/2014	Annual	1/27/2015	100342
Schwarzbeck	UHA 9105	Dipole Antenna (400 - 1GHz) Rx	11/21/2013	Biennial	11/21/2015	9105-2404
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	1/28/2014	Biennial	1/28/2016	A051107

Table 4-1. Test Equipment

Notes:

Equipment used for signaling with a calibration date of "N/A" shown in this list was only used for maintaining a link between the piece of equipment and the EUT. This equipment was not used to make direct calibrated measurements.

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5.0 SAMPLE CALCULATIONS

Emission Designator

QPSK Modulation

Emission Designator = 8M62G7D

LTE BW = 8.62 MHz
G = Phase Modulation
7 = Quantized/Digital Info
D = Amplitude/Angle Modulated

16QAM Modulation

Emission Designator = 8M45W7D

LTE BW = 8.45 MHz
W = Amplitude/Angle Modulated
7 = Quantized/Digital Info
D = Combination (Audio/Data)

Spurious Radiated Emission – LTE Band

Example: Middle Channel LTE Mode 2nd Harmonic (1564 MHz)

The average spectrum analyzer reading at 3 meters with the EUT on the turntable was –81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of –81.0 dBm on the spectrum analzyer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 1564 MHz. So 6.1 dB is added to the signal generator reading of –30.9 dBm yielding –24.80 dBm. The fundamental EIRP was 25.501 dBm so this harmonic was 25.501 dBm – (-24.80).

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6.0 TEST RESULTS

6.1 Summary

Company Name: Samsung Electronics, Co. Ltd.
FCC ID: A3LSMG900F
FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)
Mode(s): LTE

FCC Part Section(s)	Test Description	Test Limit	Test Condition	Result	Reference
TRANSMITTER MODE (TX)					
2.1049	Occupied Bandwidth	N/A	CONDUCTED	PASS	Section, 7.0, 8.0
2.1051 22.917(a) 24.238(a)	Band Edge / Conducted Spurious Emissions	> 43 + 10log$_{10}$ (P[Watts]) at Band Edge and for all out-of-band emissions		PASS	Section, 7.0, 8.0
24.232(d)	Peak-Average Ratio	< 13 dB		PASS	Section 8.0
2.1046	Transmitter Conducted Output Power	N/A		PASS	See RF Exposure Report
22.913(a.2)	Effective Radiated Power (Band 5)	< 7 Watts max. ERP	RADIATED	PASS	Section 6.2
24.232(c)	Equivalent Isotropic Radiated Power (Band 2)	< 2 Watts max. EIRP		PASS	Section 6.3
2.1053 22.917(a) 24.238(a)	Undesirable Emissions	> 43 + 10log$_{10}$ (P[Watts]) for all out-of-band emissions		PASS	Section, 6.4, 6.5
2.1055. 22.355 24.235	Frequency Stability	< 2.5 ppm (Part 22) and fundamental emissions stay within authorized frequency block (Part 24, 27)		PASS	Section, 6.6, 6.7

Table 6-1. Summary of Test Results

Notes:

1) All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.
2) The analyzer plots shown in Section 7.0 8.0 were all taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables, directional couplers, and attenuators used as part of the system to maintain a link between the call box and the EUT at all frequencies of interest.
3) All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables, attenuators, and couplers.
4) For conducted spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is PCTEST "2G/3G Automation", Version 1.8.

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6.2 Effective Radiated Power (ERP)

§22.913(a.2) RSS-132(4.4)

Frequency [MHz]	Channel Bandwidth [MHz]	Mod.	Battery	RB Size/Offset	Substitute Level [dBm]	Antenna Gain [dBd]	Pol [H/V]	ERP [dBm]	ERP [Watts]	Margin [dB]
824.70	1.4	QPSK	Standard	1/5	15.18	4.59	V	19.77	0.095	-18.68
836.50	1.4	QPSK	Standard	1/0	15.77	4.82	V	**20.59**	**0.115**	-17.86
848.30	1.4	QPSK	Standard	1/0	14.81	5.05	V	19.86	0.097	-18.59
824.70	1.4	16-QAM	Standard	1/5	14.30	4.59	V	18.89	0.078	-19.56
836.50	1.4	16-QAM	Standard	1/0	14.88	4.82	V	**19.70**	**0.093**	-18.75
848.30	1.4	16-QAM	Standard	1/0	13.90	5.05	V	18.95	0.078	-19.50
825.50	3	QPSK	Standard	1/14	15.53	4.59	V	20.12	0.103	-18.33
836.50	3	QPSK	Standard	1/0	15.98	4.82	V	**20.80**	**0.120**	-17.65
847.50	3	QPSK	Standard	1/0	15.00	5.05	V	20.05	0.101	-18.40
825.50	3	16-QAM	Standard	1/14	14.67	4.59	V	19.26	0.084	-19.19
836.50	3	16-QAM	Standard	1/0	14.91	4.82	V	**19.73**	**0.094**	-18.72
847.50	3	16-QAM	Standard	1/0	14.15	5.05	V	19.20	0.083	-19.25
826.50	5	QPSK	Standard	1/24	15.01	4.59	V	19.60	0.091	-18.85
836.50	5	QPSK	Standard	1/0	15.08	4.82	V	**19.90**	**0.098**	-18.55
846.50	5	QPSK	Standard	1/0	14.71	5.05	V	19.76	0.095	-18.69
826.50	5	16-QAM	Standard	1/24	13.95	4.59	V	18.54	0.072	-19.91
836.50	5	16-QAM	Standard	1/0	14.07	4.82	V	**18.89**	**0.078**	-19.56
846.50	5	16-QAM	Standard	1/0	13.63	5.05	V	18.68	0.074	-19.77
829.00	10	QPSK	Standard	1/49	15.45	4.59	V	20.04	0.101	-18.41
836.50	10	QPSK	Standard	1/0	15.45	4.82	V	20.27	0.107	-18.18
844.00	10	QPSK	Standard	1/0	15.45	5.05	V	**20.50**	**0.112**	-17.95
829.00	10	16-QAM	Standard	1/49	14.63	4.59	V	19.22	0.084	-19.23
836.50	10	16-QAM	Standard	1/0	14.37	4.82	V	19.19	0.083	-19.26
844.00	10	16-QAM	Standard	1/0	14.67	5.05	V	**19.72**	**0.094**	-18.73

Table 6-2. ERP Data (Band 5)

NOTES:

1. This device was tested under all bandwidths, and RB configurations, and modulations. This device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with QPSK modulation while using 1RB with 0 RB offset.

2. This unit was tested with its standard battery.

3. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The “H” positioning is defined with the EUT lying flat on the test surface, the “H2” positioning is defined with the EUT standing up on its side, and the “V” positioning is defined with the EUT standing upright. The worst case test configuration was found in the EUT in the [V] position for Band 5 operation and in the [H2] position for Band 2 operation. The data reported in the table above was measured in this test setup.

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6.3 Equivalent Isotropic Radiated Power (EIRP)

§24.232(c) RSS-133(6.4)

Frequency [MHz]	Channel Bandwidth [MHz]	Mod.	Battery	RB Size/Offset	Substitute Level [dBm]	Antenna Gain [dBi]	Pol [H/V]	EIRP [dBm]	EIRP [Watts]	Margin [dB]
1850.70	1.4	QPSK	Standard	1/5	11.86	9.59	H2	21.45	0.140	-11.56
1880.00	1.4	QPSK	Standard	1/0	12.12	9.53	H2	**21.65**	**0.146**	-11.36
1909.30	1.4	QPSK	Standard	1/0	9.07	9.48	H2	18.55	0.072	-14.46
1850.70	1.4	16-QAM	Standard	1/5	10.78	9.59	H2	20.37	0.109	-12.64
1880.00	1.4	16-QAM	Standard	1/0	11.10	9.53	H2	**20.63**	**0.116**	-12.38
1909.30	1.4	16-QAM	Standard	1/0	8.34	9.48	H2	17.82	0.061	-15.19
1851.50	3	QPSK	Standard	1/0	14.22	9.59	H2	**23.81**	**0.240**	-9.20
1880.00	3	QPSK	Standard	1/0	14.22	9.53	H2	23.75	0.237	-9.26
1908.50	3	QPSK	Standard	1/0	11.42	9.48	H2	20.90	0.123	-12.11
1851.50	3	16-QAM	Standard	1/0	13.33	9.59	H2	**22.92**	**0.196**	-10.09
1880.00	3	16-QAM	Standard	1/0	13.18	9.53	H2	22.71	0.187	-10.30
1908.50	3	16-QAM	Standard	1/0	10.80	9.48	H2	20.28	0.107	-12.73
1852.50	5	QPSK	Standard	1/0	13.80	9.59	H2	**23.39**	**0.218**	-9.62
1880.00	5	QPSK	Standard	1/0	13.82	9.53	H2	23.35	0.216	-9.66
1907.50	5	QPSK	Standard	1/0	11.92	9.48	H2	21.40	0.138	-11.61
1852.50	5	16-QAM	Standard	1/0	12.73	9.59	H2	**22.32**	**0.171**	-10.69
1880.00	5	16-QAM	Standard	1/0	12.75	9.53	H2	22.28	0.169	-10.73
1907.50	5	16-QAM	Standard	1/0	11.21	9.48	H2	20.69	0.117	-12.32
1855.00	10	QPSK	Standard	1/0	13.82	9.59	H2	23.41	0.219	-9.60
1880.00	10	QPSK	Standard	1/0	14.06	9.53	H2	**23.59**	**0.229**	-9.42
1905.00	10	QPSK	Standard	1/0	13.09	9.48	H2	22.57	0.181	-10.44
1855.00	10	16-QAM	Standard	1/0	12.94	9.59	H2	**22.53**	**0.179**	-10.48
1880.00	10	16-QAM	Standard	1/0	12.90	9.53	H2	22.43	0.175	-10.58
1905.00	10	16-QAM	Standard	1/0	11.97	9.48	H2	21.45	0.140	-11.56
1857.50	15	QPSK	Standard	1/0	11.80	9.59	H2	**21.39**	**0.138**	-11.62
1880.00	15	QPSK	Standard	1/74	11.64	9.53	H2	21.17	0.131	-11.84
1902.50	15	QPSK	Standard	1/0	10.74	9.48	H2	20.22	0.105	-12.79
1857.50	15	16-QAM	Standard	1/0	10.90	9.59	H2	**20.49**	**0.112**	-12.52
1880.00	15	16-QAM	Standard	1/74	10.93	9.53	H2	20.46	0.111	-12.55
1902.50	15	16-QAM	Standard	1/0	9.83	9.48	H2	19.31	0.085	-13.70
1860.00	20	QPSK	Standard	1/0	11.76	9.59	H2	**21.35**	**0.136**	-11.66
1880.00	20	QPSK	Standard	50/25	11.39	9.53	H2	20.92	0.124	-12.09
1900.00	20	QPSK	Standard	1/0	11.76	9.48	H2	21.24	0.133	-11.77
1860.00	20	16-QAM	Standard	1/0	10.70	9.59	H2	20.29	0.107	-12.72
1880.00	20	16-QAM	Standard	50/25	10.33	9.53	H2	19.86	0.097	-13.15
1900.00	20	16-QAM	Standard	1/0	11.00	9.48	H2	**20.48**	**0.112**	-12.53

Table 6-3. EIRP Data (Band 2)

NOTES:

1. This device was tested under all bandwidths, and RB configurations, and modulations. This device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with QPSK modulation while using 1RB with 0 RB offset.

2. This unit was tested with its standard battery.

3. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The "H" positioning is defined with the EUT lying flat on the test surface, the "H2" positioning is defined with the EUT standing up on its side, and the "V" positioning is defined with the EUT standing upright. The worst case test configuration was found in the EUT in the [V] position for Band 5 operation and in the [H2] position for Band 2 operation. The data reported in the table above was measured in this test setup.

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6.4 Band 5 Radiated Spurious Emissions

§2.1053 §22.917(a) RSS-132(4.5.1)

Field Strength of SPURIOUS Radiation

OPERATING FREQUENCY:	825.50	MHz		
MEASURED OUTPUT POWER:	22.27	dBm	=	0.169 W
MODULATION SIGNAL:	QPSK			
BANDWIDTH:	3 MHz			
DISTANCE:	3	meters		
LIMIT:	43 + 10 $\log_{10}$ (W) =	35.27	dBc	

FREQUENCY (MHz)	LEVEL @ ANTENNA TERMINALS (dBm)	SUBSTITUTE ANTENNA GAIN (dBd)	SPURIOUS EMISSION LEVEL (dBm)	POL (H/V)	(dBc)
1651.00	-43.63	3.72	-39.91	V	62.18
2476.50	-47.95	3.61	-44.33	V	66.61
3302.00	-81.19	5.64	-75.54	V	97.82
4127.50	-81.17	6.94	-74.22	V	96.50
4953.00	-79.90	7.84	-72.06	V	94.34

Table 6-4. Radiated Spurious Data

NOTES:

1. This device was tested under all bandwidths, and RB configurations, and modulations. This device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with QPSK modulation while using 1RB with 0 RB offset.

2. This unit was tested with its standard battery.

3. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The “H” positioning is defined with the EUT lying flat on the test surface, the “H2” positioning is defined with the EUT standing up on its side, and the “V” positioning is defined with the EUT standing upright. The worst case test configuration was found in the EUT in the [V] position for Band 5 operation and in the [H2] position for Band 2 operation. The data reported in the table above was measured in this test setup.

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Band 5 Radiated Spurious Measurements (continued)

§2.1053 §22.917(a) RSS-132(4.5.1)

Field Strength of SPURIOUS Radiation

OPERATING FREQUENCY:	836.50	MHz		
MEASURED OUTPUT POWER:	22.95	dBm	=	0.197 W
MODULATION SIGNAL:	QPSK			
BANDWIDTH:	3 MHz			
DISTANCE:	3	meters		
LIMIT:	43 + 10 $\log_{10}$ (W) =	35.95	dBc	

FREQUENCY (MHz)	LEVEL @ ANTENNA TERMINALS (dBm)	SUBSTITUTE ANTENNA GAIN (dBd)	SPURIOUS EMISSION LEVEL (dBm)	POL (H/V)	(dBc)
1673.00	-38.68	3.67	-35.02	V	57.97
2509.50	-44.48	3.65	-40.83	V	63.79
3346.00	-81.28	5.74	-75.54	V	98.49
4182.50	-81.26	7.04	-74.22	V	97.18
5019.00	-79.82	7.90	-71.92	V	94.88

Table 6-5. Radiated Spurious Data

NOTES:

1. This device was tested under all bandwidths, and RB configurations, and modulations. This device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with QPSK modulation while using 1RB with 0 RB offset.

2. This unit was tested with its standard battery.

3. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The “H” positioning is defined with the EUT lying flat on the test surface, the “H2” positioning is defined with the EUT standing up on its side, and the “V” positioning is defined with the EUT standing upright. The worst case test configuration was found in the EUT in the [V] position for Band 5 operation and in the [H2] position for Band 2 operation. The data reported in the table above was measured in this test setup.

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Band 5 Radiated Spurious Measurements (continued)

§2.1053 §22.917(a) RSS-132(4.5.1)

Field Strength of SPURIOUS Radiation

OPERATING FREQUENCY:	847.50	MHz		
MEASURED OUTPUT POWER:	22.20	dBm	=	0.166 W
MODULATION SIGNAL:	QPSK			
BANDWIDTH:	3 MHz			
DISTANCE:	3	meters		
LIMIT:	43 + 10 $\log_{10}$ (W) =	35.20	dBc	

FREQUENCY (MHz)	LEVEL @ ANTENNA TERMINALS (dBm)	SUBSTITUTE ANTENNA GAIN (dBd)	SPURIOUS EMISSION LEVEL (dBm)	POL (H/V)	(dBc)
1695.00	-47.60	3.62	-43.99	V	66.18
2542.50	-54.01	3.72	-50.30	V	72.49
3390.00	-81.37	5.83	-75.53	V	97.73
4237.50	-81.30	7.11	-74.19	V	96.39
5085.00	-79.66	7.93	-71.73	V	93.93

Table 6-6. Radiated Spurious Data

NOTES:

1. This device was tested under all bandwidths, and RB configurations, and modulations. This device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with QPSK modulation while using 1RB with 0 RB offset.

2. This unit was tested with its standard battery.

3. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The “H” positioning is defined with the EUT lying flat on the test surface, the “H2” positioning is defined with the EUT standing up on its side, and the “V” positioning is defined with the EUT standing upright. The worst case test configuration was found in the EUT in the [V] position for Band 5 operation and in the [H2] position for Band 2 operation. The data reported in the table above was measured in this test setup.

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6.5 Band 2 Radiated Spurious Emissions

§2.1053 §24.238(a) RSS-133(6.5.1)

Field Strength of SPURIOUS Radiation

OPERATING FREQUENCY:	1851.50	MHz		
MEASURED OUTPUT POWER:	23.81	dBm	=	0.240 W
MODULATION SIGNAL:	QPSK			
BANDWIDTH:	3 MHz			
DISTANCE:	3	meters		
LIMIT:	43 + 10 $\log_{10}$ (W) =	36.81	dBc	

FREQUENCY (MHz)	LEVEL @ ANTENNA TERMINALS (dBm)	SUBSTITUTE ANTENNA GAIN (dBi)	SPURIOUS EMISSION LEVEL (dBm)	POL (H/V)	(dBc)
3703.00	-47.41	8.30	-39.11	H2	62.92
5554.50	-55.39	10.59	-44.80	H2	68.61
7406.00	-82.20	11.96	-70.24	H2	94.05
9257.50	-80.91	13.16	-67.75	H2	91.55
11109.00	-78.34	13.25	-65.09	H2	88.90

Table 6-7. Radiated Spurious Data

NOTES:

1. This device was tested under all bandwidths, and RB configurations, and modulations. This device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with QPSK modulation while using 1RB with 0 RB offset.

2. This unit was tested with its standard battery.

3. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The “H” positioning is defined with the EUT lying flat on the test surface, the “H2” positioning is defined with the EUT standing up on its side, and the “V” positioning is defined with the EUT standing upright. The worst case test configuration was found in the EUT in the [V] position for Band 5 operation and in the [H2] position for Band 2 operation. The data reported in the table above was measured in this test setup.

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Band 2 Radiated Spurious Measurements (continued)

§2.1053 §24.238(a) RSS-133(6.5.1)

Field Strength of SPURIOUS Radiation

OPERATING FREQUENCY:	1880.00	MHz		
MEASURED OUTPUT POWER:	23.75	dBm	=	0.237 W
MODULATION SIGNAL:	QPSK			
BANDWIDTH:	3 MHz			
DISTANCE:	3	meters		
LIMIT:	43 + 10 $\log_{10}$ (W) =	36.75	dBc	

FREQUENCY (MHz)	LEVEL @ ANTENNA TERMINALS (dBm)	SUBSTITUTE ANTENNA GAIN (dBi)	SPURIOUS EMISSION LEVEL (dBm)	POL (H/V)	(dBc)
3760.00	-44.24	8.32	-35.92	H2	59.67
5640.00	-59.95	10.67	-49.27	H2	73.03
7520.00	-82.14	12.05	-70.09	H2	93.84
9400.00	-80.73	13.16	-67.58	H2	91.33
11280.00	-78.10	13.32	-64.77	H2	88.53

Table 6-8. Radiated Spurious Data

NOTES:

1. This device was tested under all bandwidths, and RB configurations, and modulations. This device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with QPSK modulation while using 1RB with 0 RB offset.

2. This unit was tested with its standard battery.

3. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The “H” positioning is defined with the EUT lying flat on the test surface, the “H2” positioning is defined with the EUT standing up on its side, and the “V” positioning is defined with the EUT standing upright. The worst case test configuration was found in the EUT in the [V] position for Band 5 operation and in the [H2] position for Band 2 operation. The data reported in the table above was measured in this test setup.

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Band 2 Radiated Spurious Measurements (continued)

§2.1053 §24.238(a) RSS-133(6.5.1)

Field Strength of SPURIOUS Radiation

OPERATING FREQUENCY:	1908.50	MHz		
MEASURED OUTPUT POWER:	20.90	dBm	=	0.123 W
MODULATION SIGNAL:	QPSK			
BANDWIDTH:	3 MHz			
DISTANCE:	3	meters		
LIMIT:	43 + 10 $\log_{10}$ (W) =	33.90	dBc	

FREQUENCY (MHz)	LEVEL @ ANTENNA TERMINALS (dBm)	SUBSTITUTE ANTENNA GAIN (dBi)	SPURIOUS EMISSION LEVEL (dBm)	POL (H/V)	(dBc)
3817.00	-50.59	8.36	-42.23	H2	63.13
5725.50	-55.51	10.73	-44.78	H2	65.68
7634.00	-82.03	12.12	-69.91	H2	90.81
9542.50	-80.49	13.14	-67.35	H2	88.25
11451.00	-77.97	13.36	-64.62	H2	85.52

Table 6-9. Radiated Spurious Data

NOTES:

1. This device was tested under all bandwidths, and RB configurations, and modulations. This device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with QPSK modulation while using 1RB with 0 RB offset.

2. This unit was tested with its standard battery.

3. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The “H” positioning is defined with the EUT lying flat on the test surface, the “H2” positioning is defined with the EUT standing up on its side, and the “V” positioning is defined with the EUT standing upright. The worst case test configuration was found in the EUT in the [V] position for Band 5 operation and in the [H2] position for Band 2 operation. The data reported in the table above was measured in this test setup.

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6.6 Band 5 Frequency Stability Measurements

§2.1055 §22.355 RSS-132(4.3)

OPERATING FREQUENCY: 836,500,000 Hz

CHANNEL: 20525

REFERENCE VOLTAGE: 3.8 VDC

DEVIATION LIMIT: ± 0.00025 % or 2.5 ppm

VOLTAGE (%)	POWER (VDC)	TEMP (°C)	FREQUENCY (Hz)	Freq. Dev. (Hz)	Deviation (%)
100 %	3.80	+ 20 (Ref)	836,500,002	2	0.0000002
100 %		- 30	836,500,010	10	0.0000012
100 %		- 20	836,500,011	11	0.0000013
100 %		- 10	836,499,990	-10	-0.0000012
100 %		0	836,500,004	4	0.0000005
100 %		+ 10	836,500,008	8	0.0000010
100 %		+ 20	836,499,998	-2	-0.0000002
100 %		+ 30	836,499,996	-4	-0.0000004
100 %		+ 40	836,499,993	-7	-0.0000008
100 %		+ 50	836,499,995	-5	-0.0000006
115 %	4.37	+ 20	836,500,015	15	0.0000018
BATT. ENDPOINT	3.42	+ 20	836,499,999	-1	-0.0000002

Table 6-10. Frequency Stability Data (Band 5)

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Band 5 Frequency Stability Measurements (Cont'd)

§2.1055 §22.355 RSS-132(4.3)

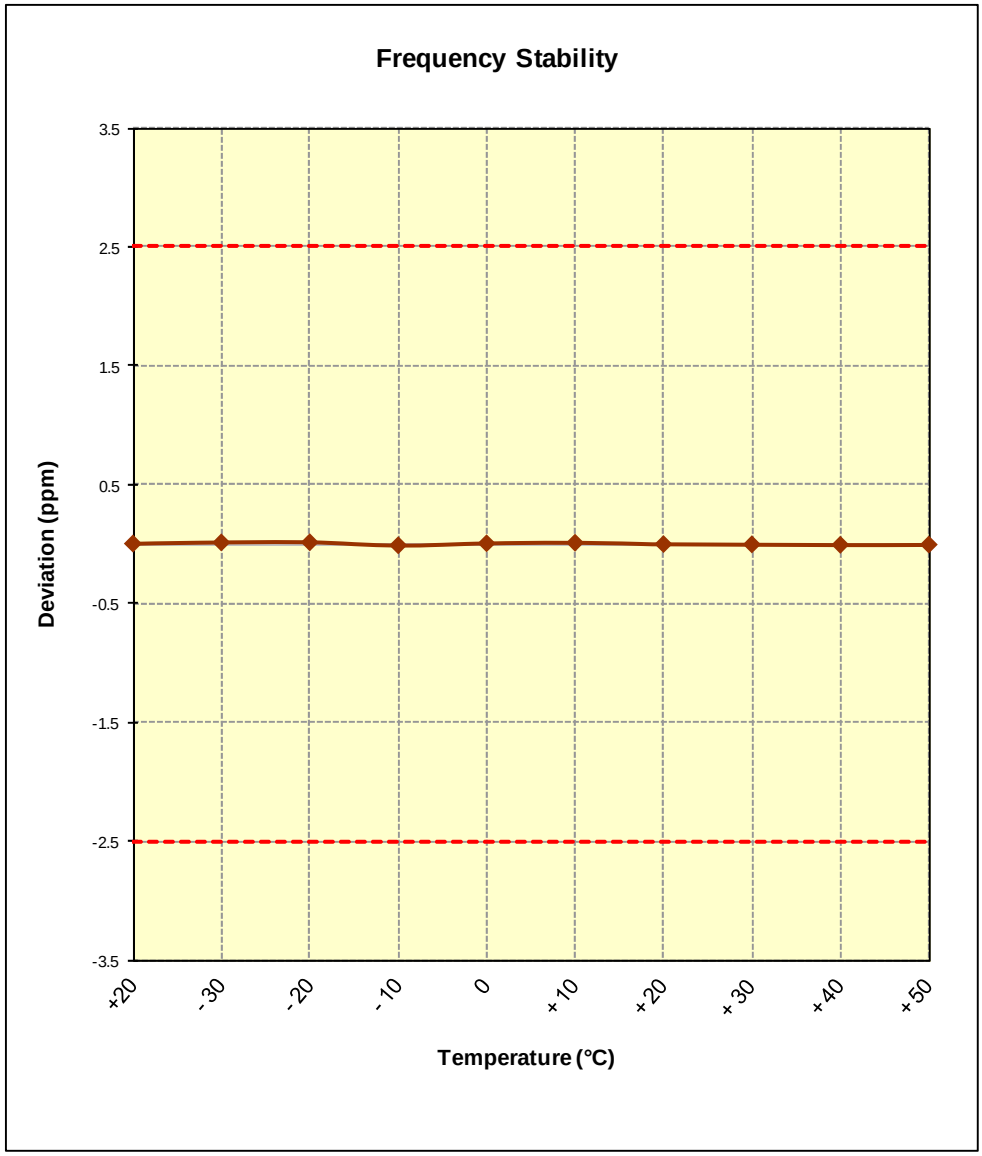

Figure 6-1. Frequency Stability Graph (Band 5)

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6.7 Band 2 Frequency Stability Measurements

§2.1055 §24.235 RSS-133(6.3)

OPERATING FREQUENCY: 1,880,000,000 Hz

CHANNEL: 18900

REFERENCE VOLTAGE: 3.8 VDC

VOLTAGE (%)	POWER (VDC)	TEMP (°C)	FREQUENCY (Hz)	Freq. Dev. (Hz)	Deviation (%)
100 %	3.80	+ 20 (Ref)	1,880,000,009	9	0.0000005
100 %		- 30	1,880,000,003	3	0.0000002
100 %		- 20	1,880,000,012	12	0.0000006
100 %		- 10	1,879,999,992	-8	-0.0000004
100 %		0	1,880,000,007	7	0.0000004
100 %		+ 10	1,880,000,017	17	0.0000009
100 %		+ 20	1,880,000,006	6	0.0000003
100 %		+ 30	1,880,000,018	18	0.0000010
100 %		+ 40	1,880,000,007	7	0.0000004
100 %		+ 50	1,880,000,003	3	0.0000002
115 %	4.37	+ 20	1,880,000,005	5	0.0000003
BATT. ENDPOINT	3.42	+ 20	1,880,000,009	9	0.0000005

Table 6-11. Frequency Stability Data (Band 2)

Note:

Based on the results of the frequency stability test at the center channel the frequency deviation results measured are very small. As such it is determined that the channels at the band edge would remain in-band when the maximum measured frequency deviation noted during the frequency stability tests is applied. Therefore the device is determined to remain operating in band over the temperature and voltage range as tested.

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Band 2 Frequency Stability Measurements (Cont'd)

§2.1055 §24.235 RSS-133(6.3)

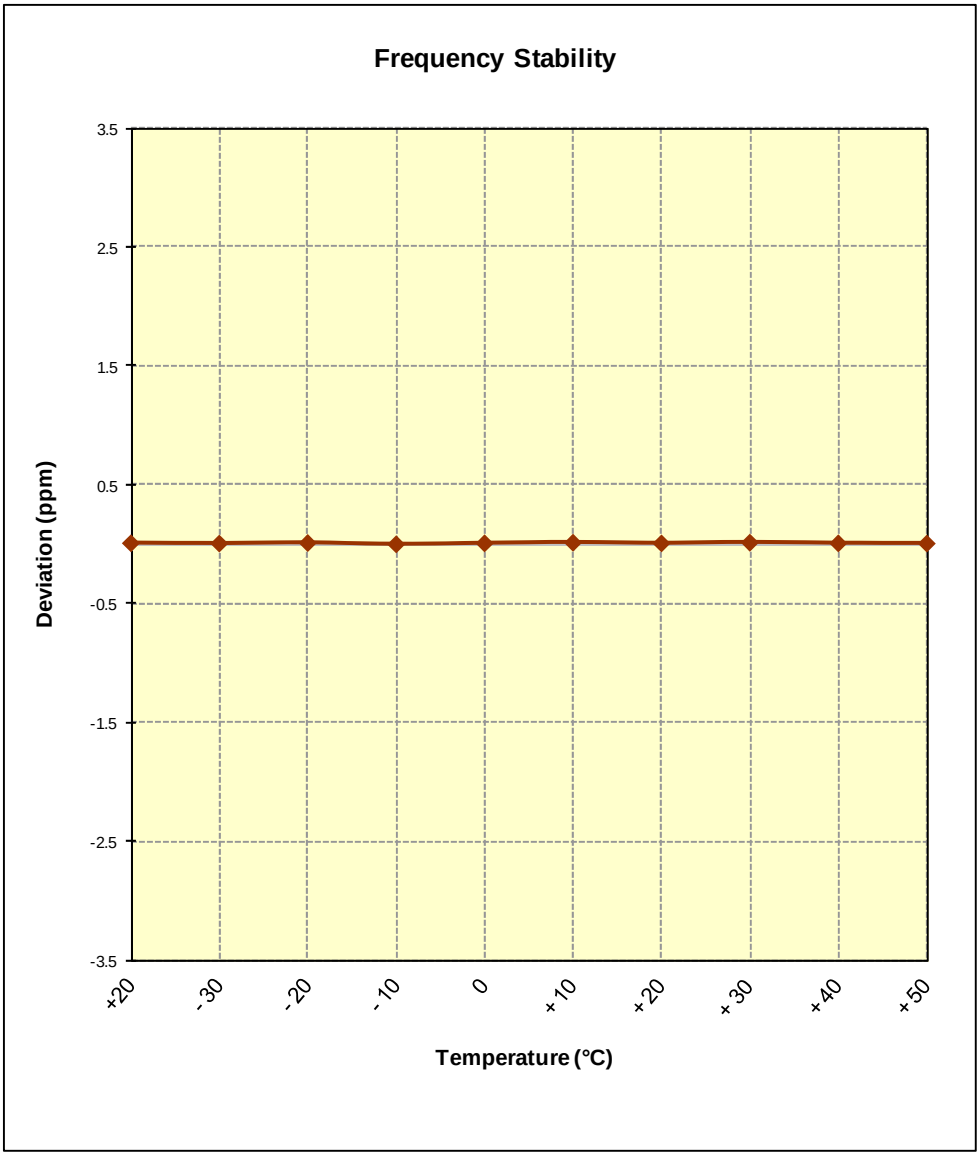

Figure 6-2. Frequency Stability Graph (Band 2)

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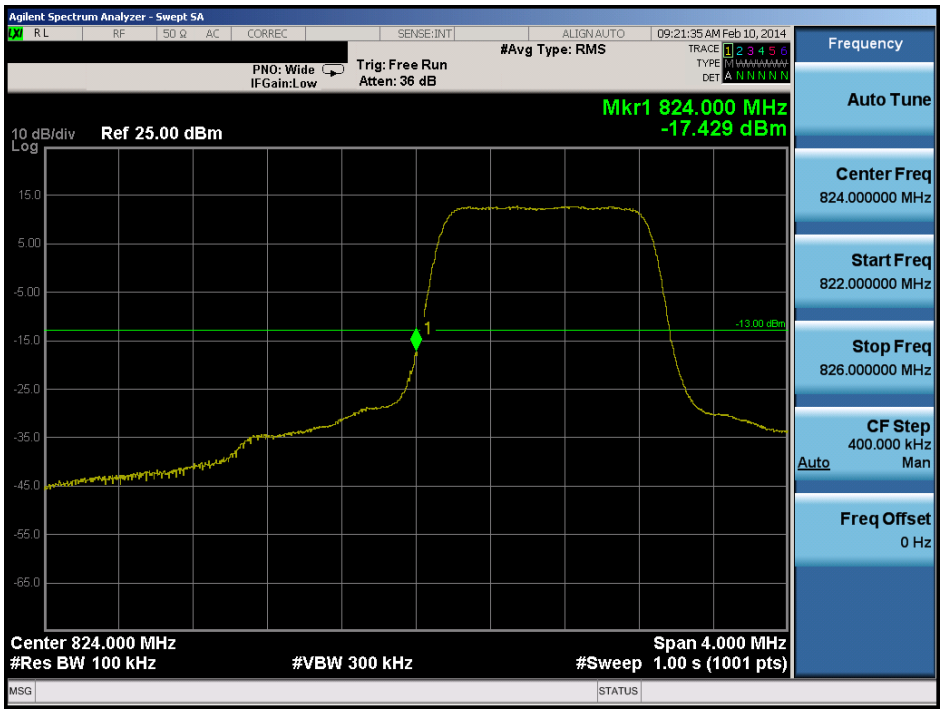
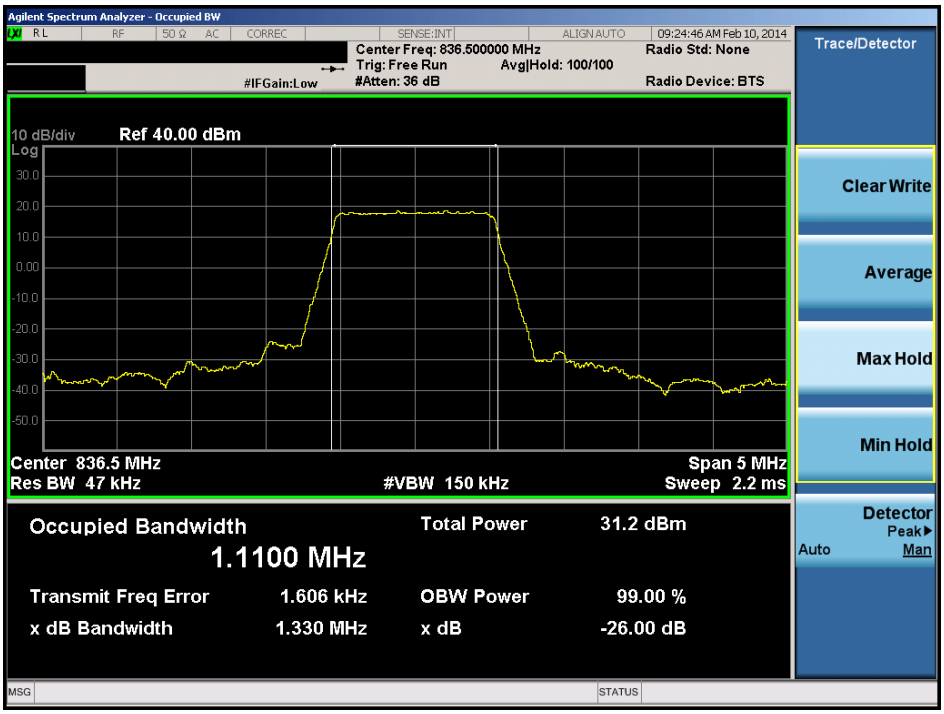
7.0 BAND 5 PLOTS OF EMISSIONS

Note: All bandwidths, RB configurations, and modulations were investigated. The worst case test results are reported below.



Plot 7-1. Lower Band Edge Plot (1.4MHz QPSK – RB Size 6)



Plot 7-2. Occupied Bandwidth Plot (1.4MHz QPSK – RB Size 6)

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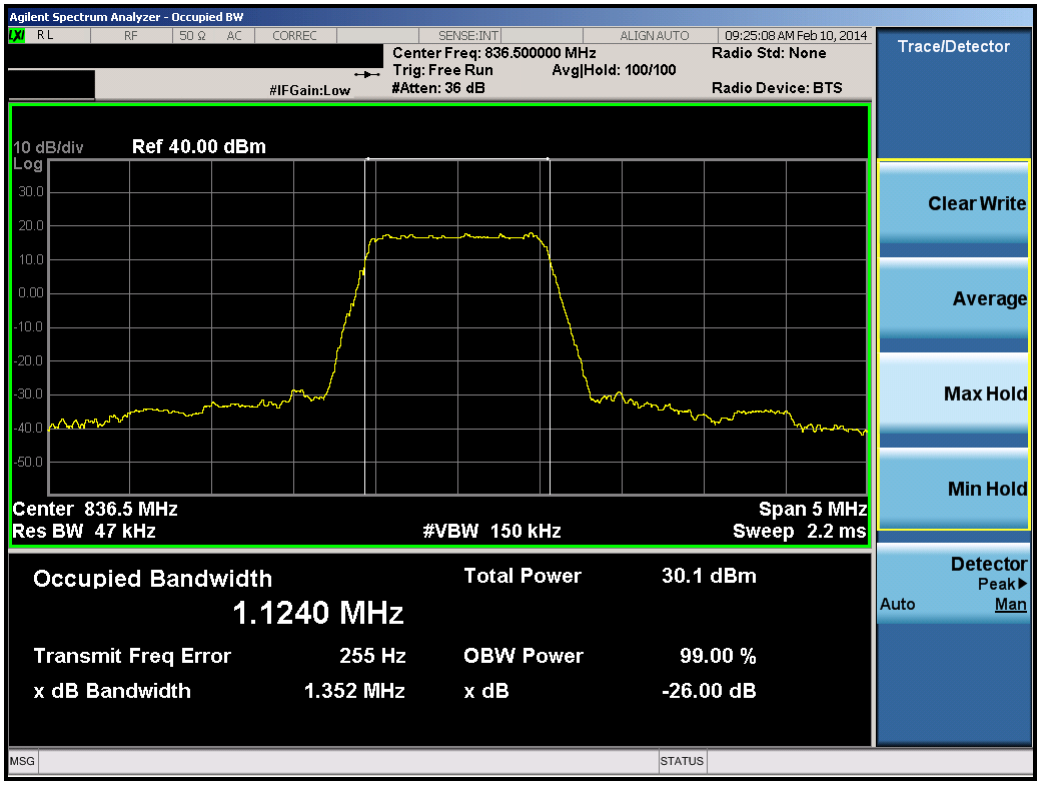
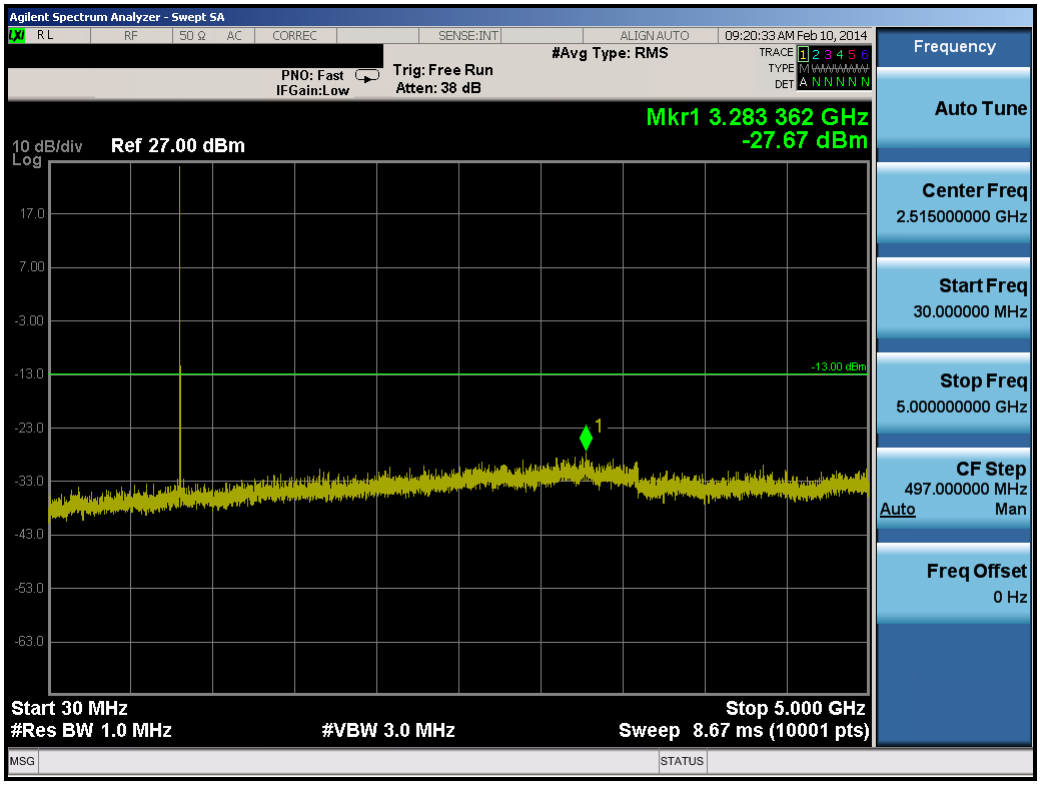


Plot 7-3. Occupied Bandwidth Plot (1.4MHz 16-QAM – RB Size 6)



Plot 7-4. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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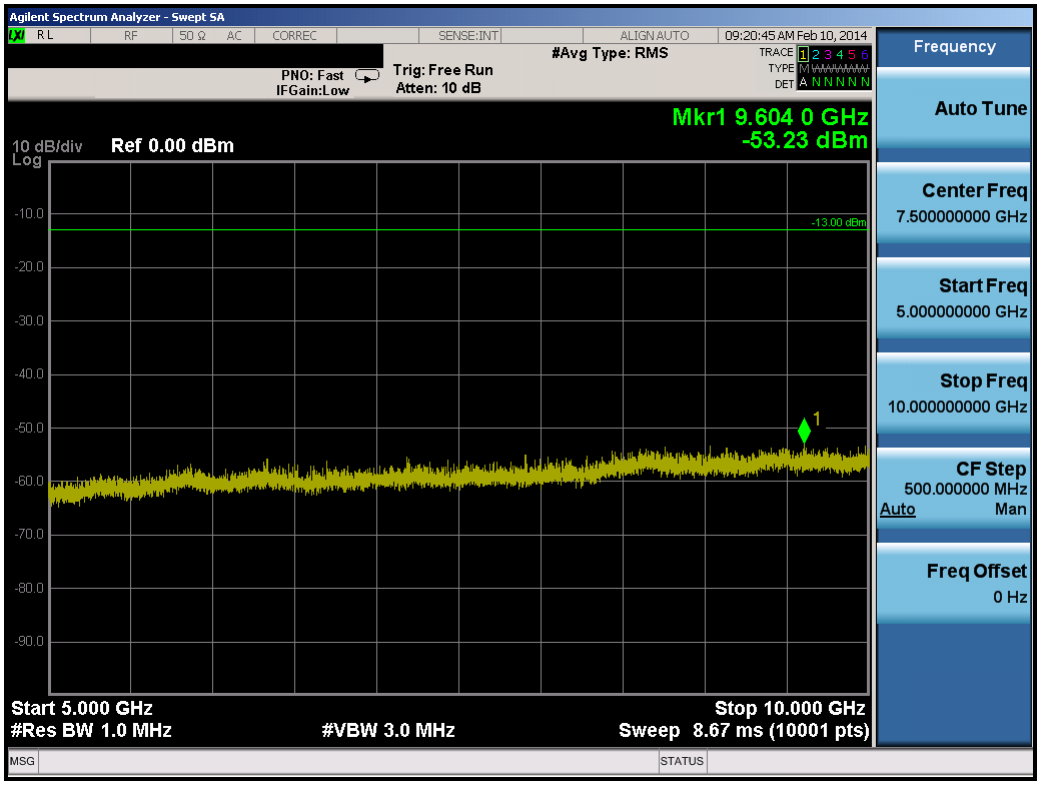
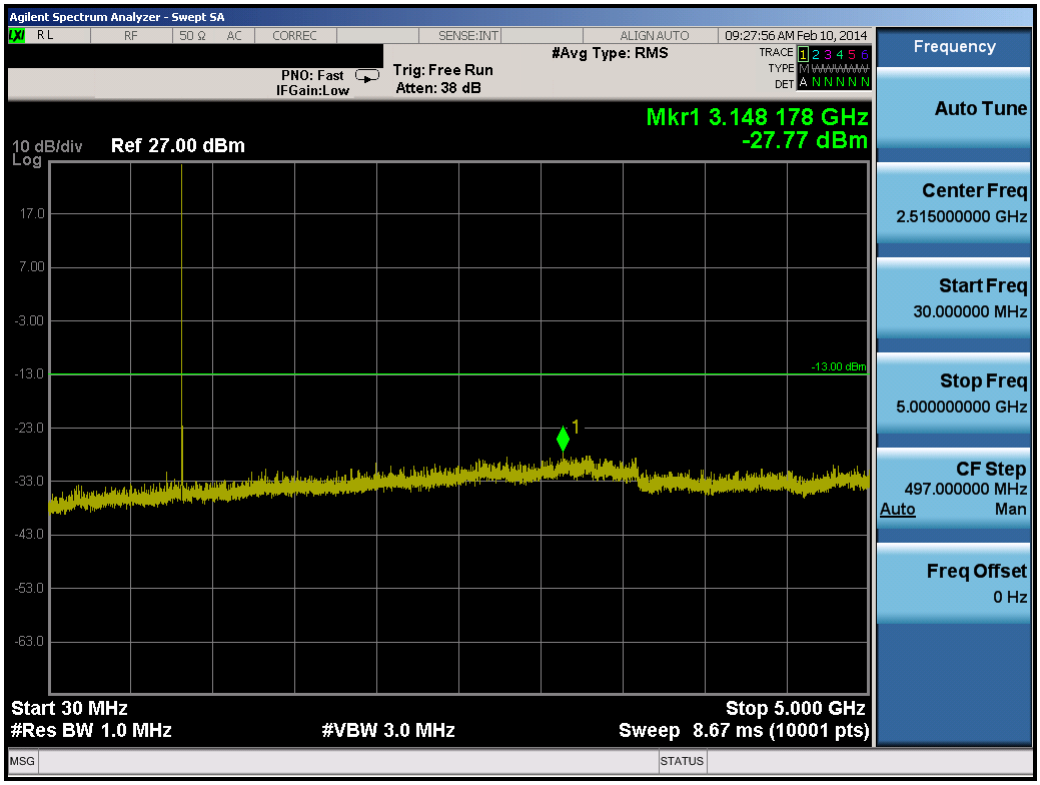


Plot 7-5. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 7-6. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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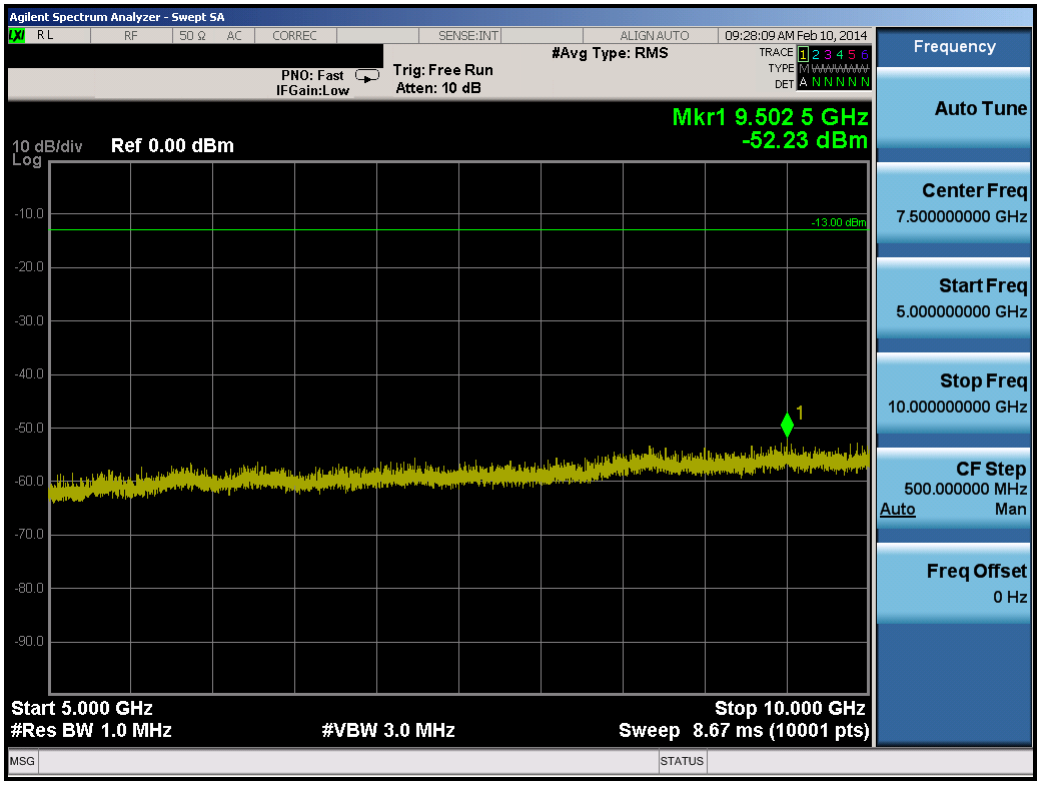
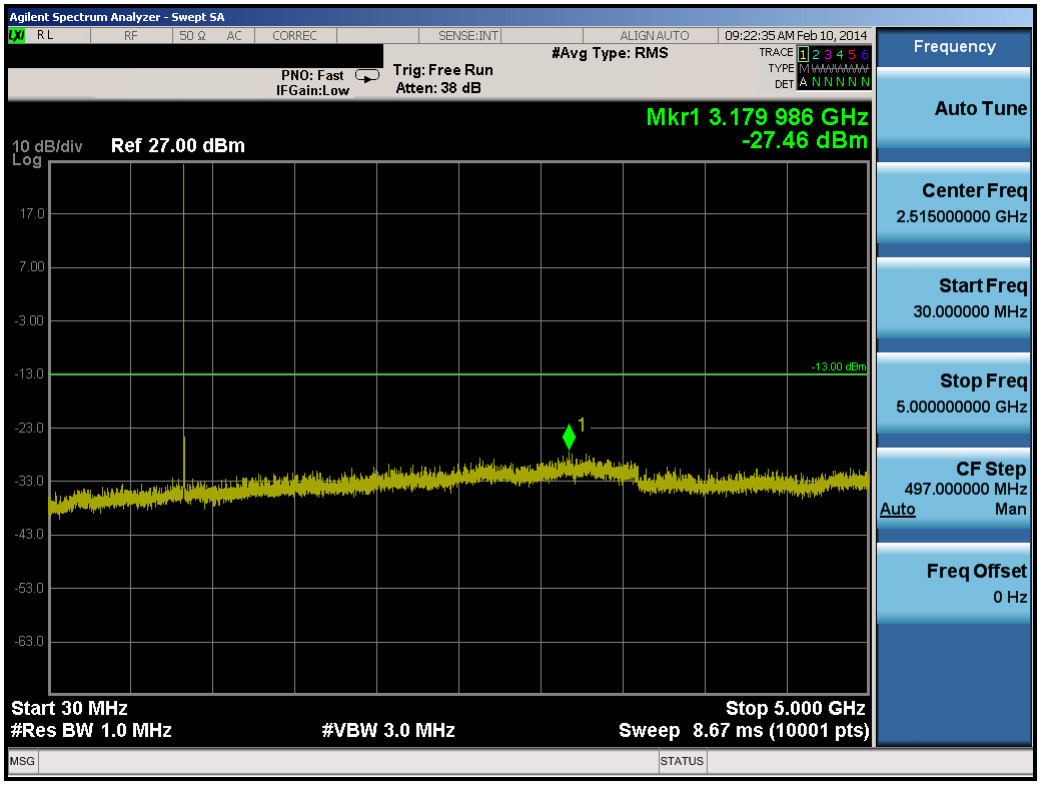


Plot 7-7. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 7-8. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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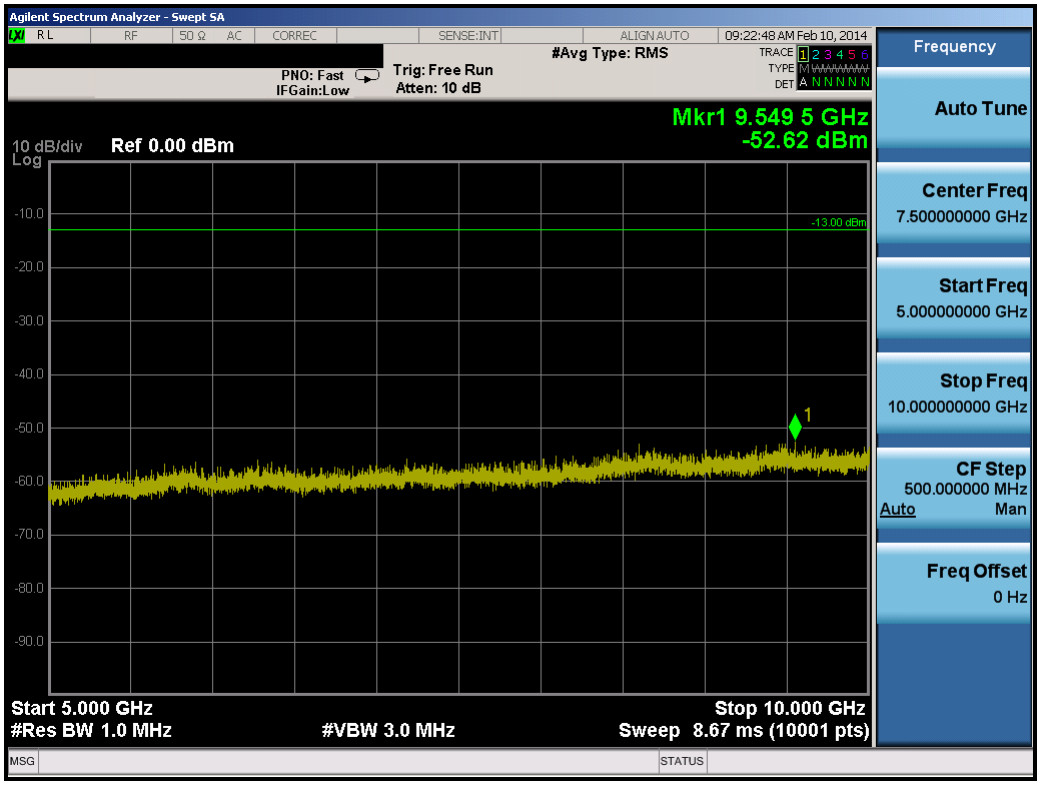

Plot 7-9. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

Plot 7-10. Upper Band Edge Plot (1.4MHz QPSK – RB Size 6)

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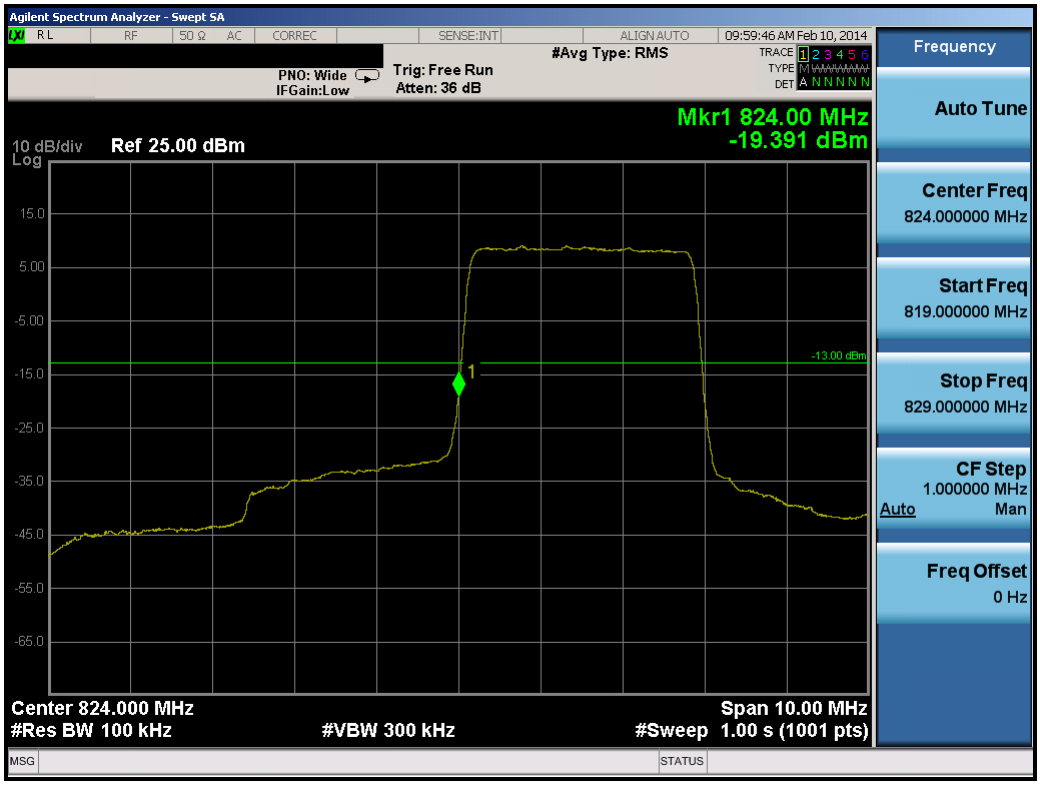
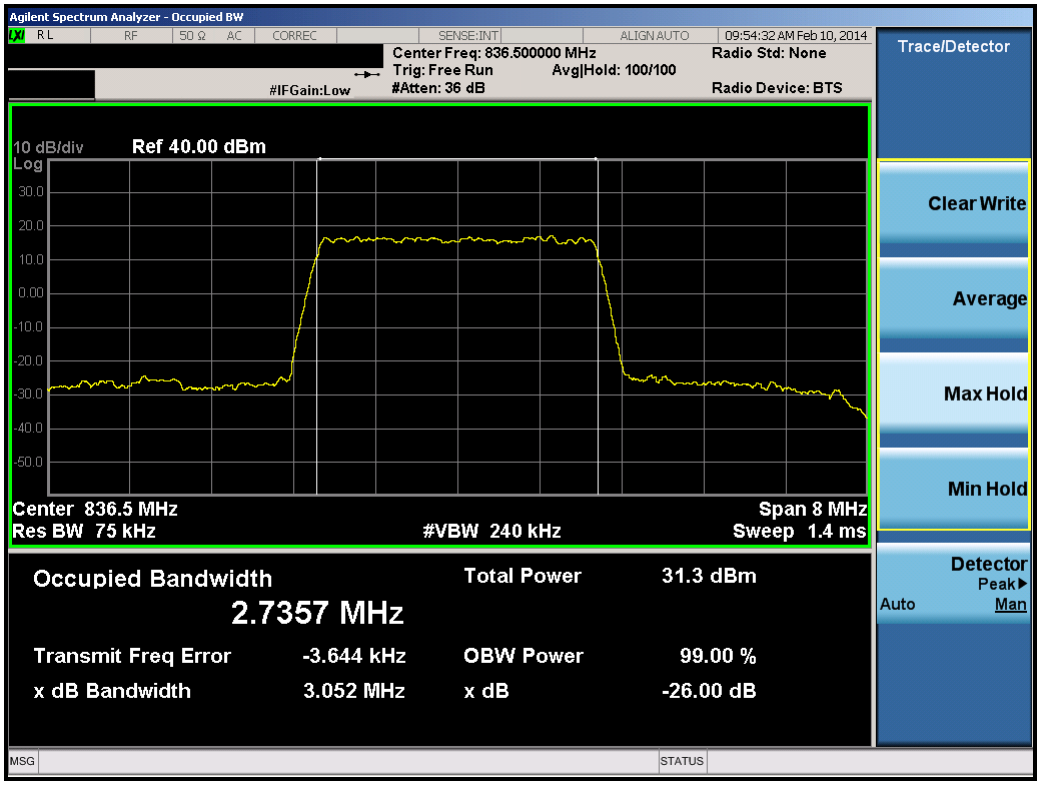


Plot 7-11. Lower Band Edge Plot (3.0MHz QPSK – RB Size 15)



Plot 7-12. Occupied Bandwidth Plot (3.0MHz QPSK – RB Size 15)

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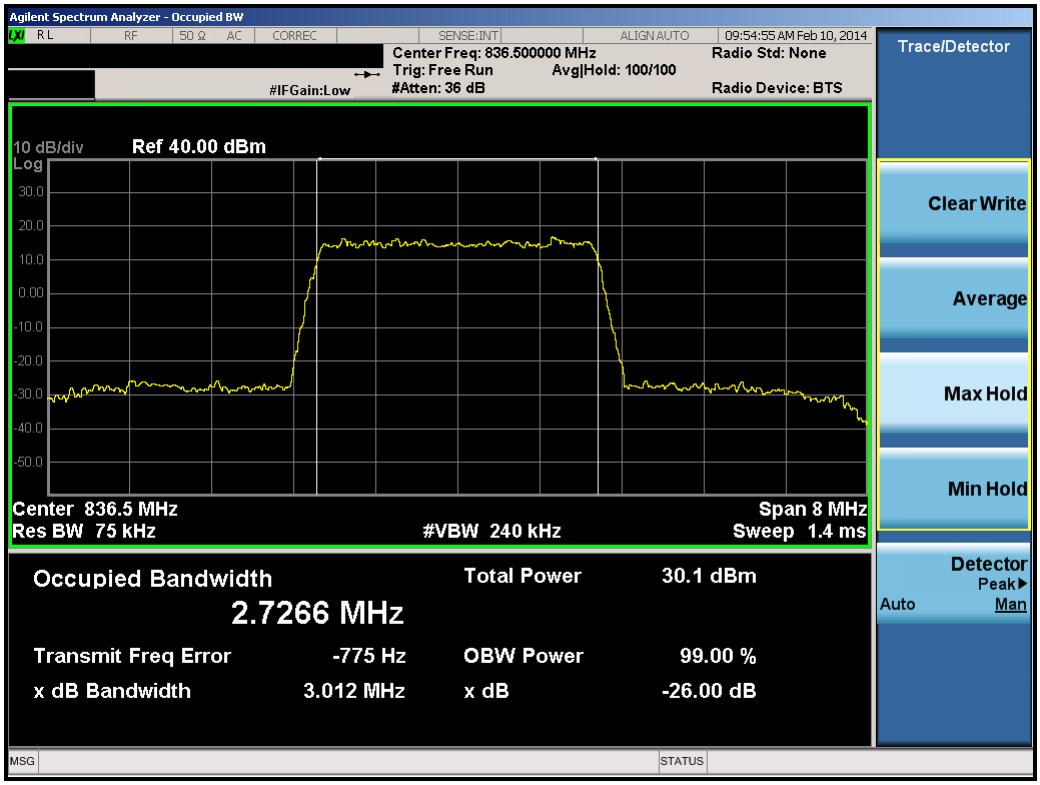
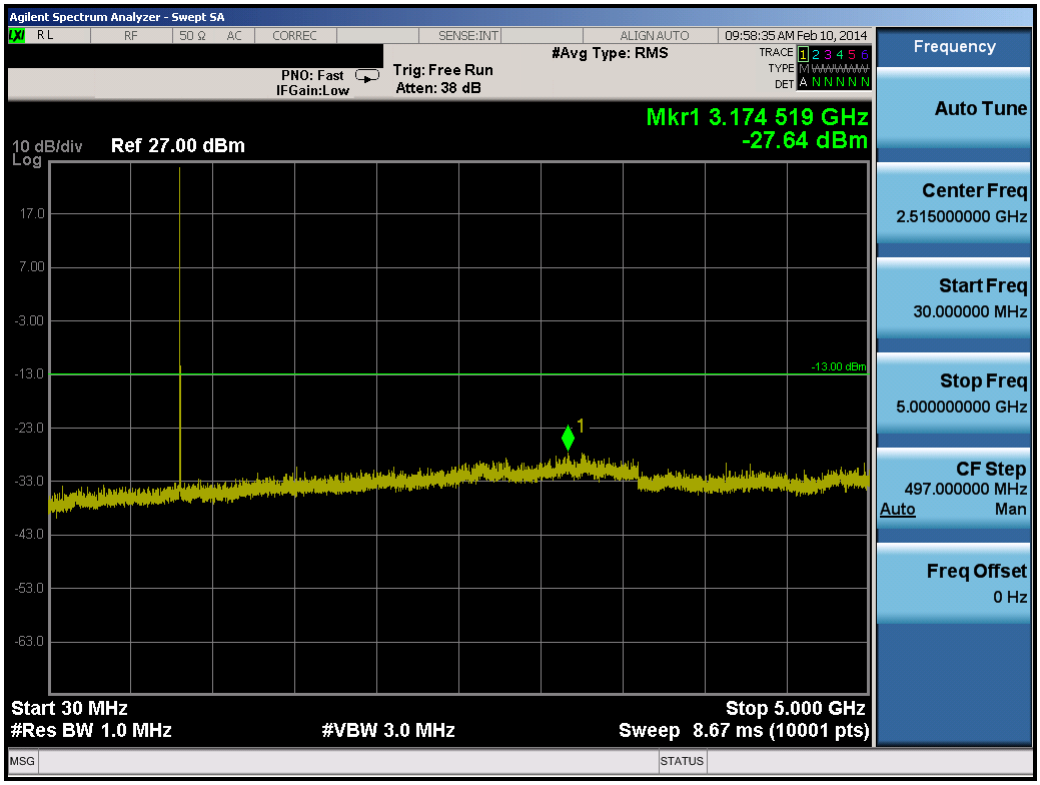


Plot 7-13. Occupied Bandwidth Plot (3.0MHz 16-QAM – RB Size 15)



Plot 7-14. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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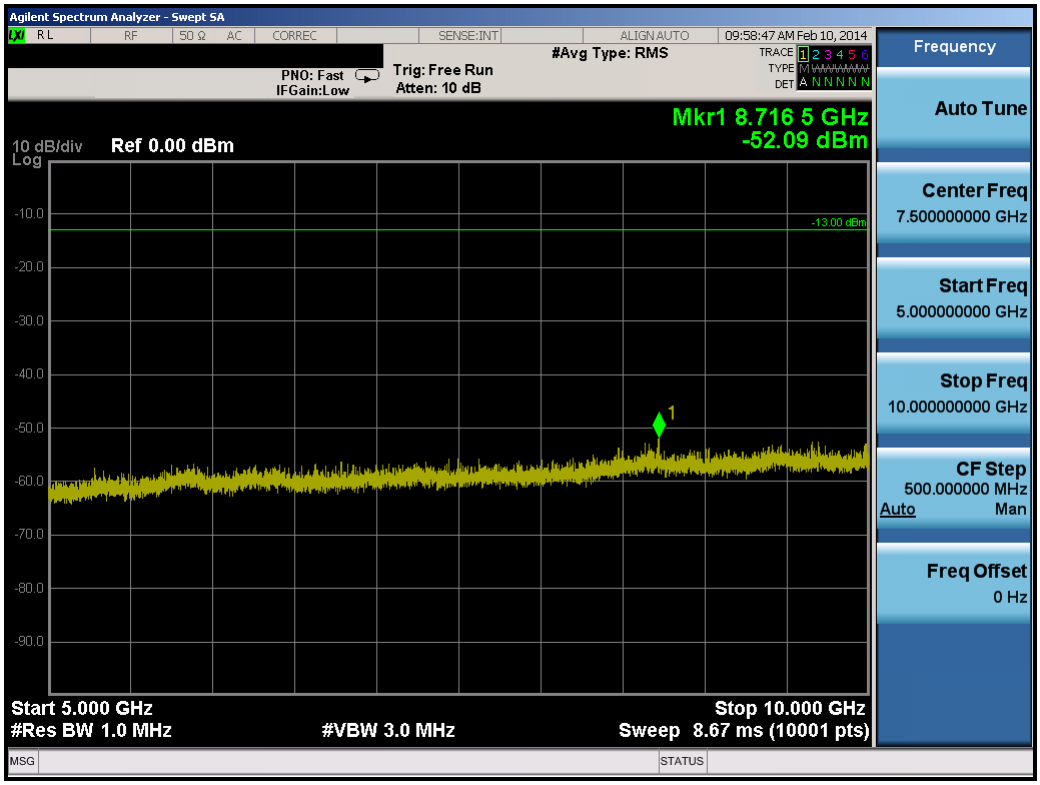
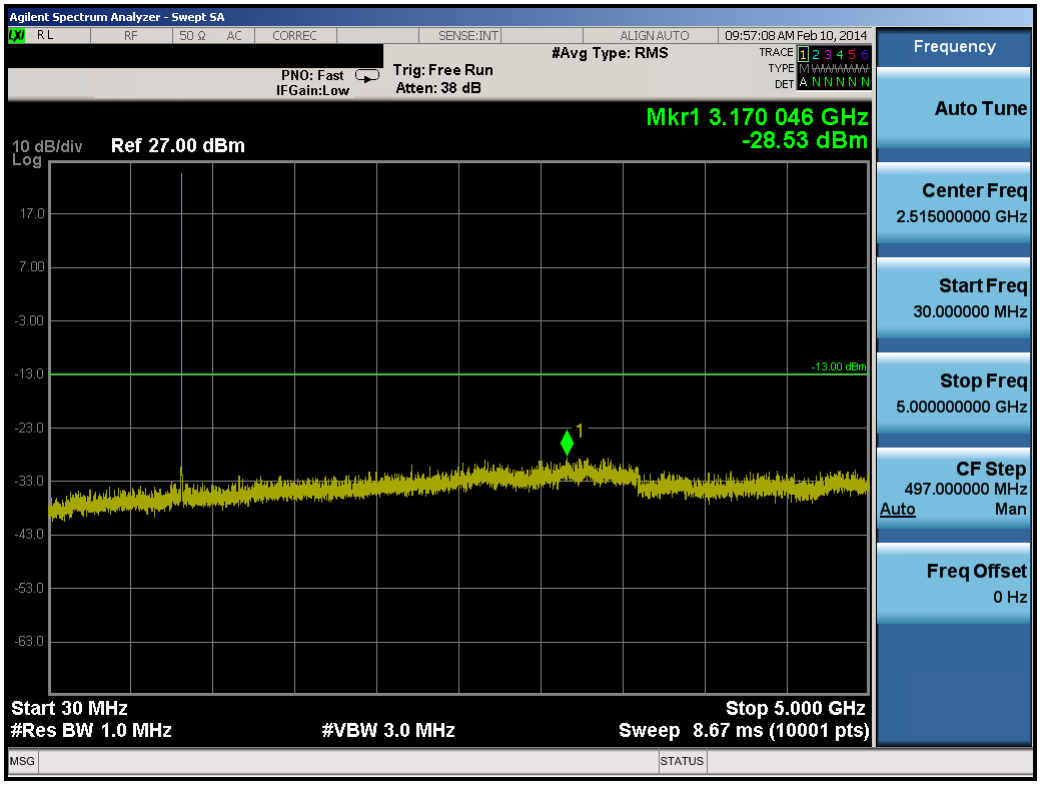


Plot 7-15. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 7-16. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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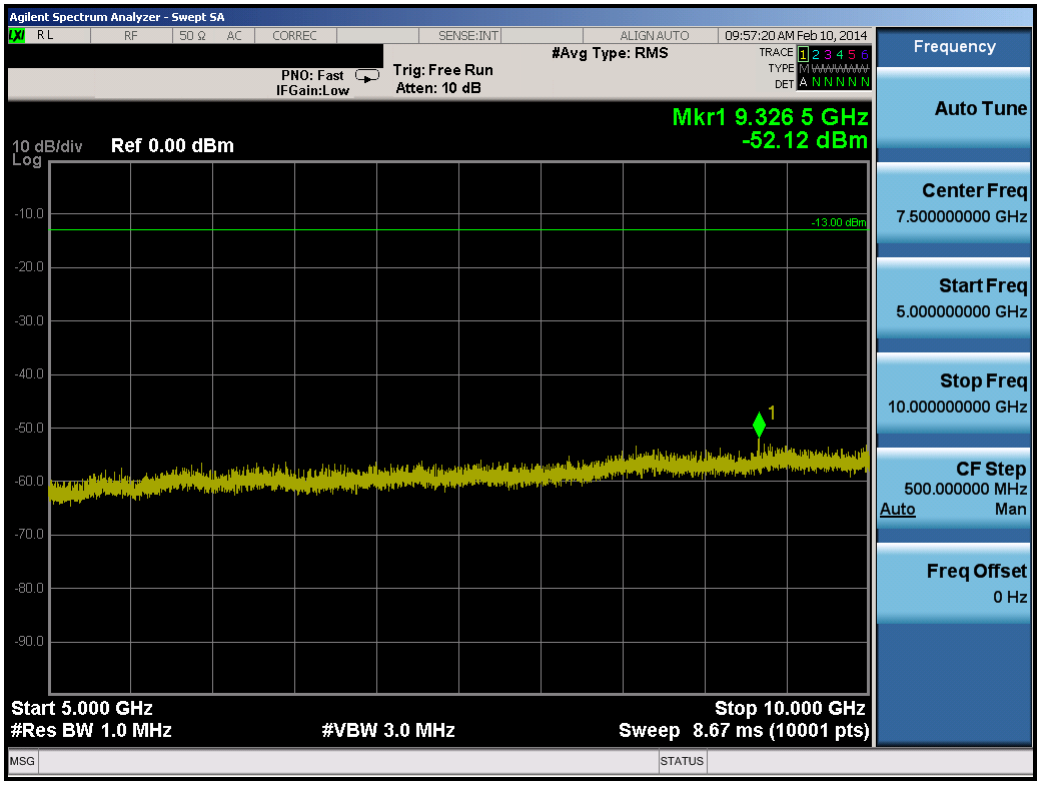
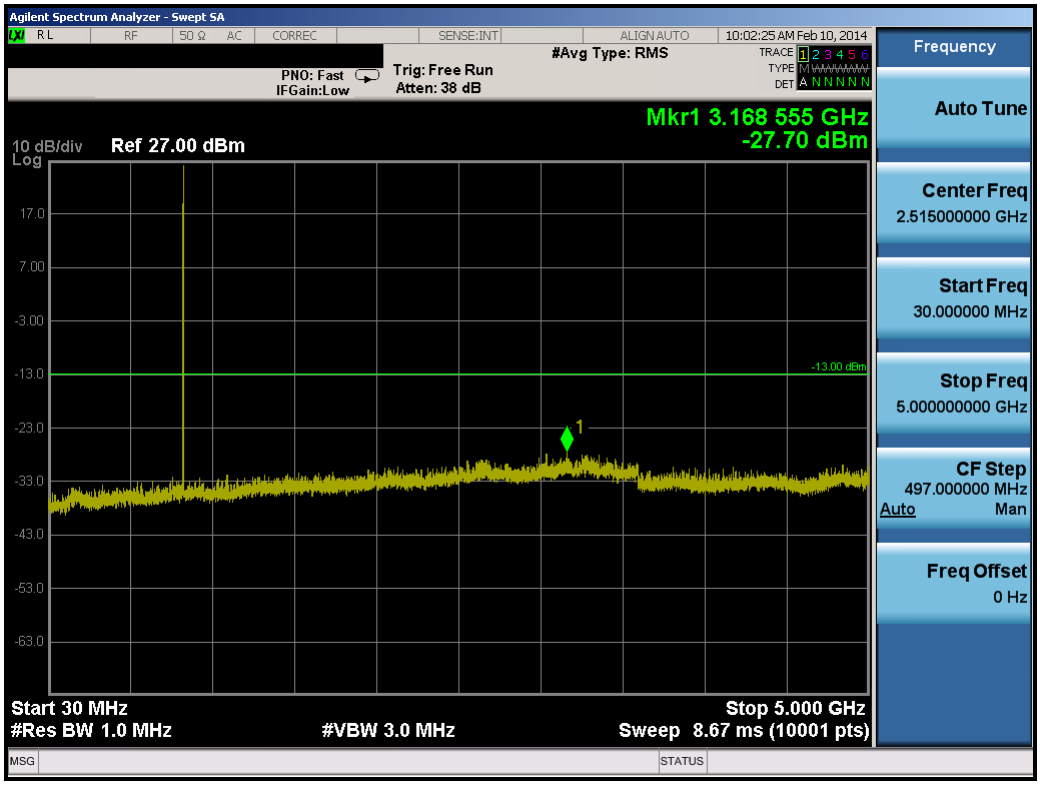


Plot 7-17. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 7-18. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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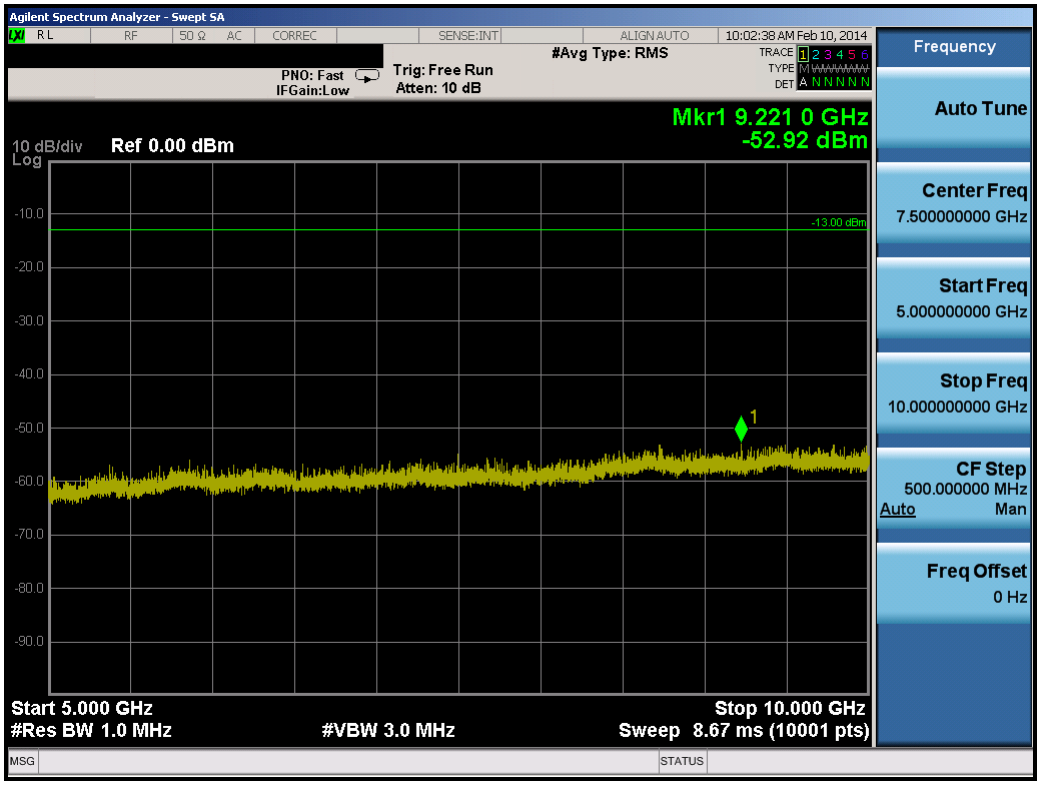

Plot 7-19. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

Plot 7-20. Upper Band Edge Plot (3.0MHz QPSK – RB Size 15)

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Plot 7-21. Lower Band Edge Plot (5.0MHz QPSK – RB Size 25)

Plot 7-22. Occupied Bandwidth Plot (5.0MHz QPSK – RB Size 25)

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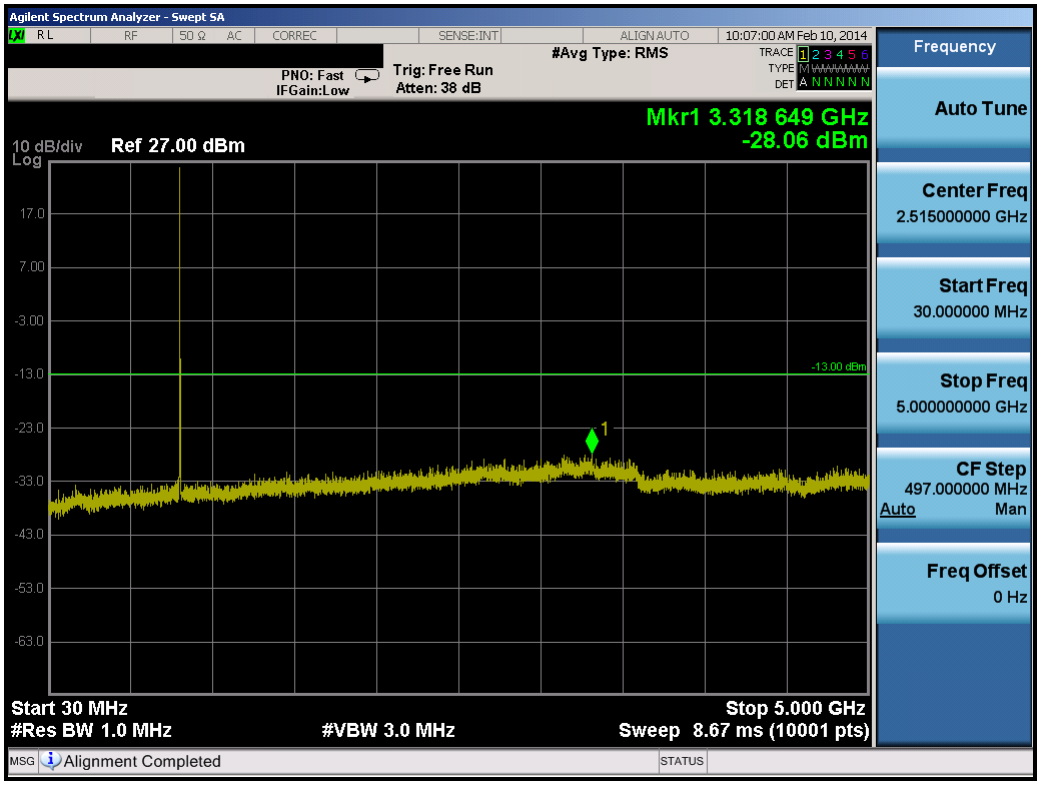
Plot 7-23. Occupied Bandwidth Plot (5.0MHz 16-QAM – RB Size 25)



Plot 7-24. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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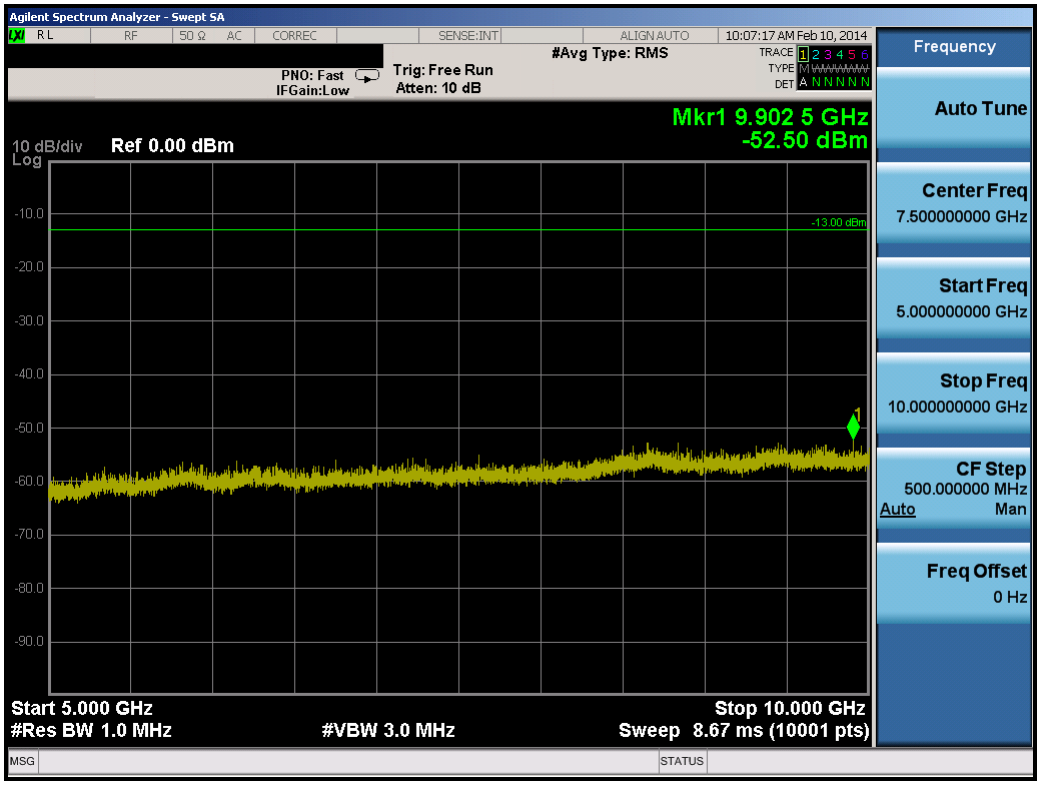
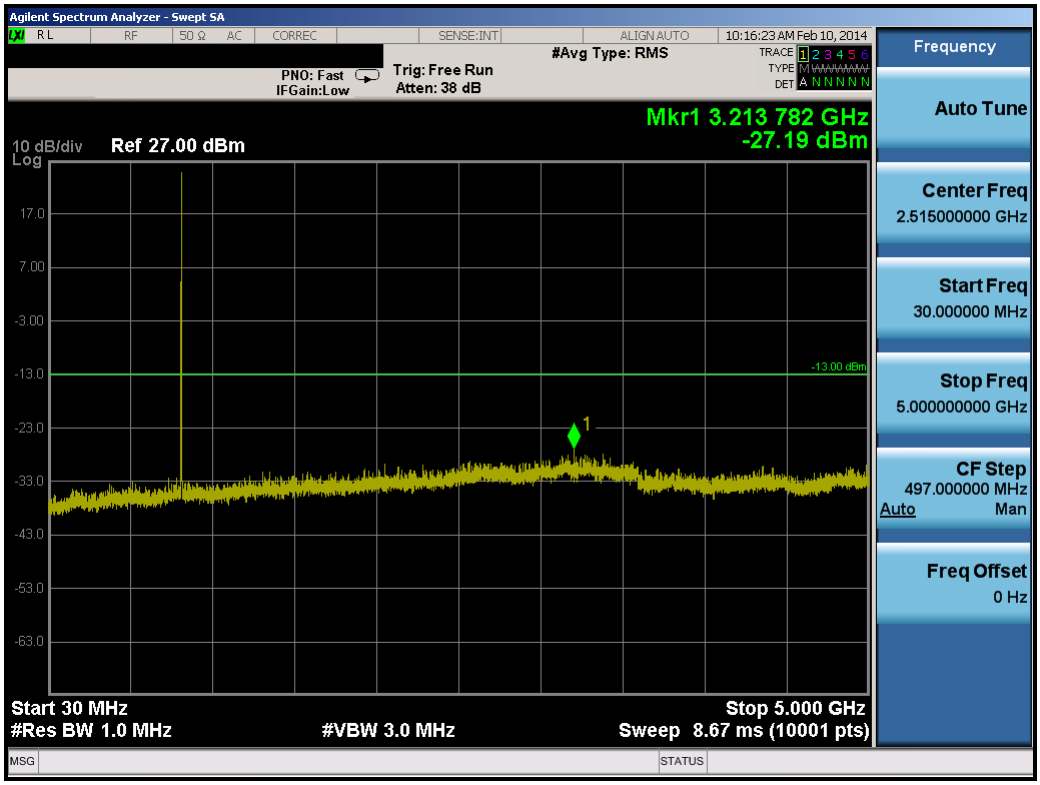


Plot 7-25. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 7-26. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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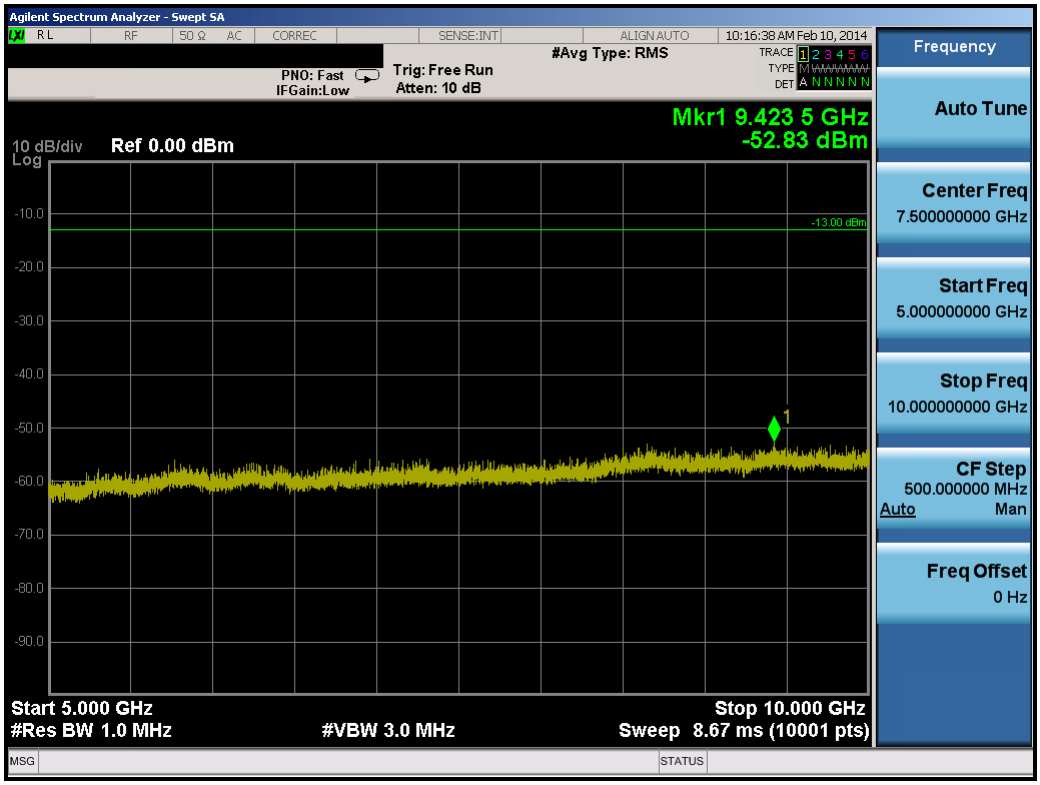
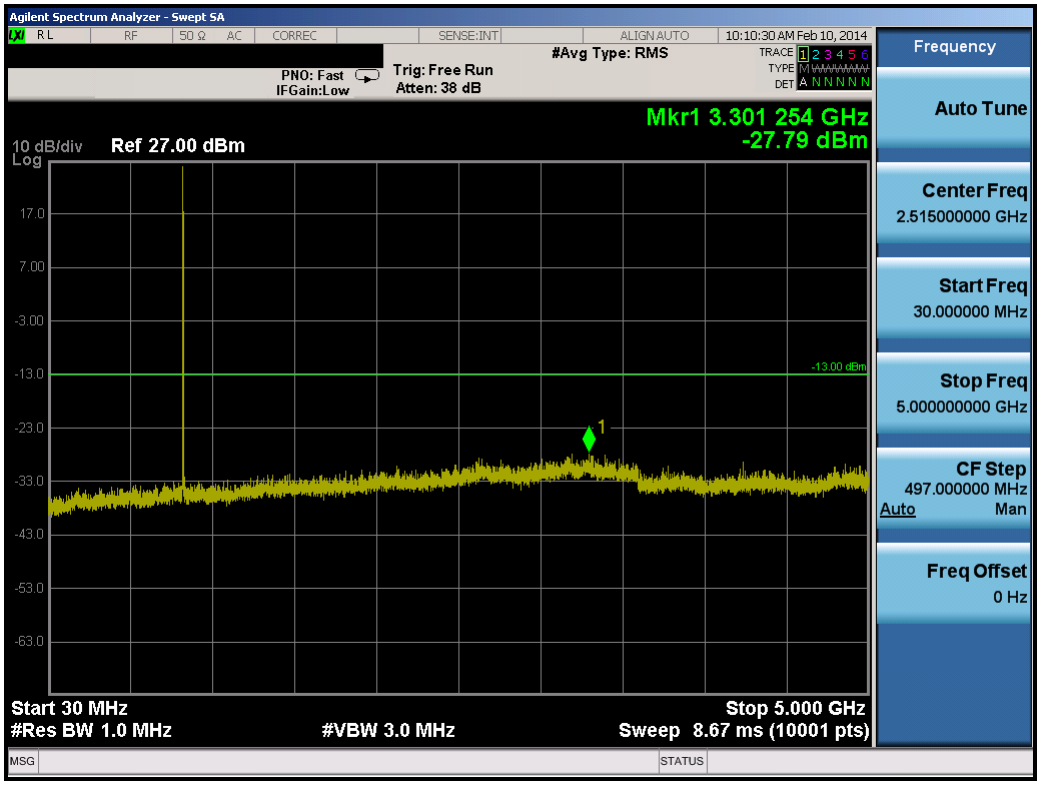


Plot 7-27. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 7-28. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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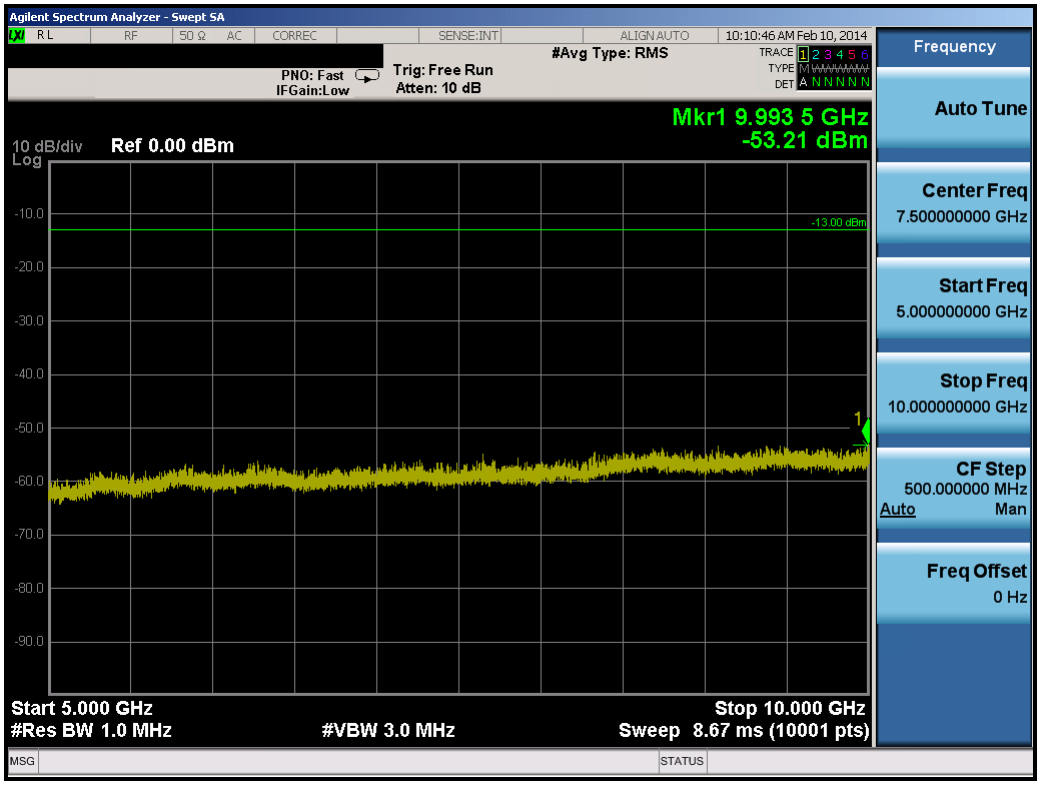
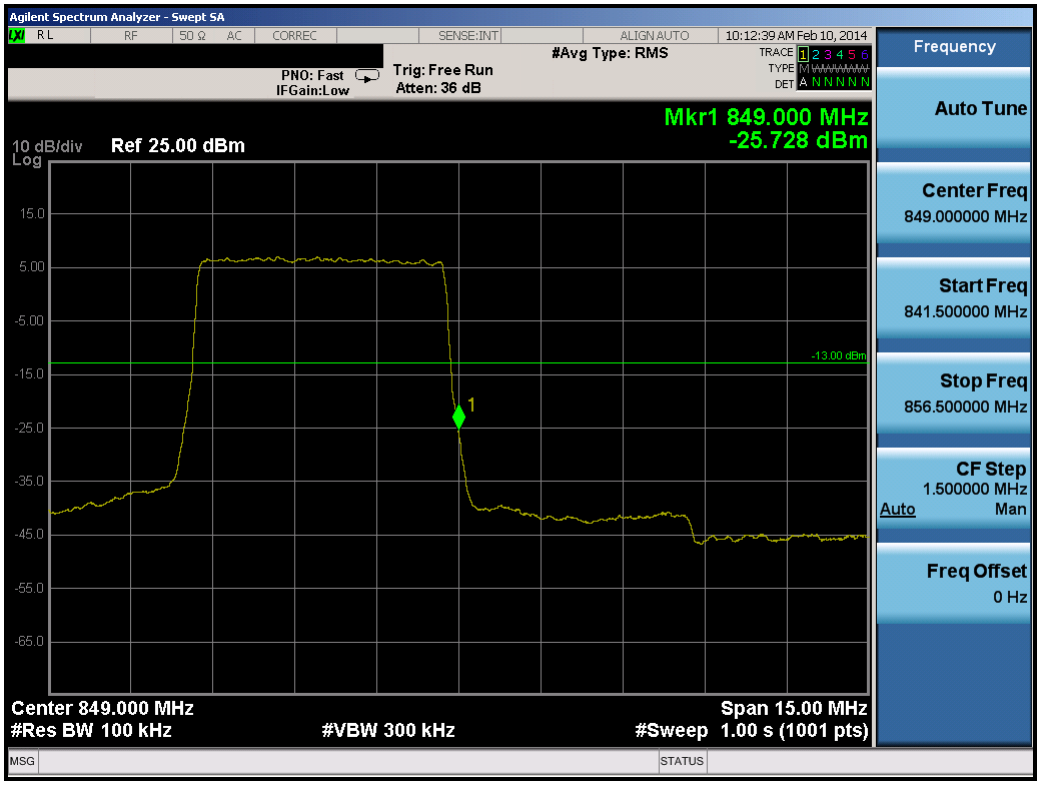


Plot 7-29. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 7-30. Upper Band Edge Plot (5.0MHz QPSK – RB Size 25)

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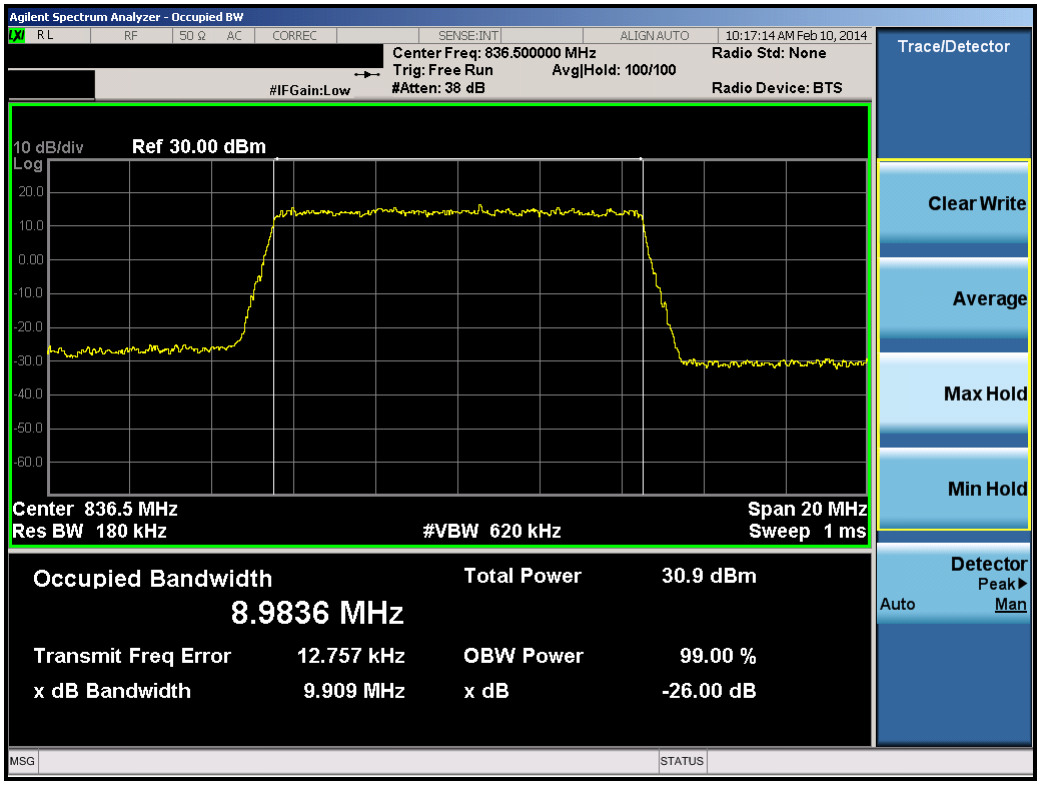
Plot 7-31. Lower Band Edge Plot (10.0MHz QPSK – RB Size 50)



Plot 7-32. Occupied Bandwidth Plot (10.0MHz QPSK – RB Size 50)

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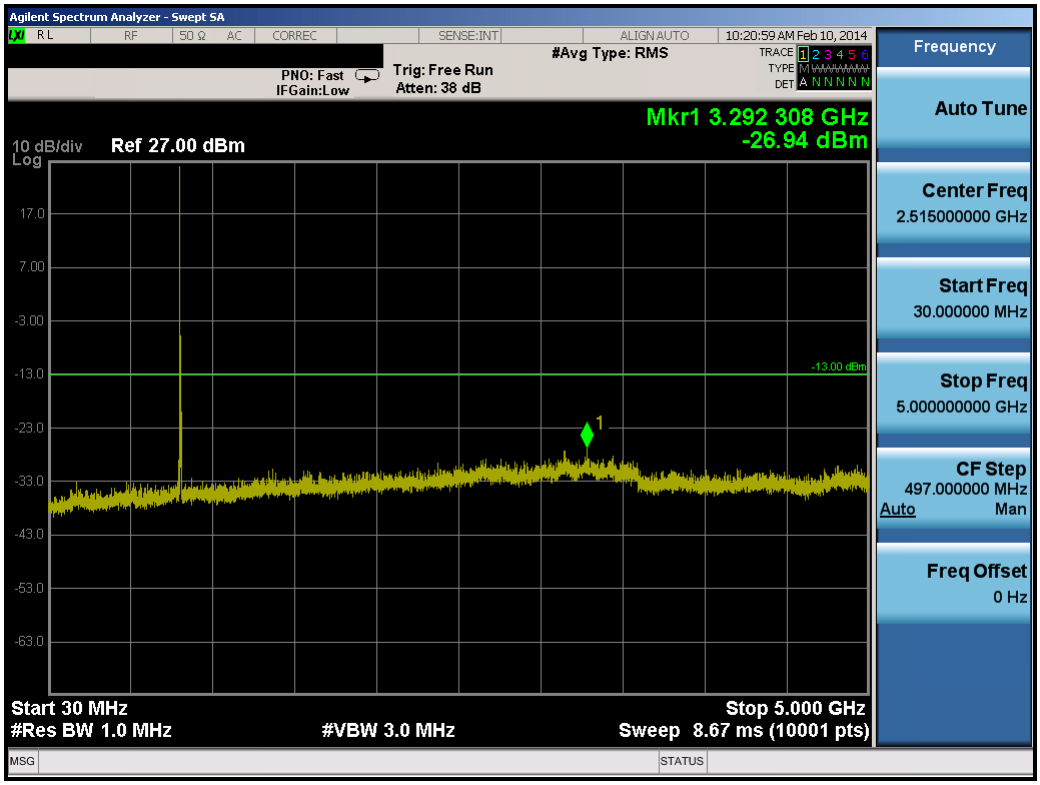
Plot 7-33. Occupied Bandwidth Plot (10.0MHz 16-QAM – RB Size 50)



Plot 7-34. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

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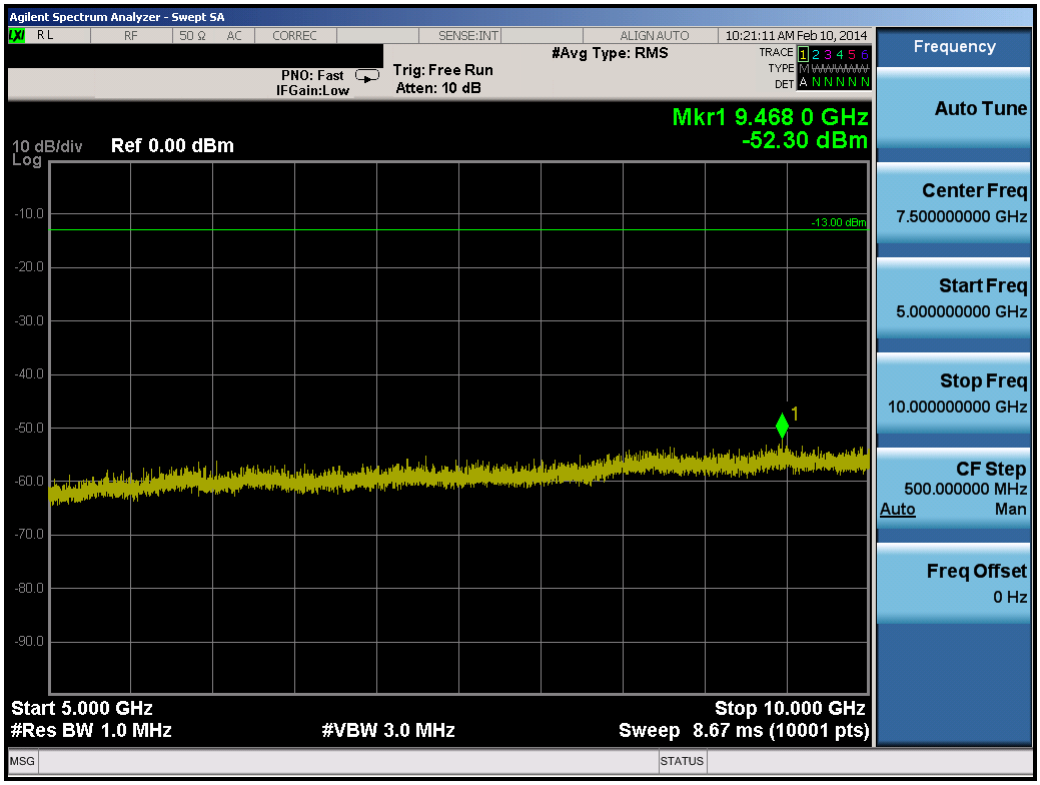
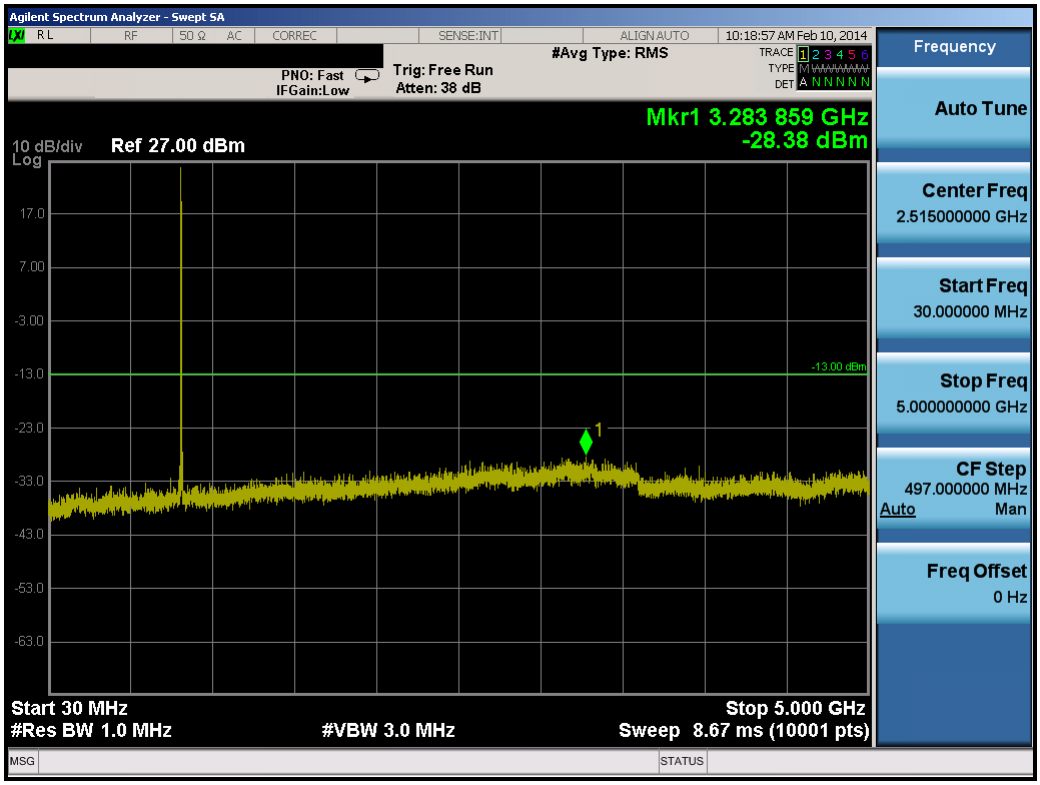


Plot 7-35. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 7-36. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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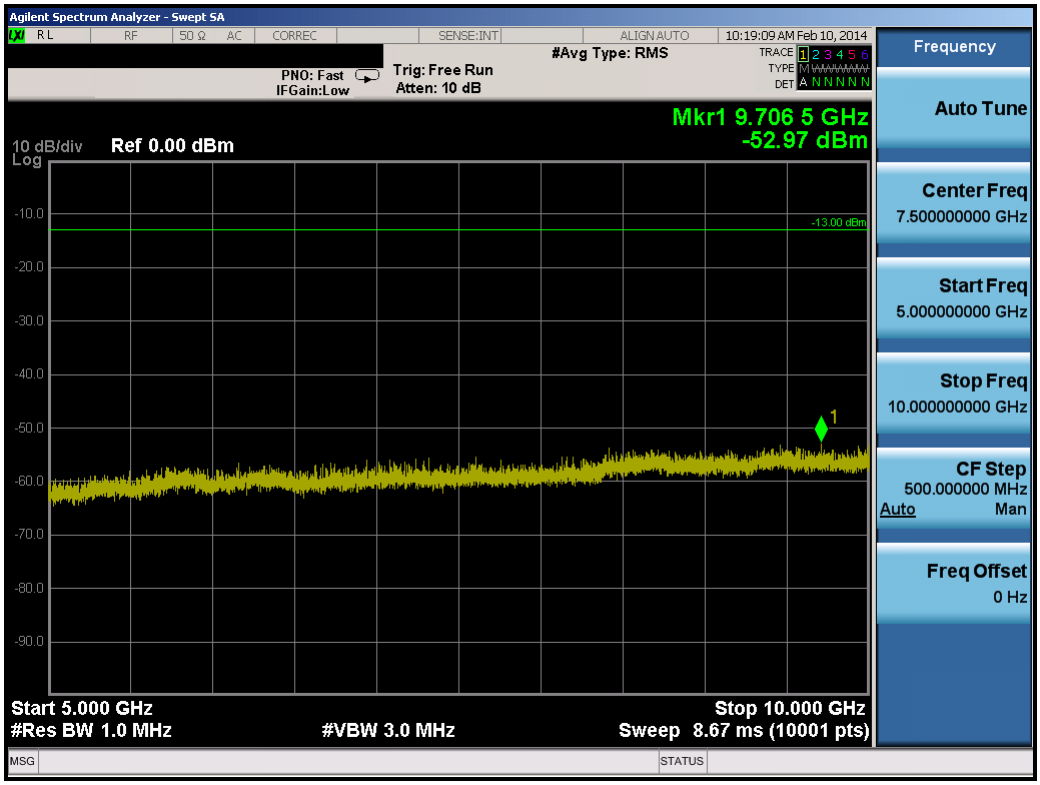
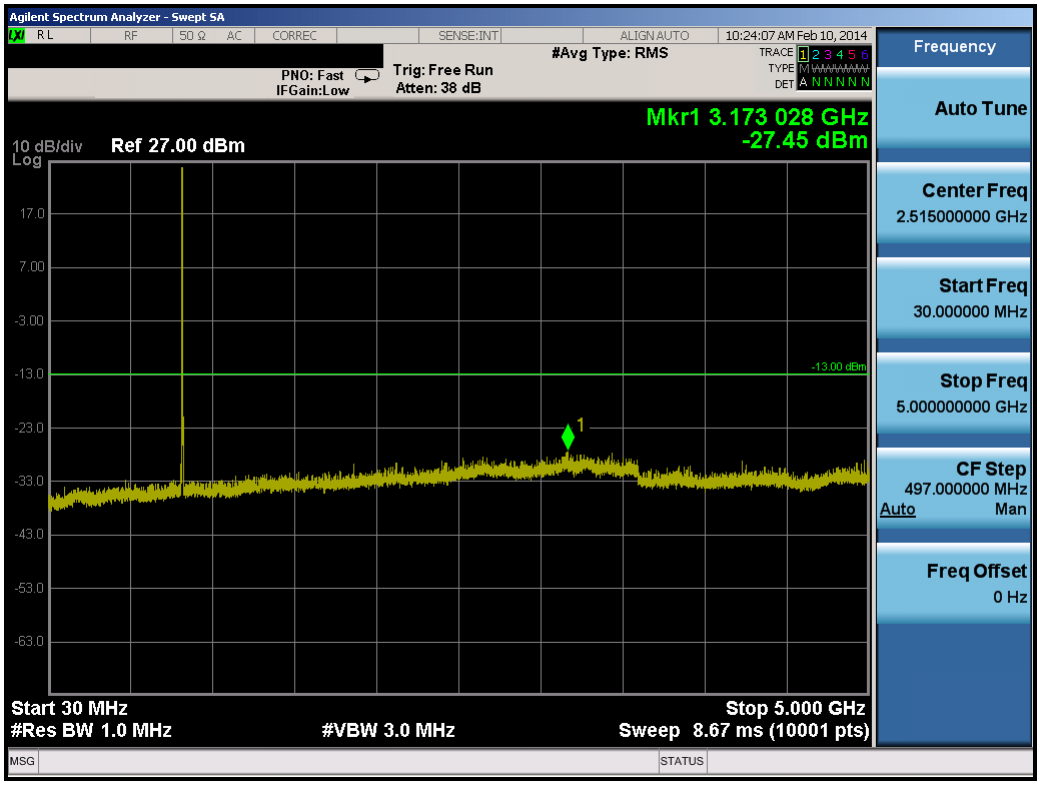


Plot 7-37. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 7-38. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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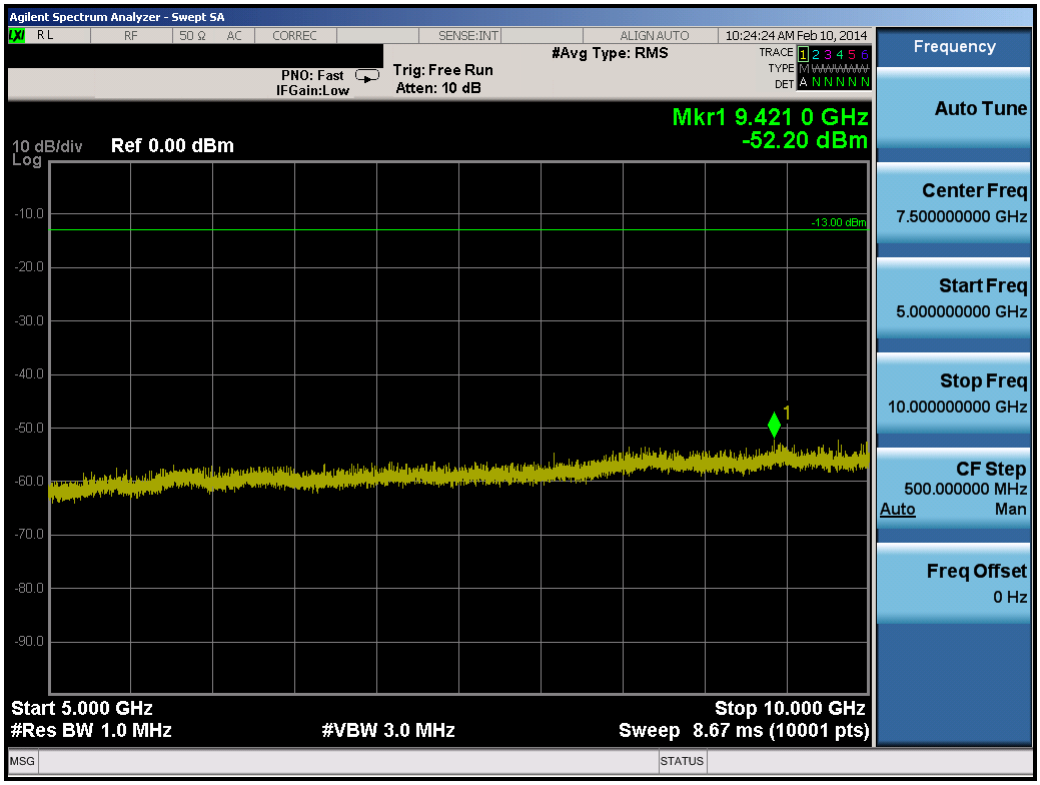
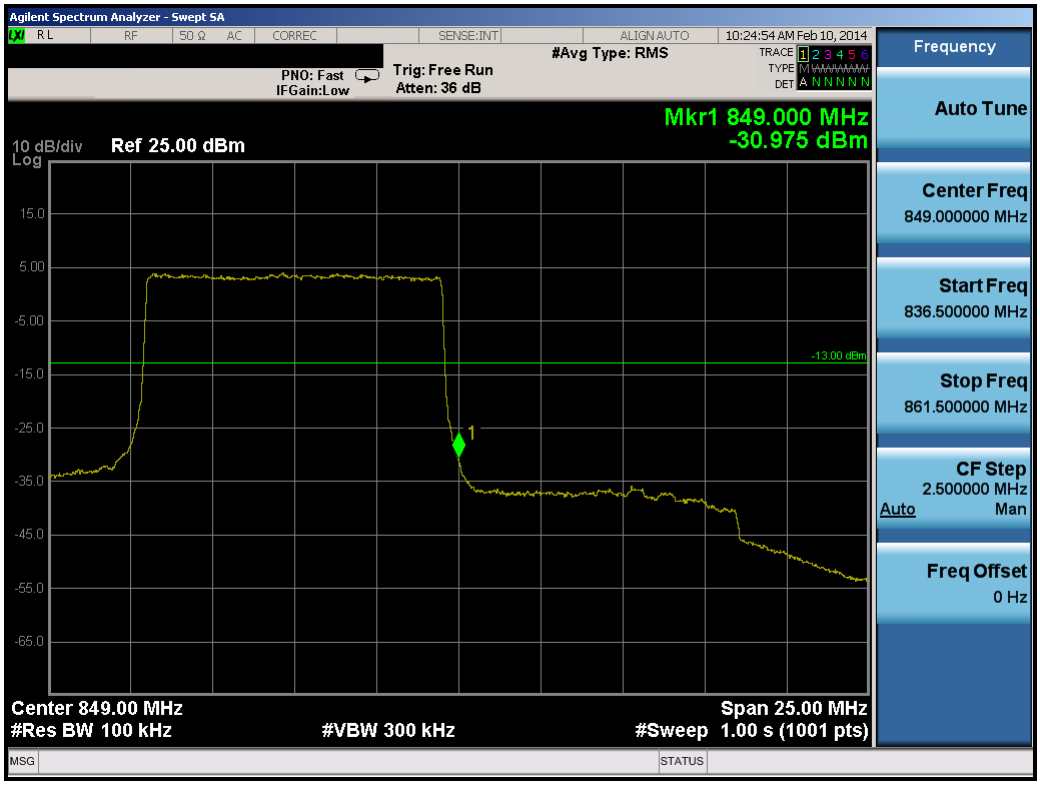


Plot 7-39. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 7-40. Upper Band Edge Plot (10.0MHz QPSK – RB Size 50)

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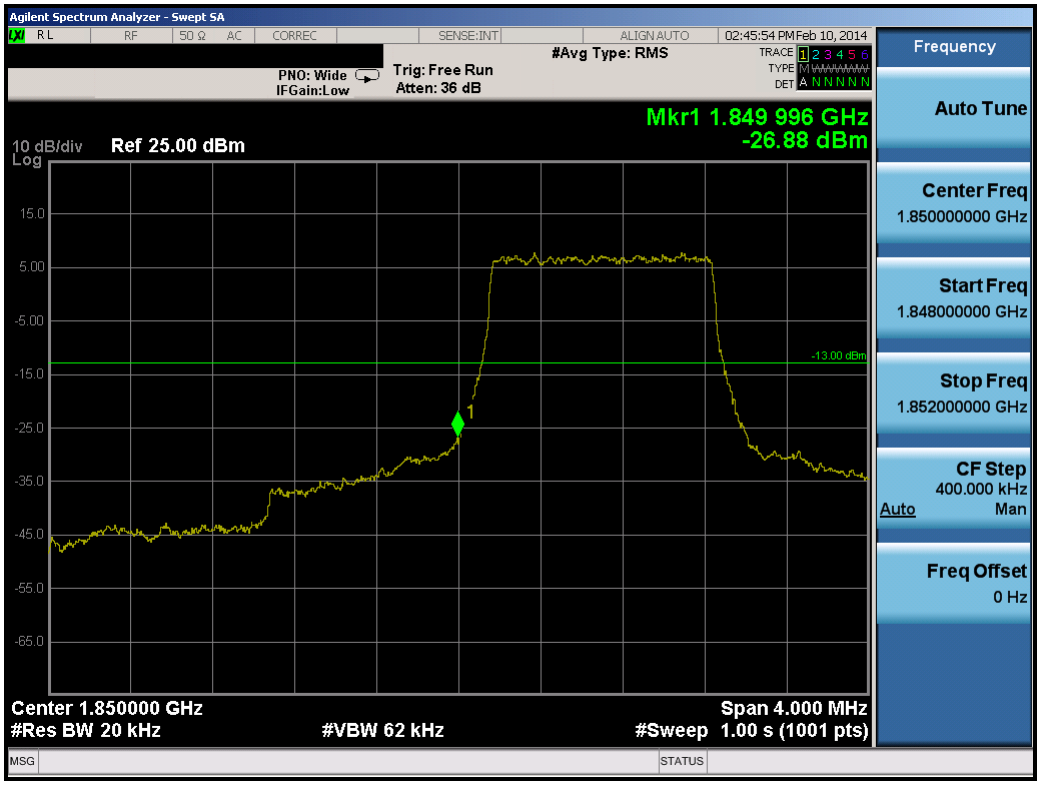
8.0 BAND 2 PLOTS OF EMISSIONS

Note: All bandwidths, RB configurations, and modulations were investigated. The worst case test results are reported below.



Plot 8-1. Lower Band Edge Plot (1.4MHz QPSK – RB Size 6)

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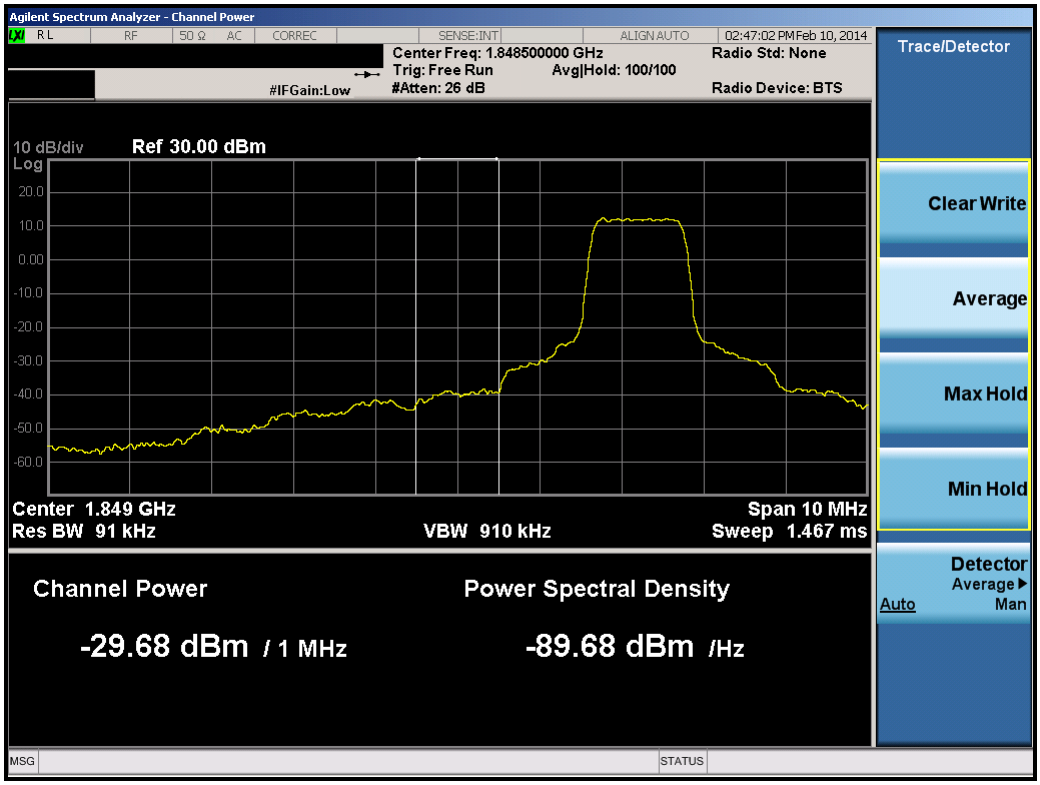
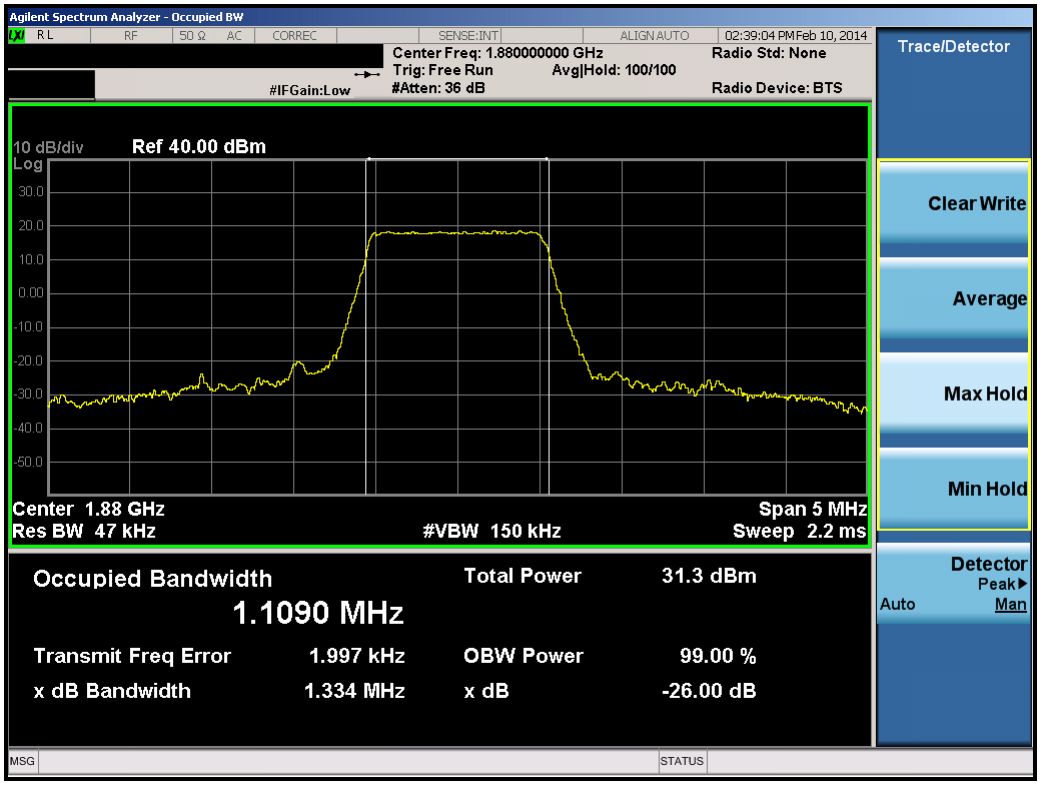


Plot 8-2. Lower Extended Band Edge Plot (1.4MHz QPSK – RB Size 6)



Plot 8-3. Occupied Bandwidth Plot (1.4MHz QPSK – RB Size 6)

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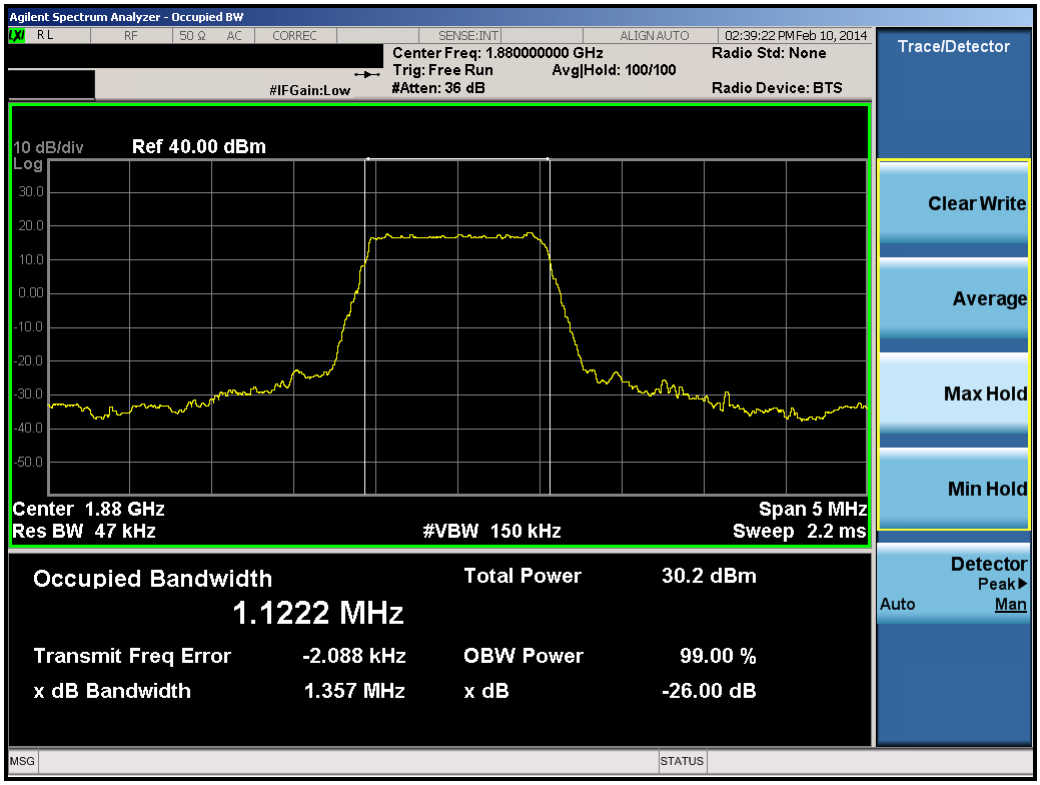
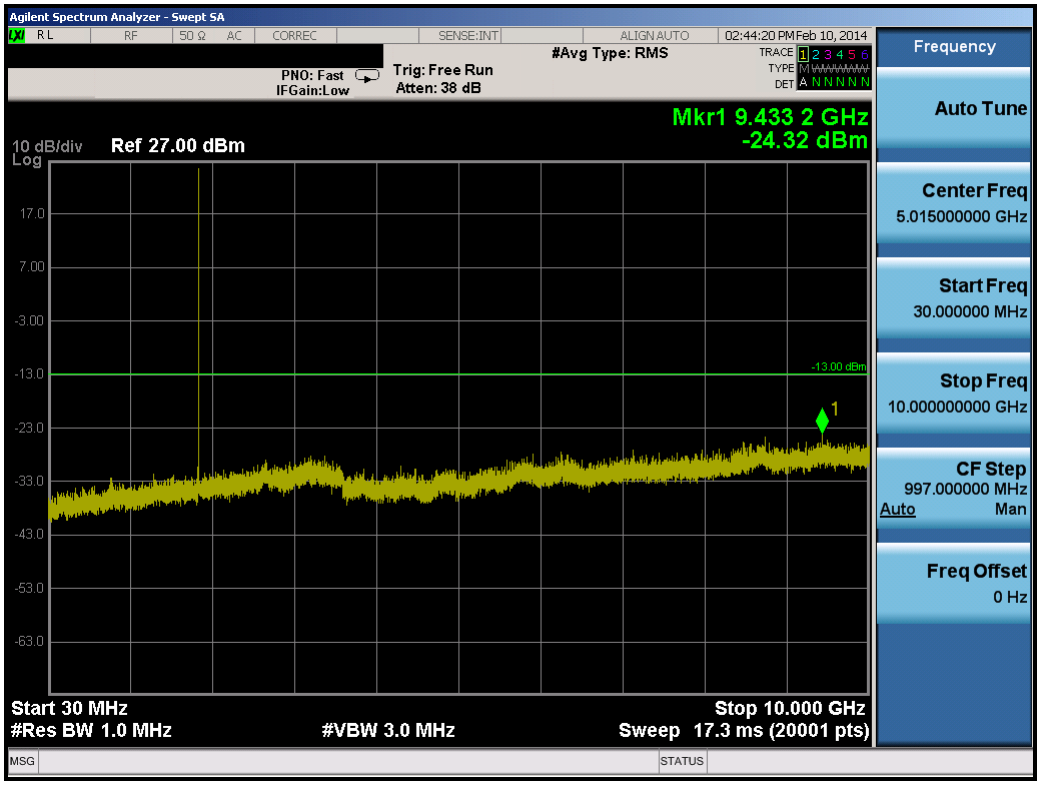


Plot 8-4. Occupied Bandwidth Plot (1.4MHz 16-QAM – RB Size 6)



Plot 8-5. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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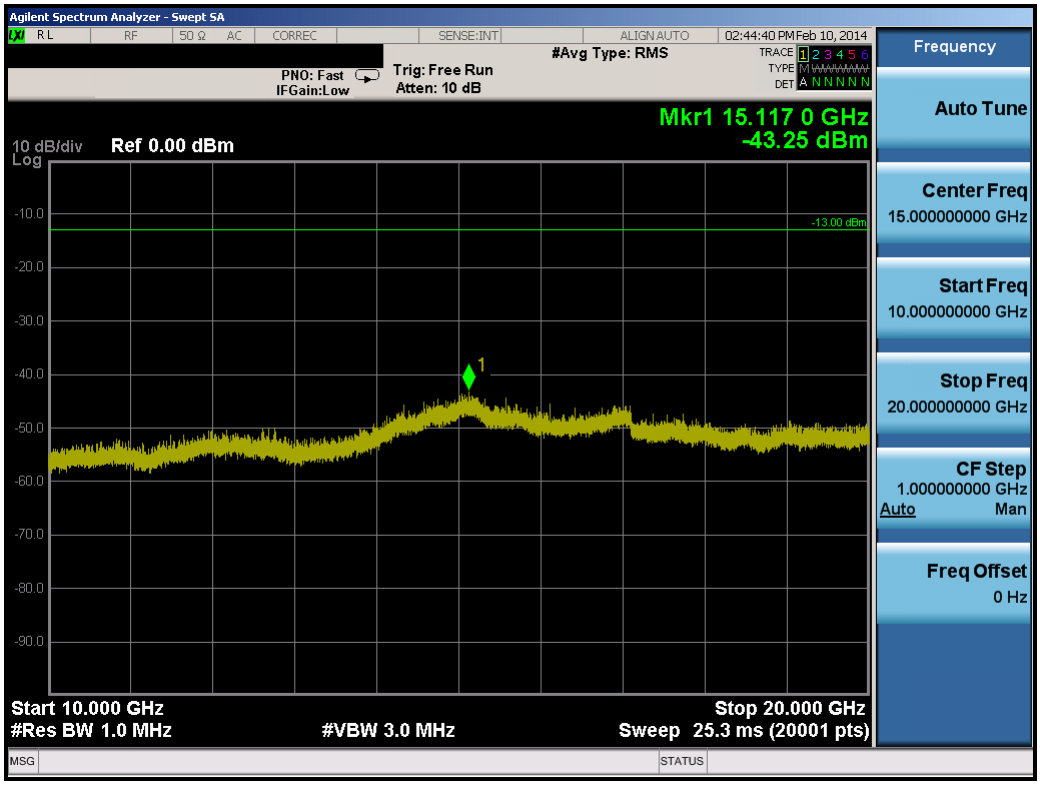
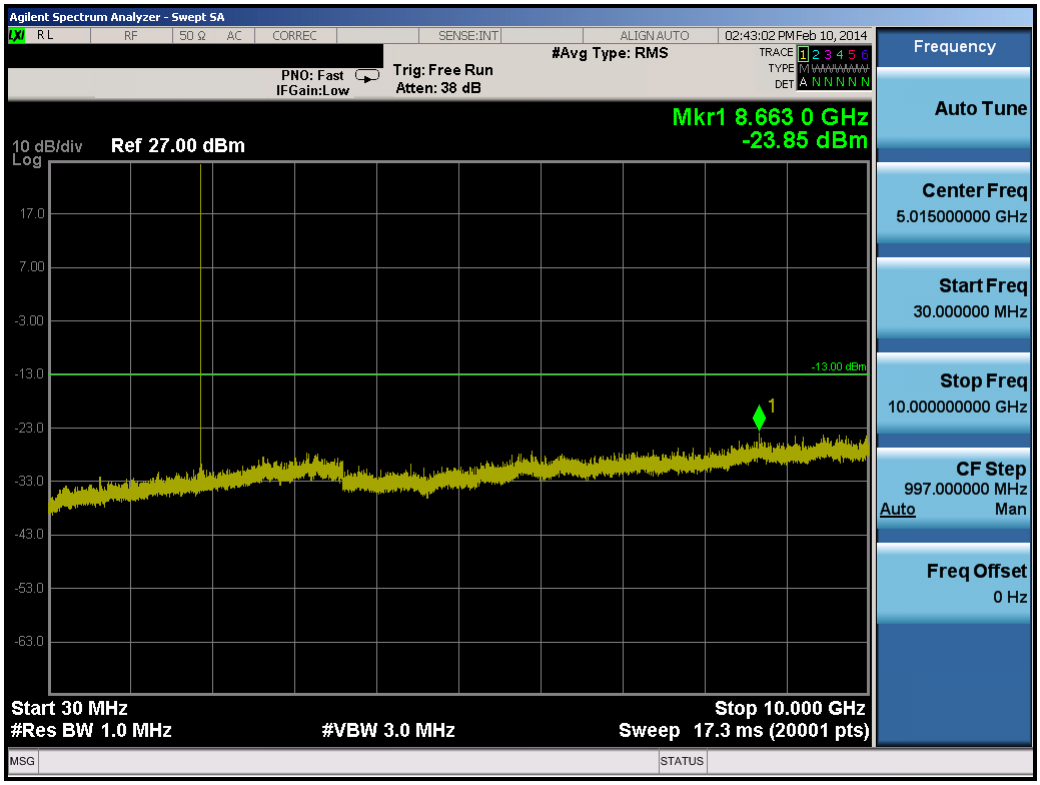


Plot 8-6. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 8-7. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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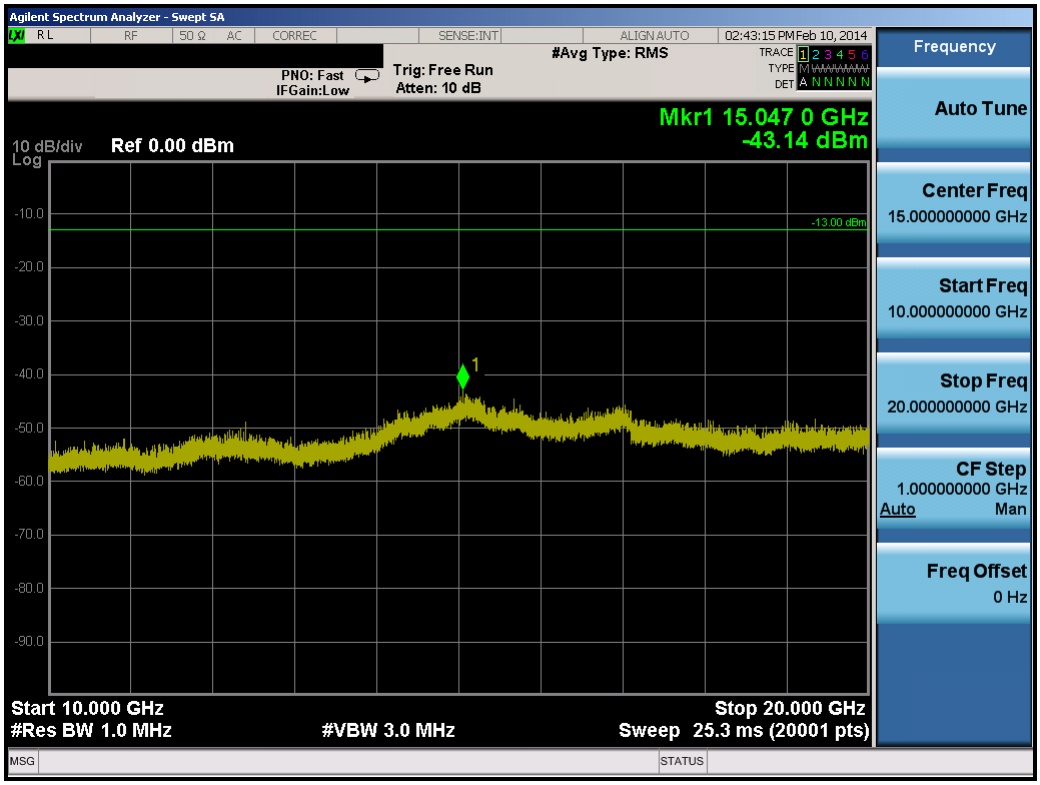
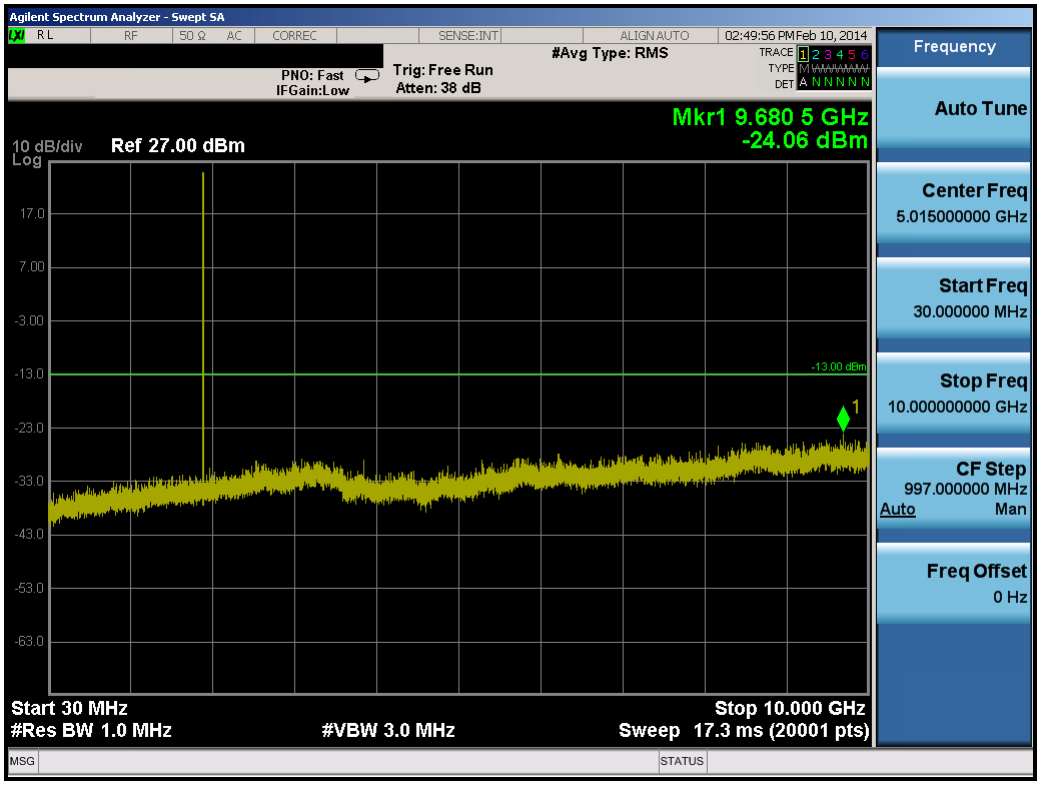


Plot 8-8. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 8-9. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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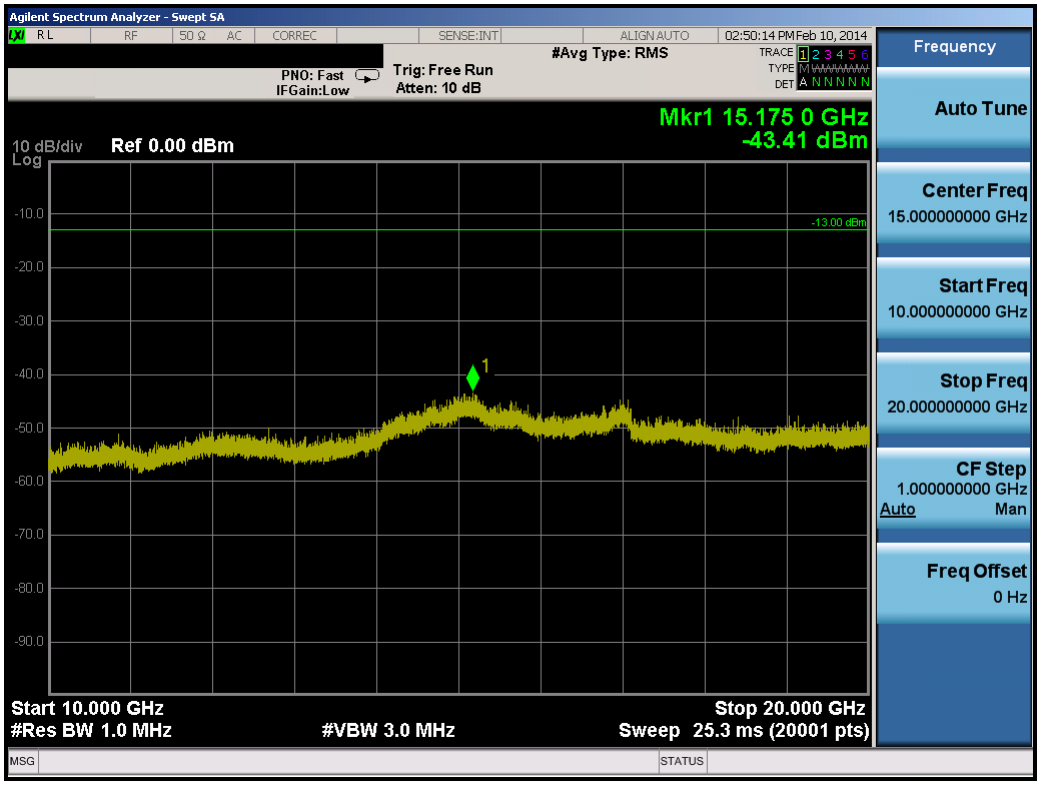
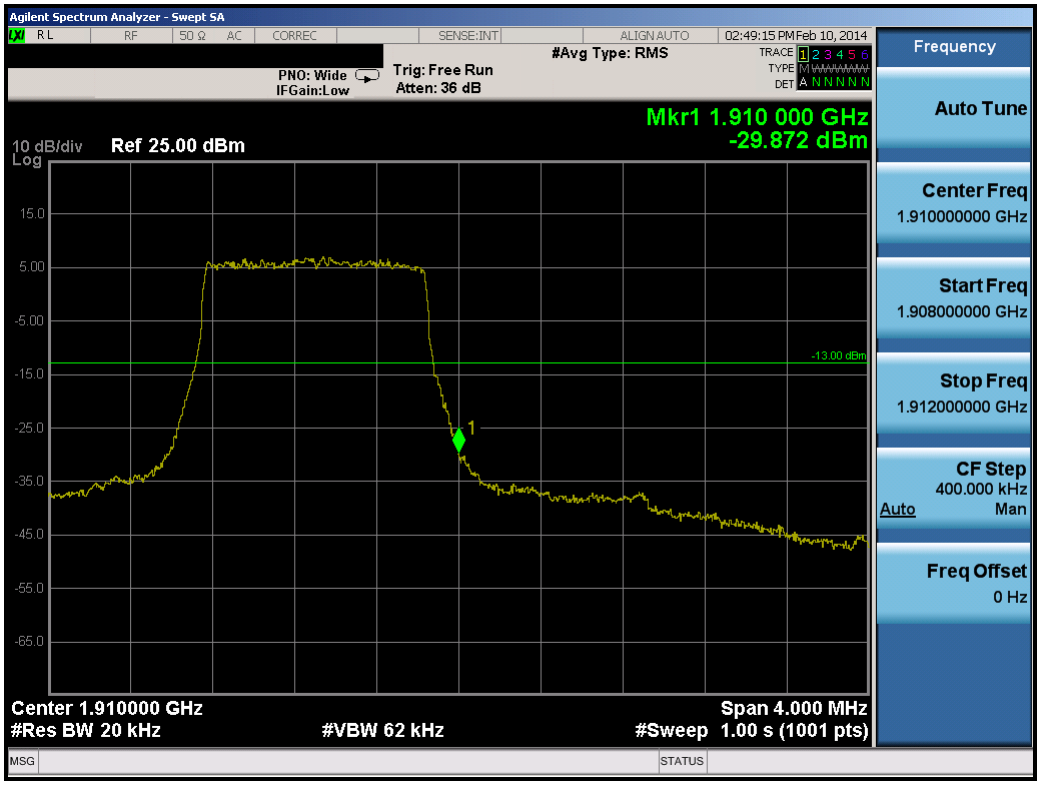


Plot 8-10. Conducted Spurious Plot (1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 8-11. Upper Band Edge Plot (1.4MHz QPSK – RB Size 6)

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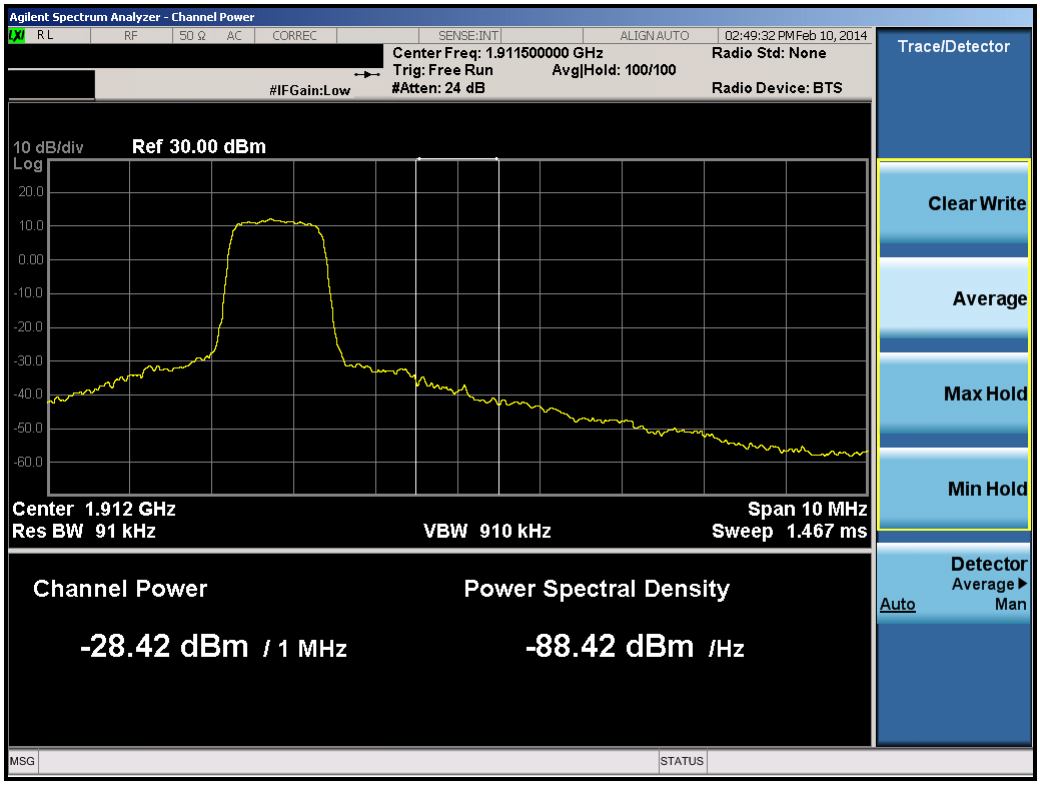
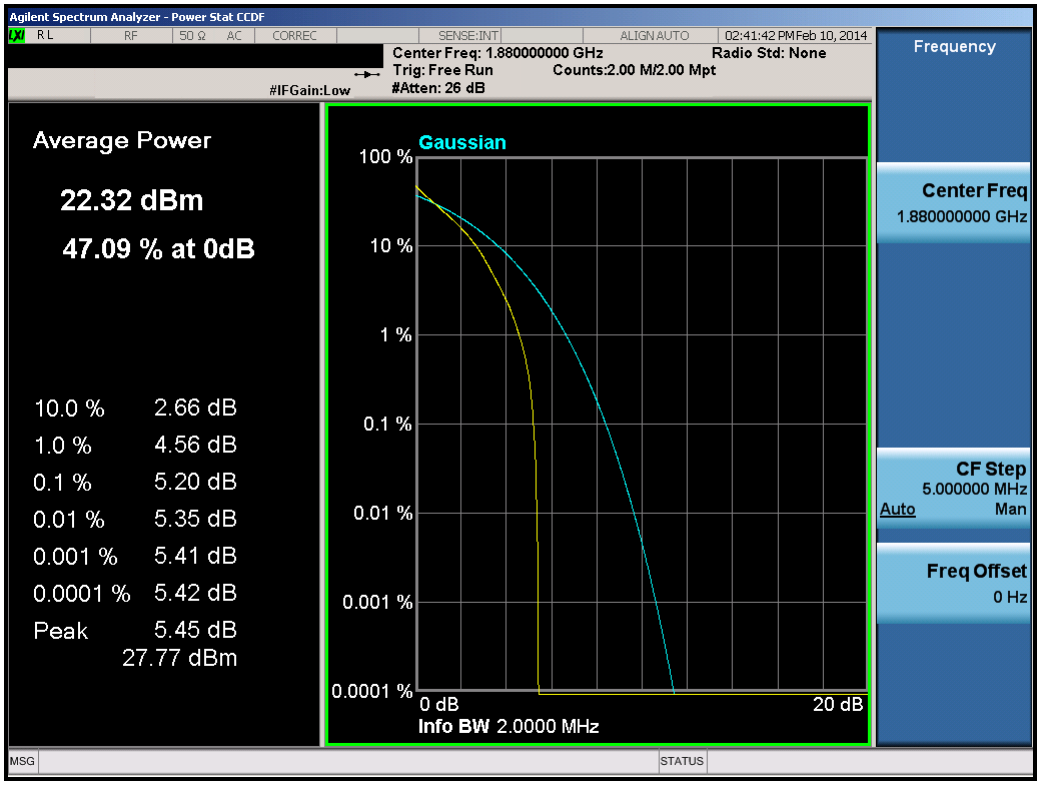


Plot 8-12. Upper Extended Band Edge Plot (1.4MHz QPSK – RB Size 6)



Plot 8-13. PAR Plot (1.4MHz QPSK – RB Size 6)

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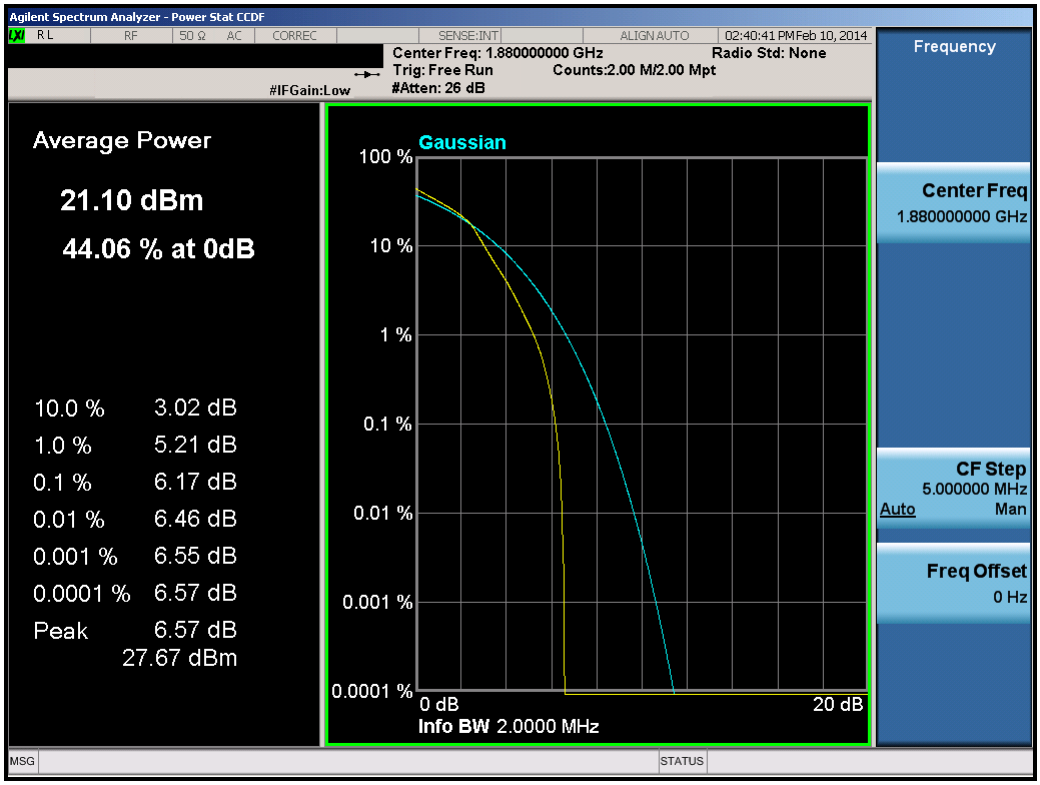

Plot 8-14. PAR Plot (1.4MHz 16-QAM – RB Size 6)

Plot 8-15. Lower Band Edge Plot (3.0MHz QPSK – RB Size 15)

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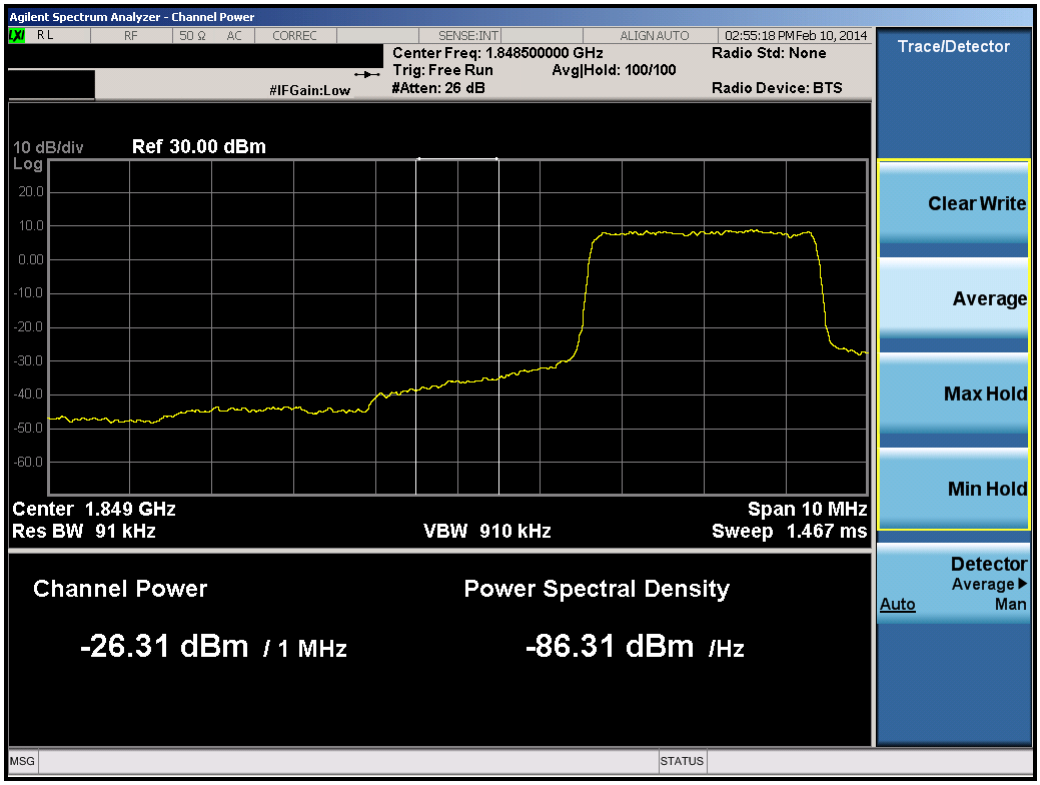
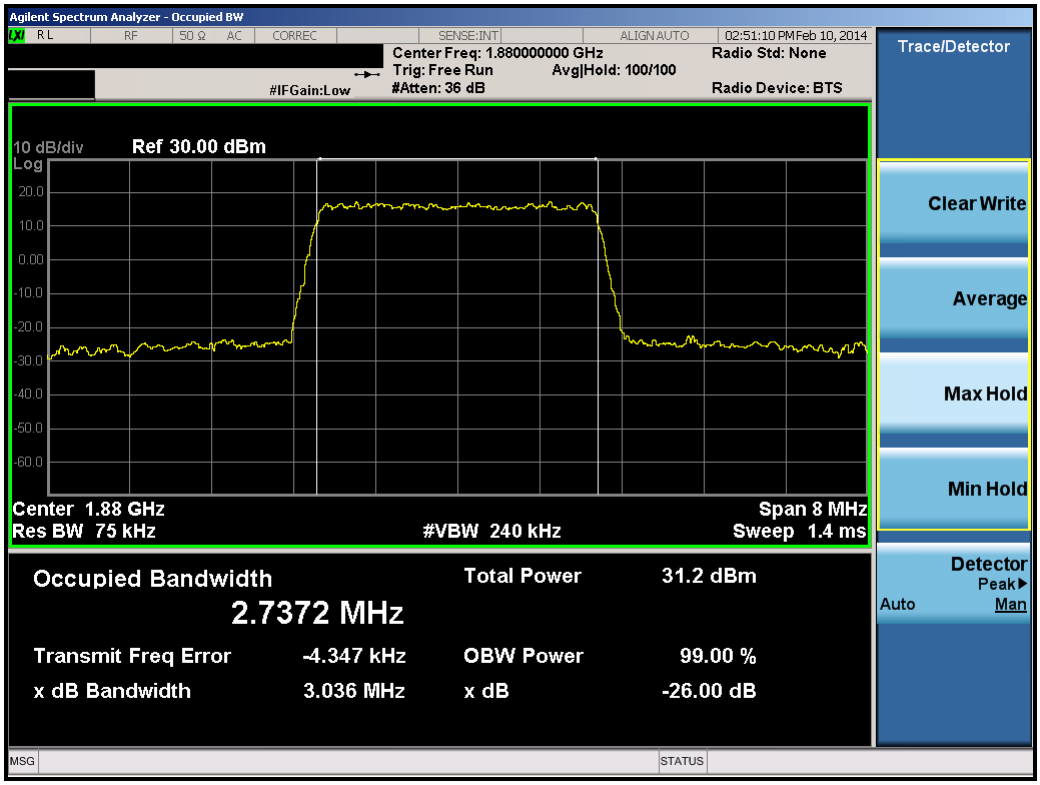


Plot 8-16. Lower Extended Band Edge Plot (3.0MHz QPSK – RB Size 15)



Plot 8-17. Occupied Bandwidth Plot (3.0MHz QPSK – RB Size 15)

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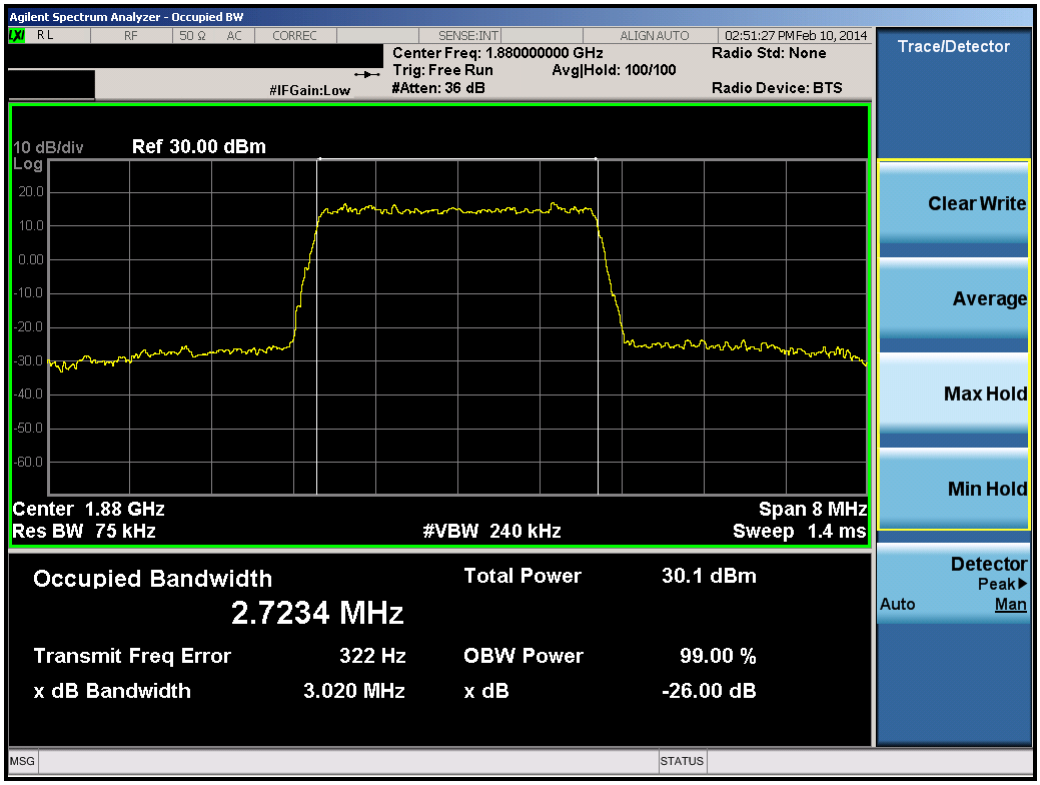
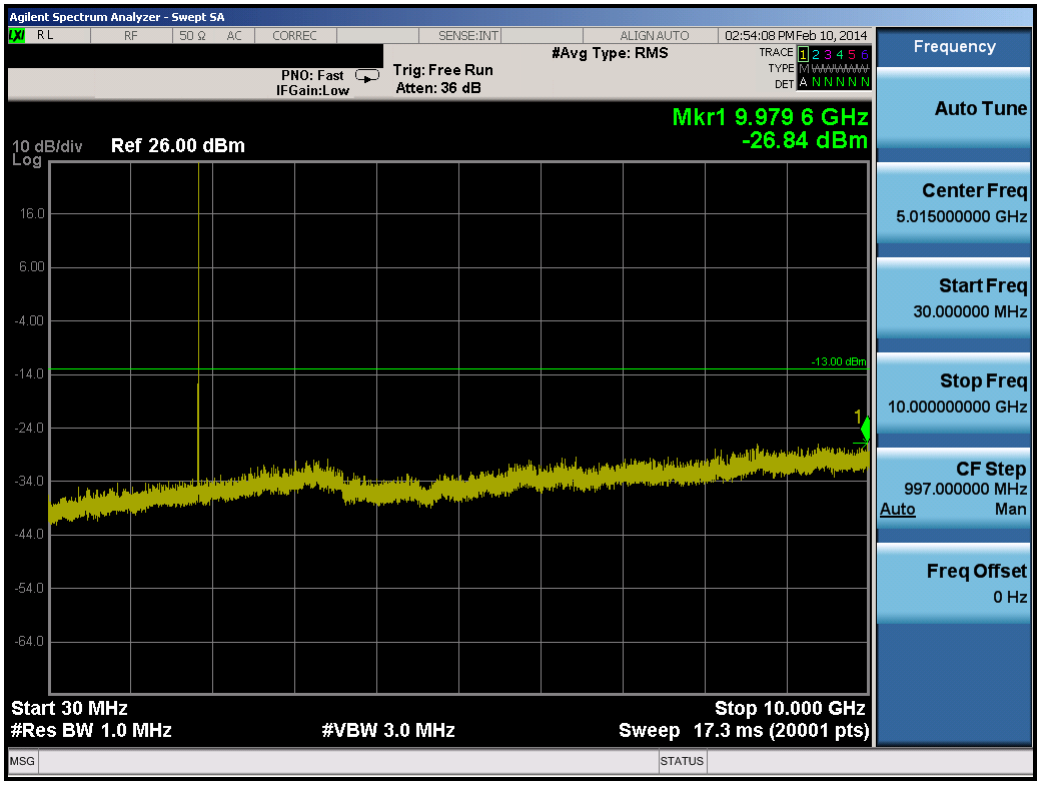


Plot 8-18. Occupied Bandwidth Plot (3.0MHz 16-QAM – RB Size 15)



Plot 8-19. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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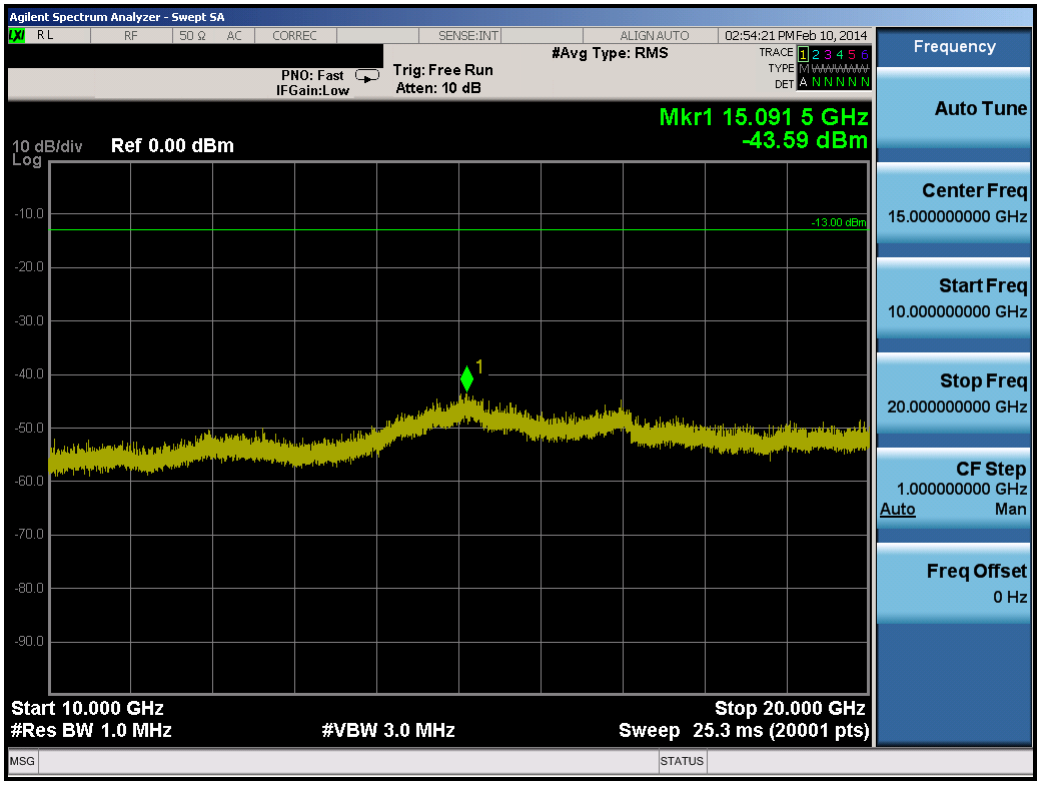
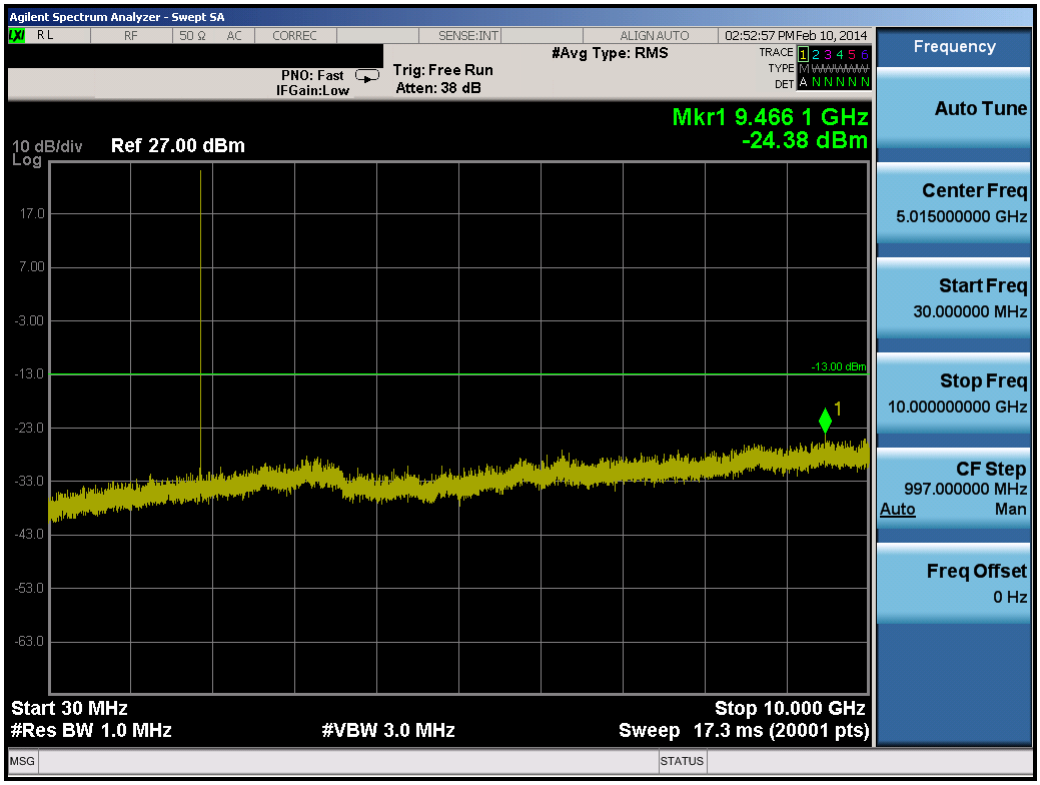


Plot 8-20. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 8-21. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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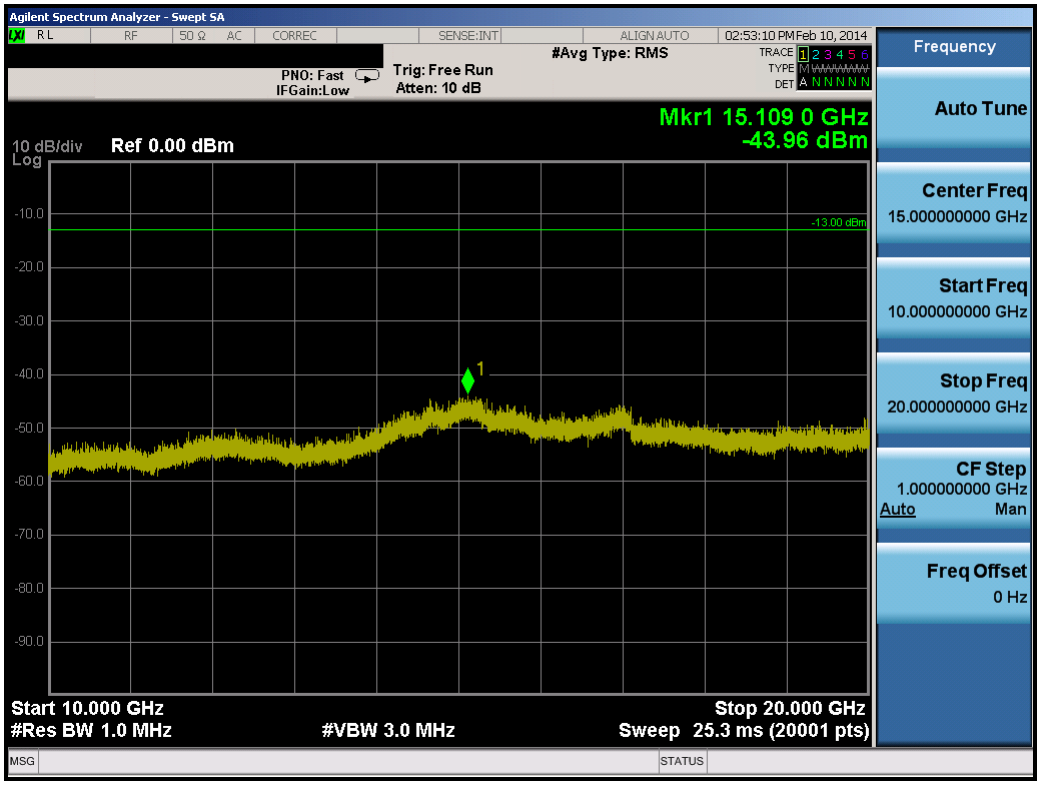
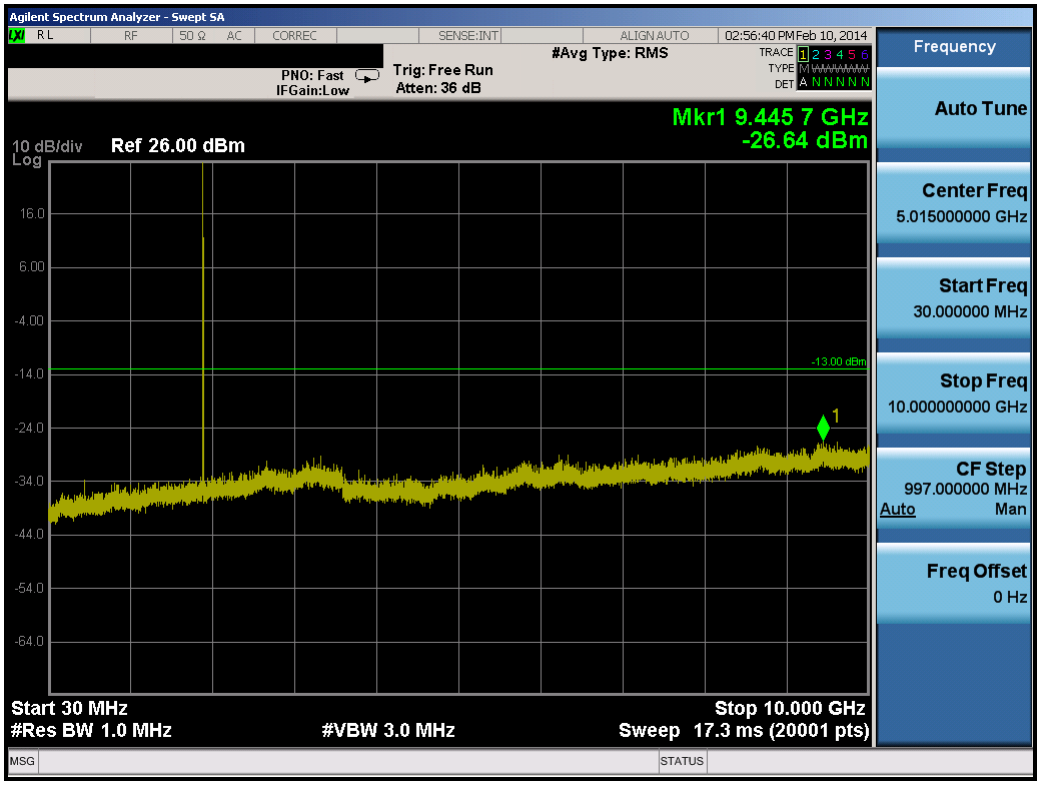


Plot 8-22. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 8-23. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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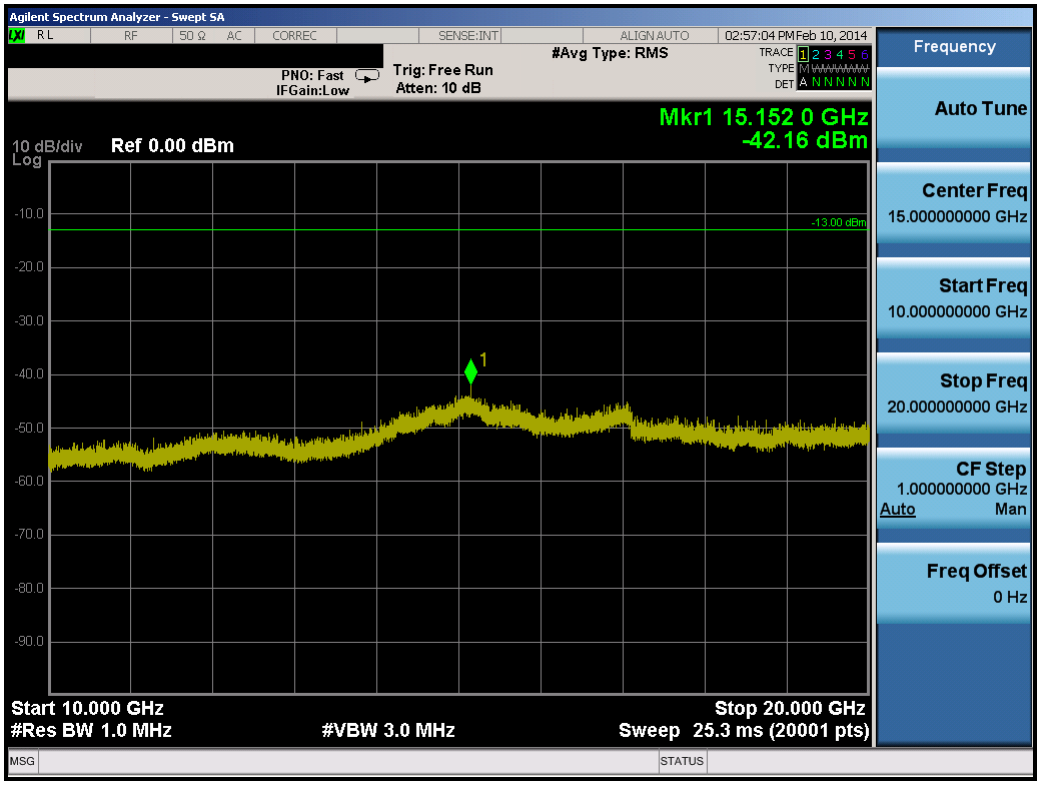
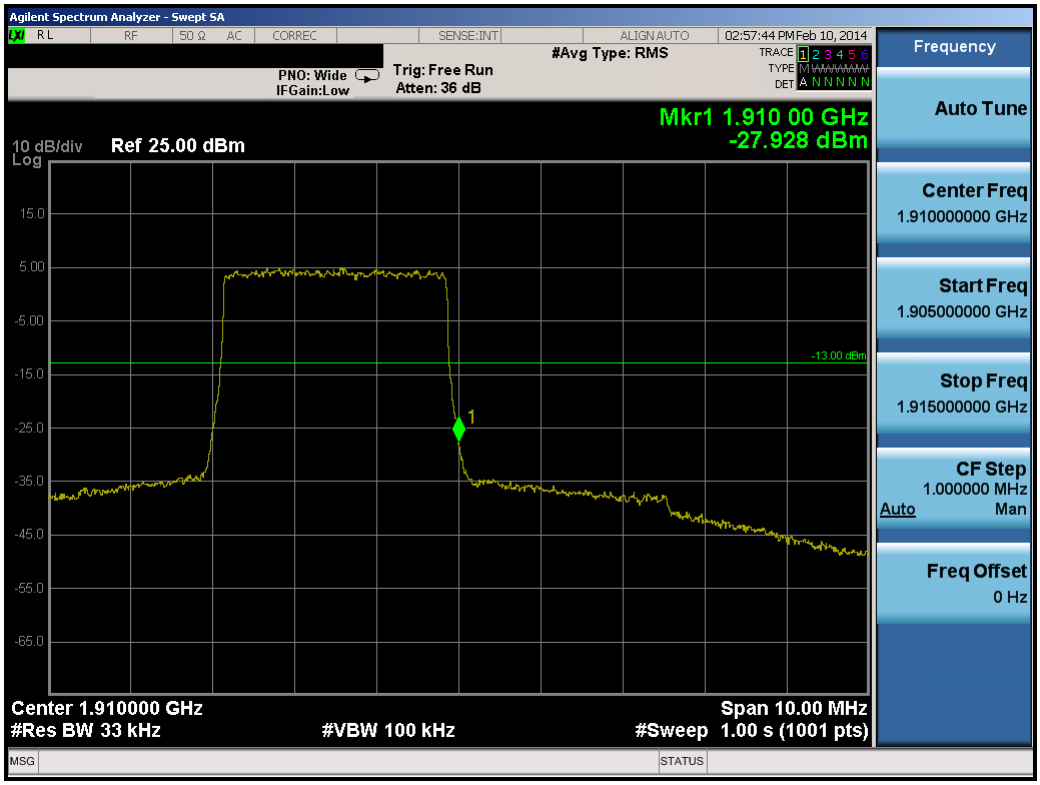


Plot 8-24. Conducted Spurious Plot (3.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 8-25. Upper Band Edge Plot (3.0MHz QPSK – RB Size 15)

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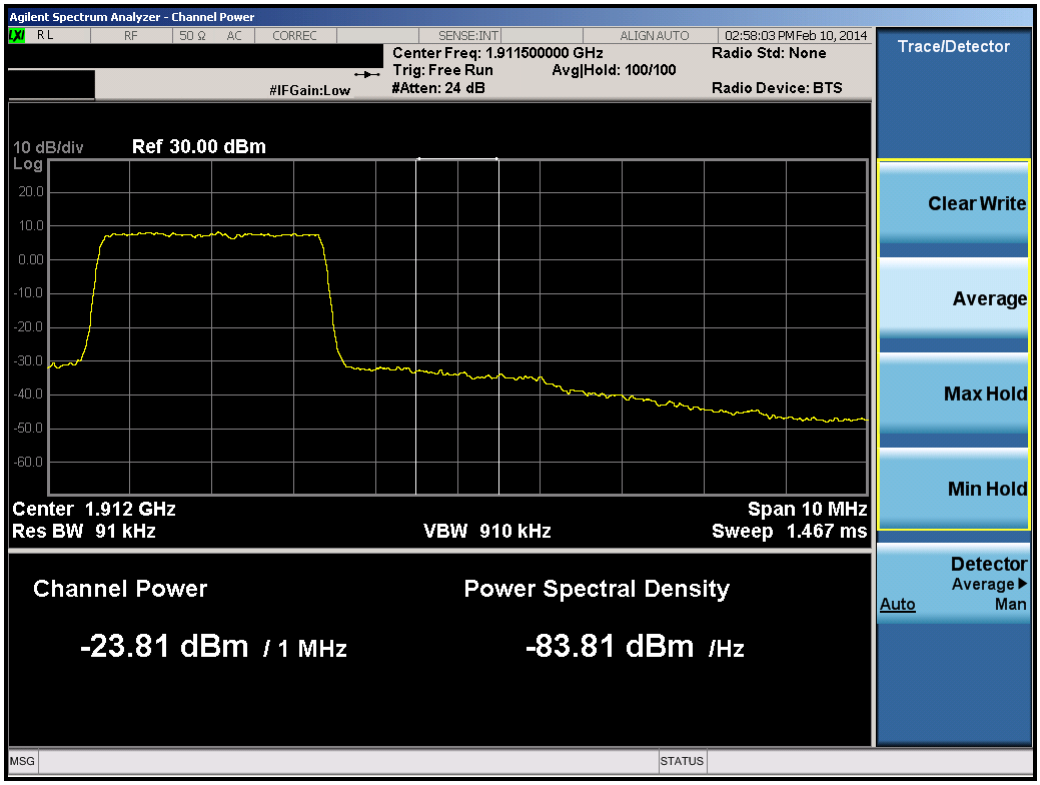
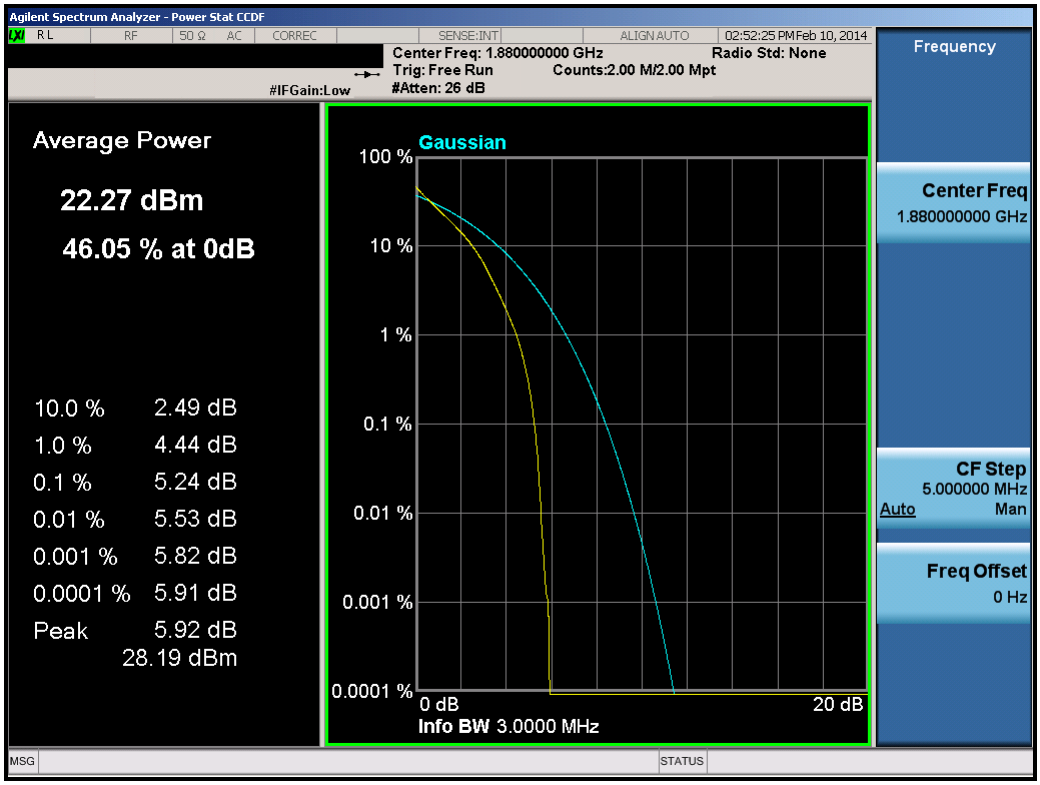


Plot 8-26. Upper Extended Band Edge Plot (3.0MHz QPSK – RB Size 15)



Plot 8-27. PAR Plot (3.0MHz QPSK – RB Size 15)

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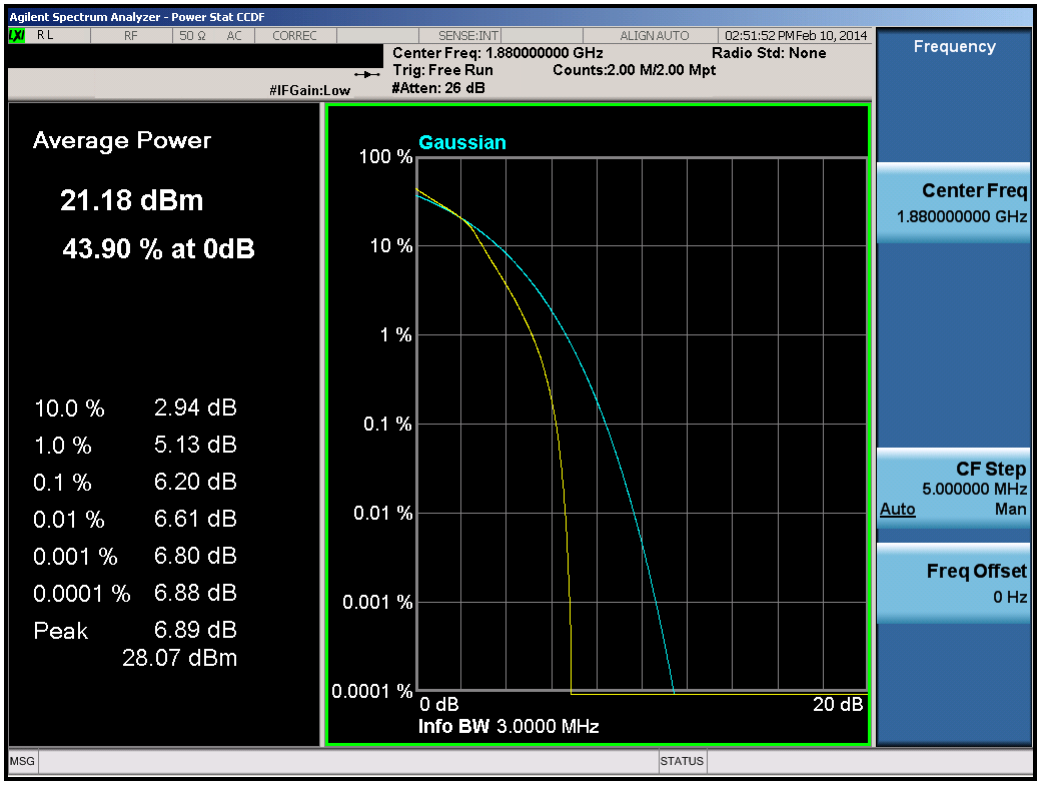
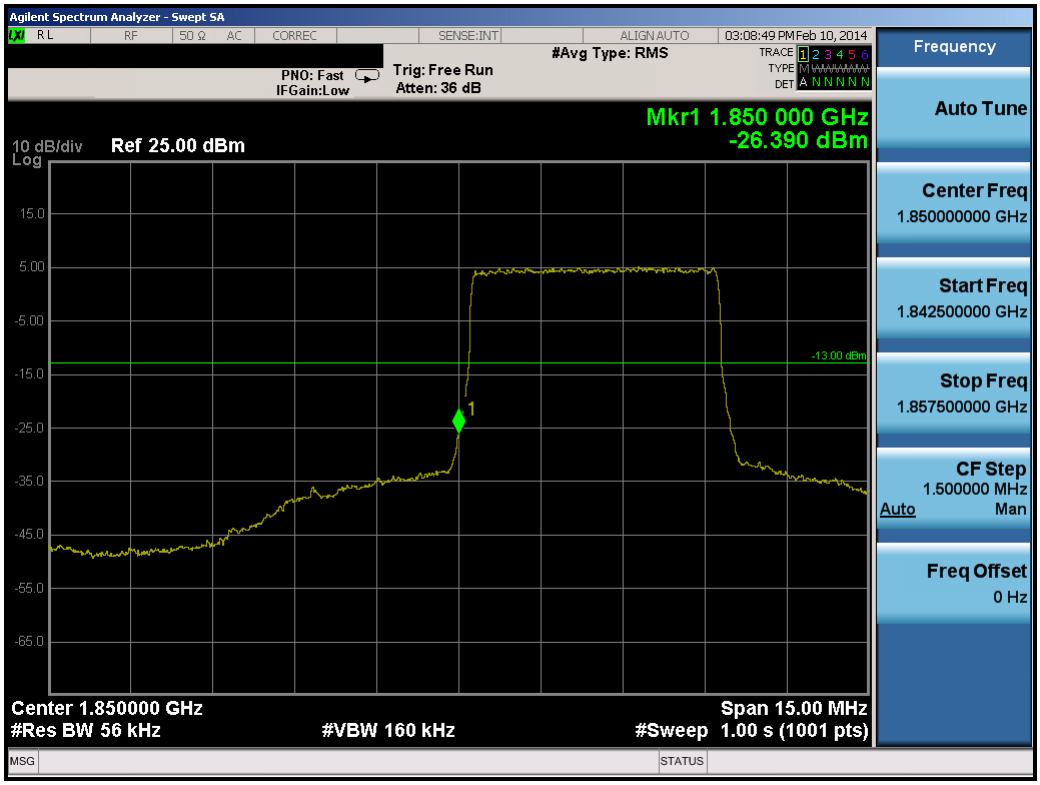


Plot 8-28. PAR Plot (3.0MHz 16-QAM – RB Size 15)



Plot 8-29. Lower Band Edge Plot (5.0MHz QPSK – RB Size 25)

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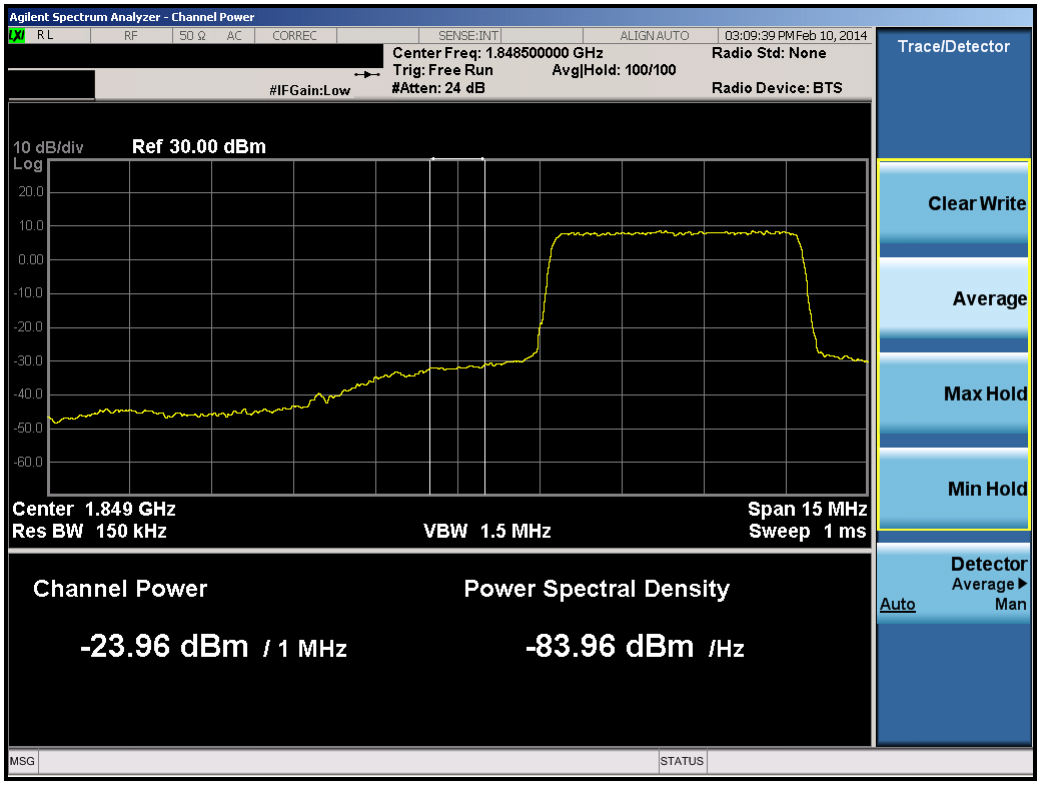

Plot 8-30. Lower Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)

Plot 8-31. Occupied Bandwidth Plot (5.0MHz QPSK – RB Size 25)

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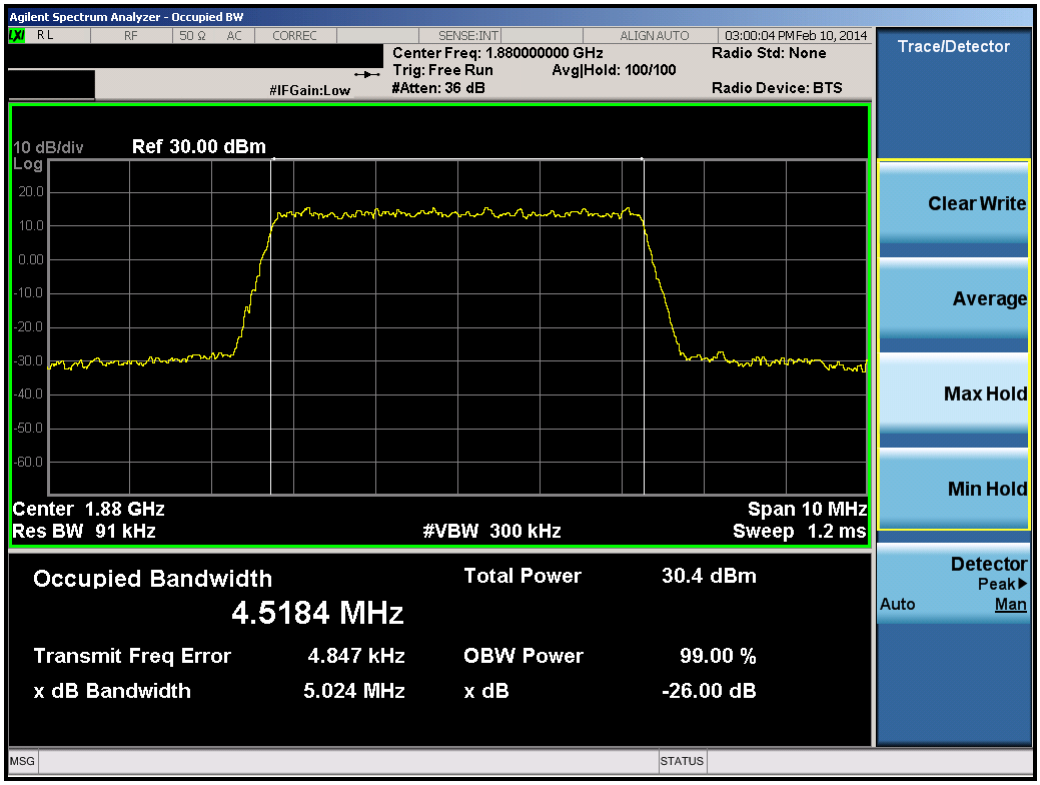
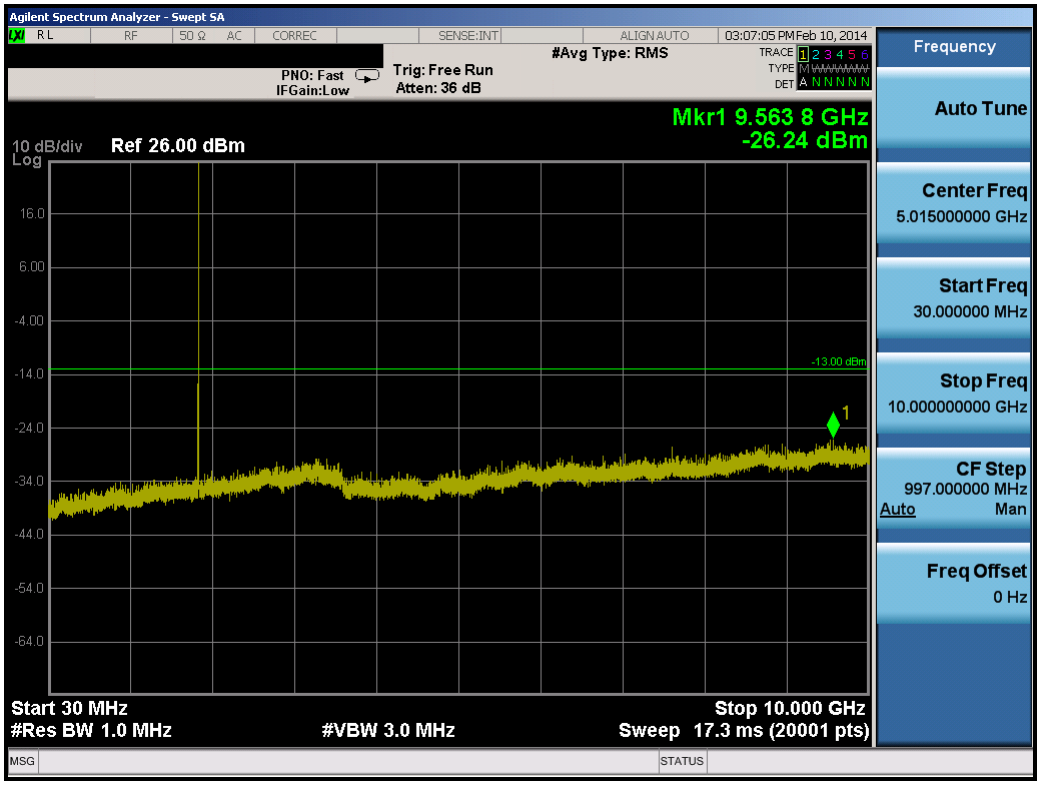


Plot 8-32. Occupied Bandwidth Plot (5.0MHz 16-QAM – RB Size 25)



Plot 8-33. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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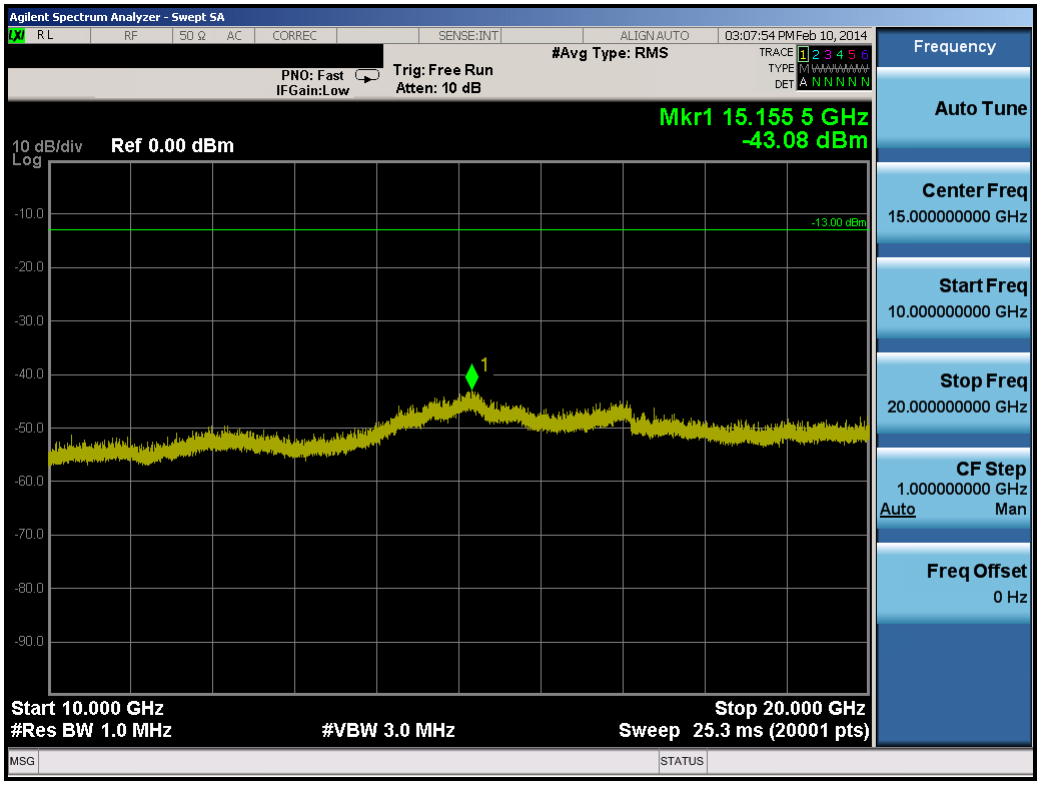
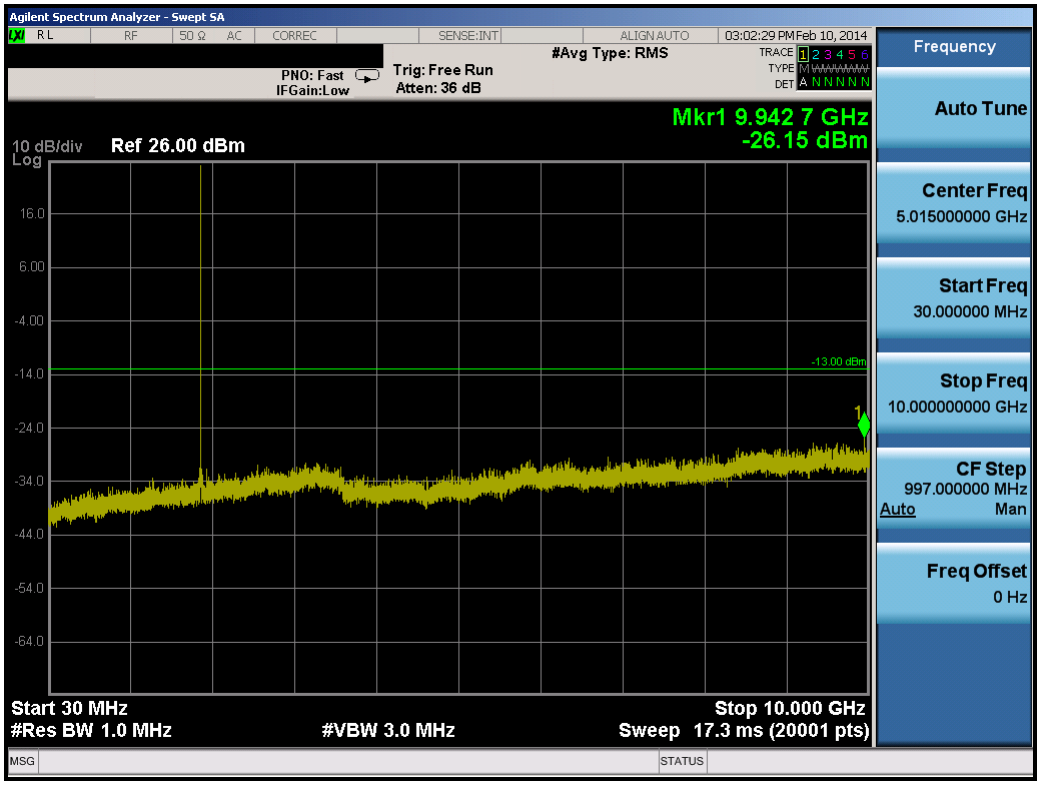


Plot 8-34. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 8-35. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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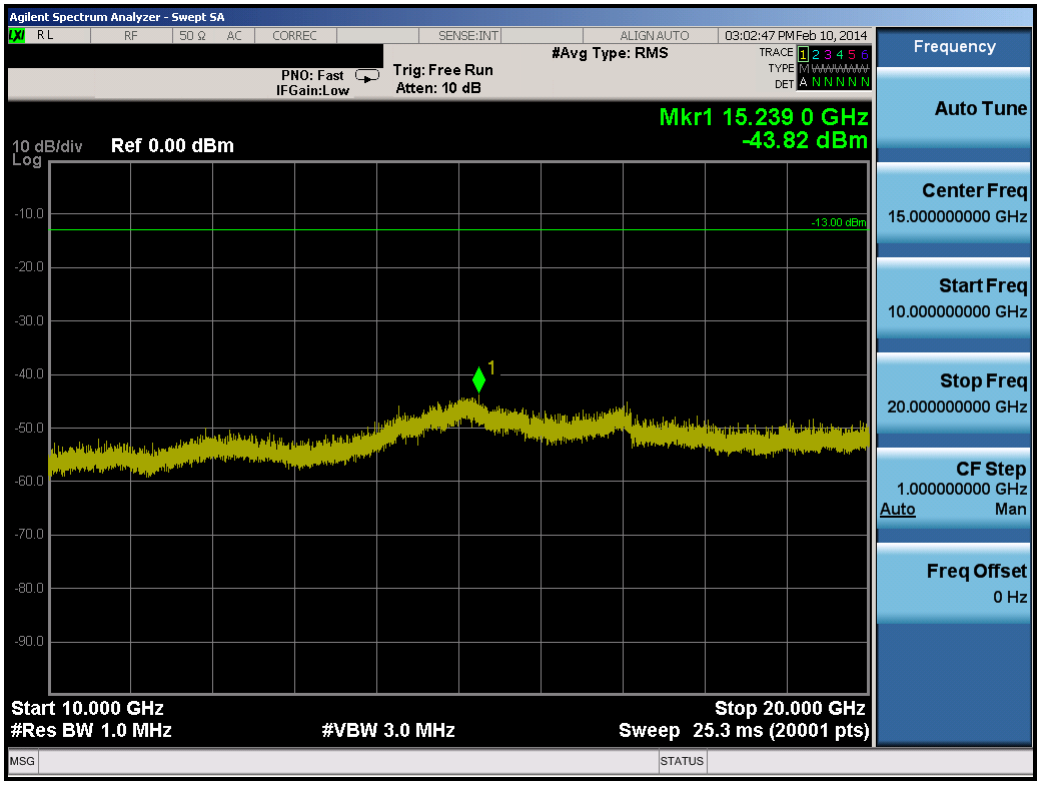
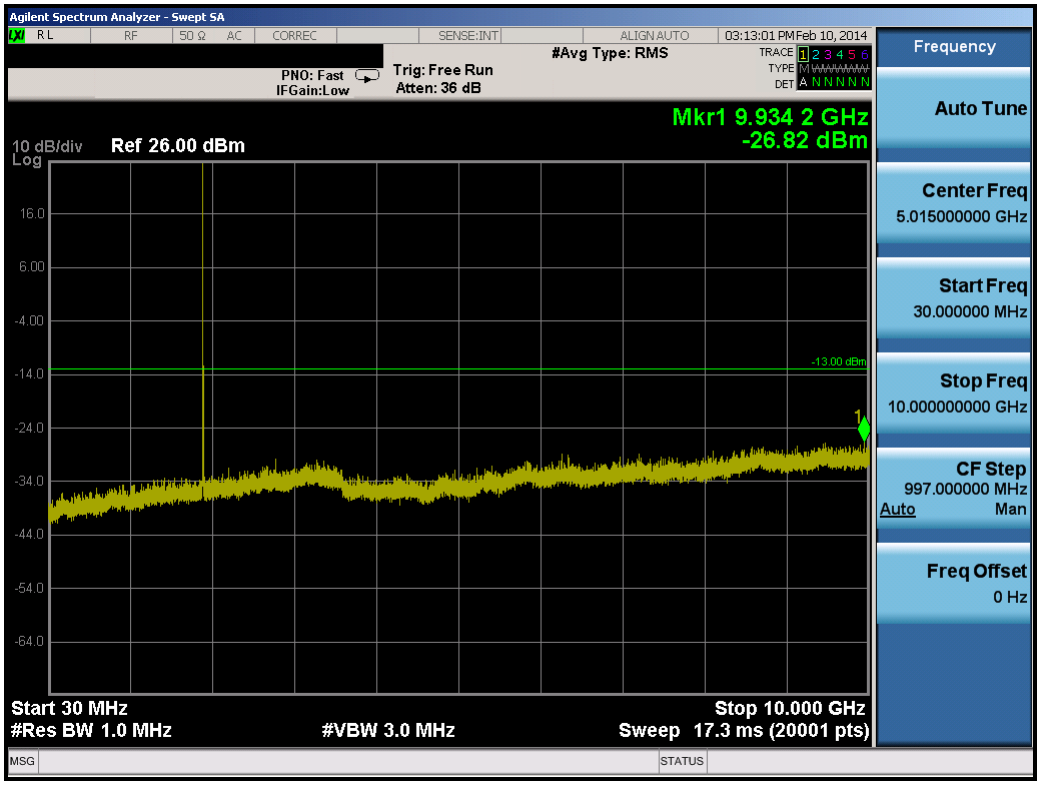


Plot 8-36. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 8-37. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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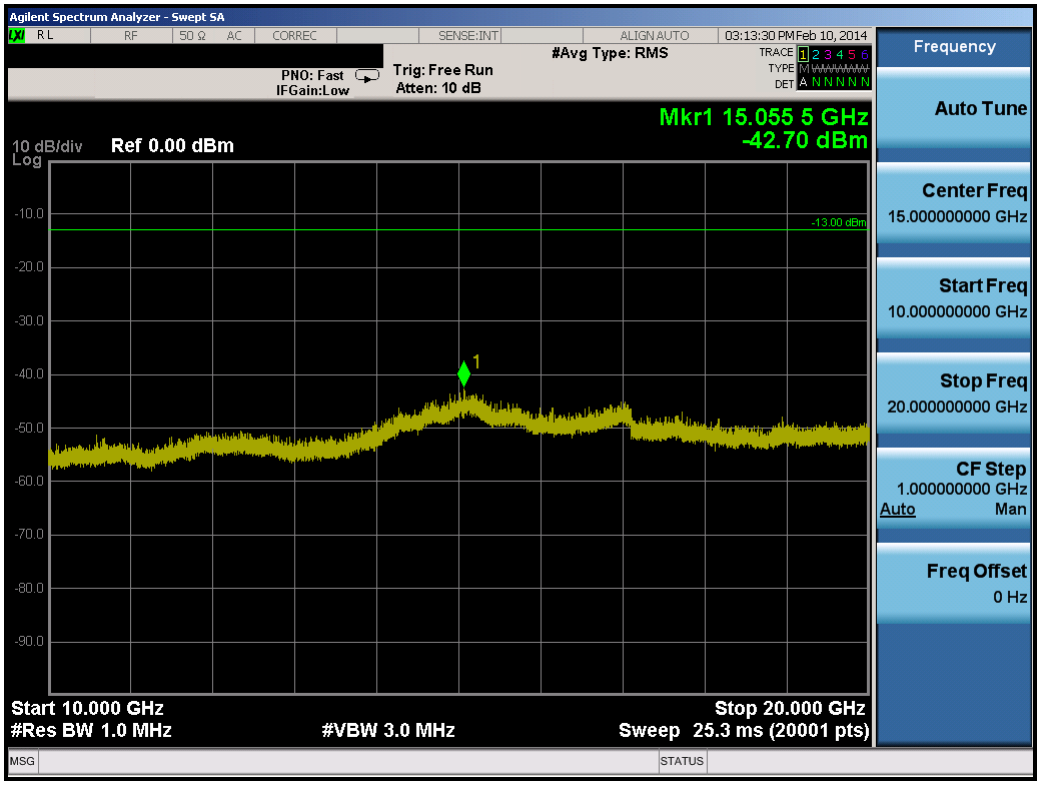
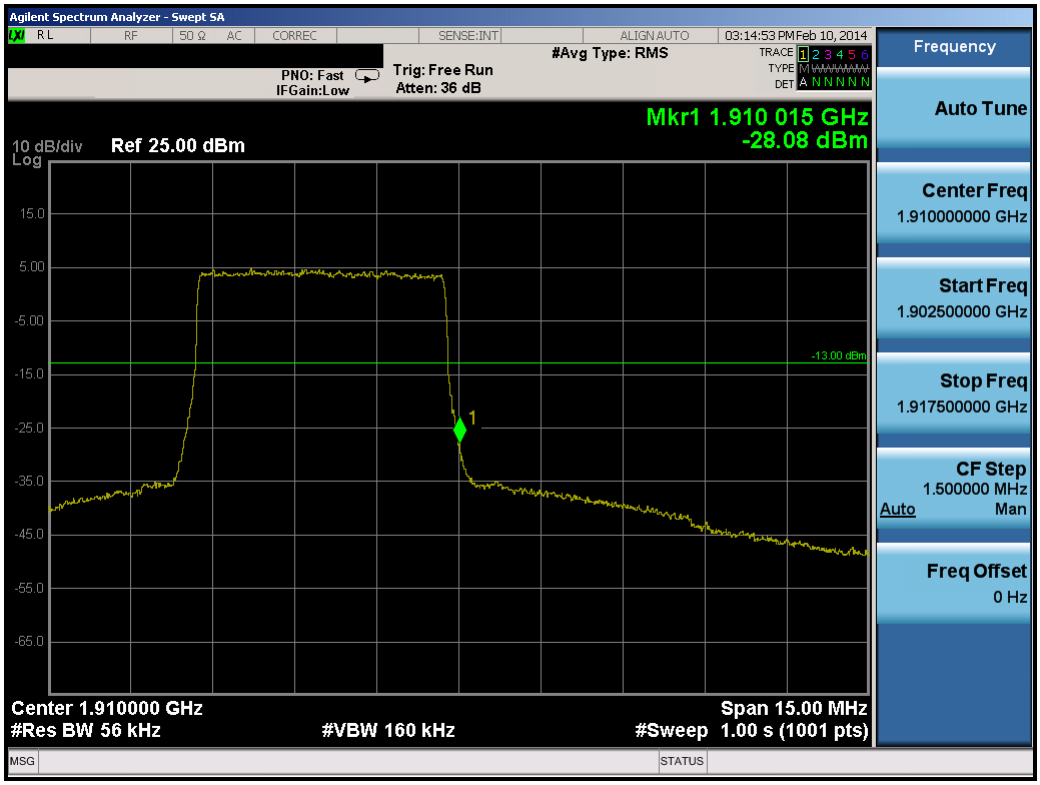


Plot 8-38. Conducted Spurious Plot (5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 8-39. Upper Band Edge Plot (5.0MHz QPSK – RB Size 25)

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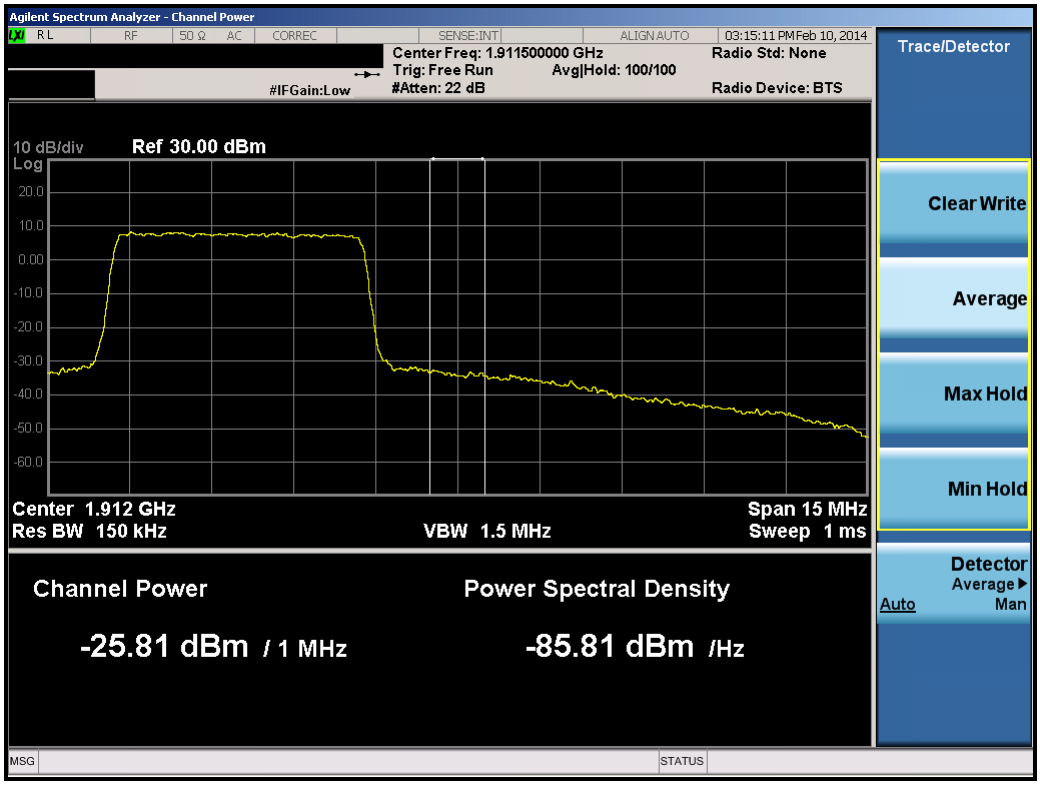
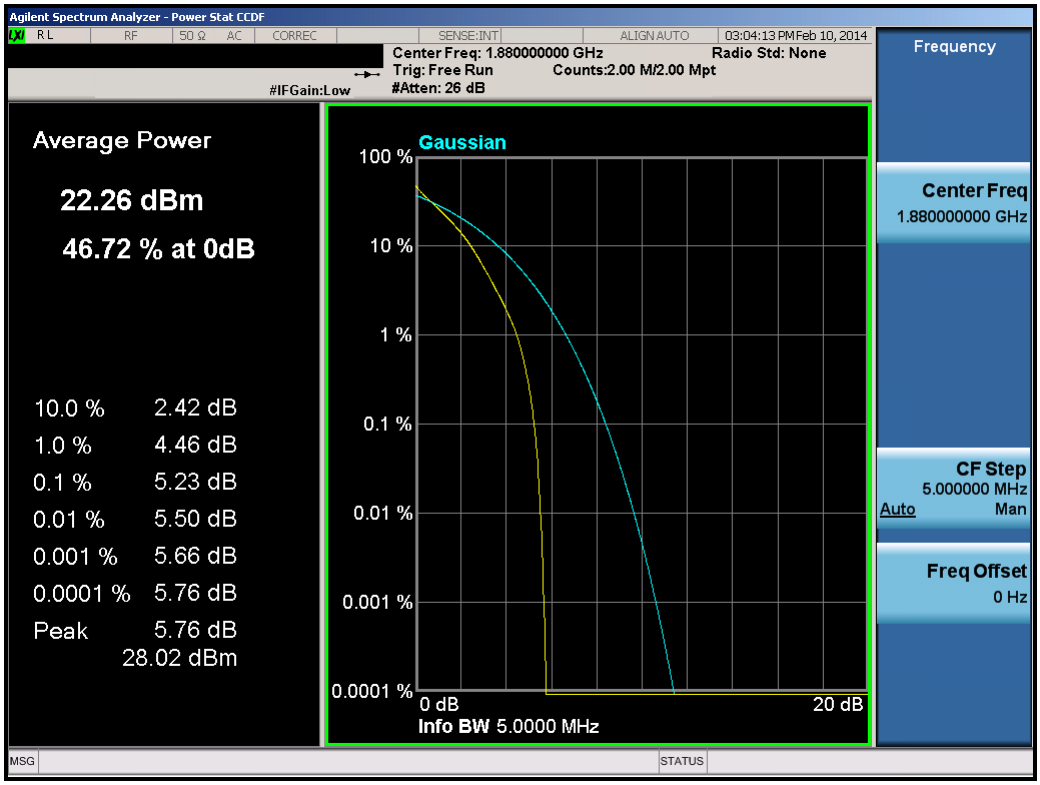


Plot 8-40. Upper Extended Band Edge Plot (5.0MHz QPSK – RB Size 25)



Plot 8-41. PAR Plot (5.0MHz QPSK – RB Size 25)

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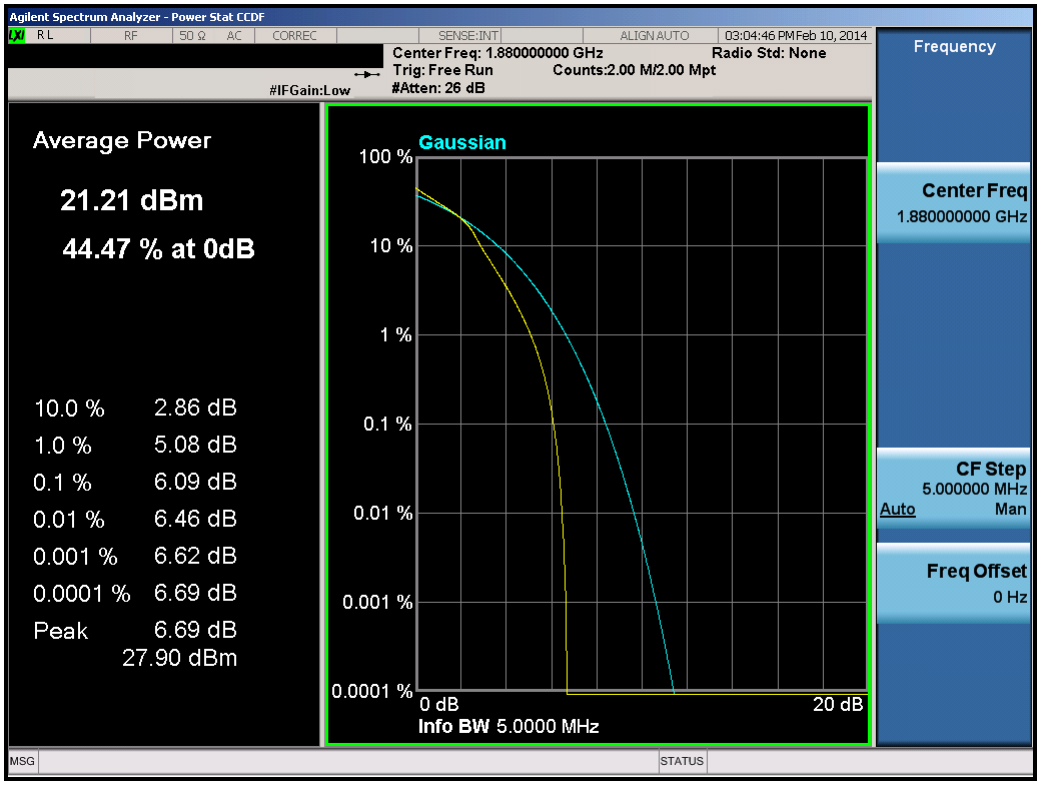
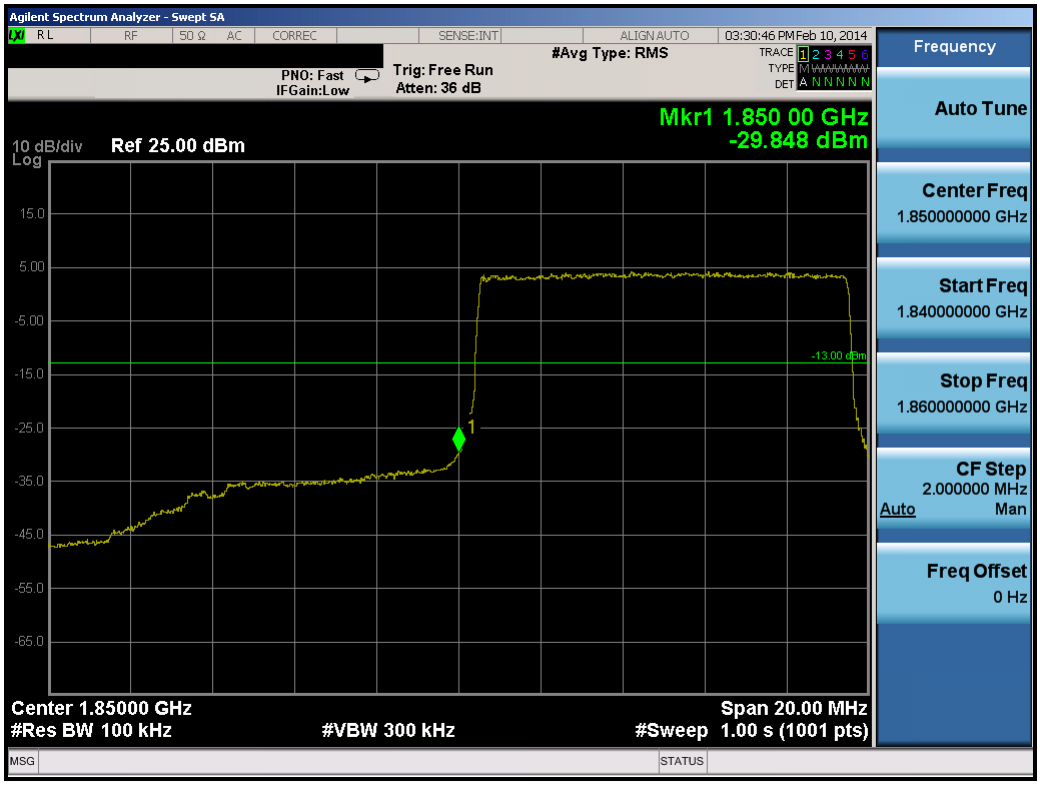


Plot 8-42. PAR Plot (5.0MHz 16-QAM – RB Size 25)



Plot 8-43. Lower Band Edge Plot (10.0MHz QPSK – RB Size 50)

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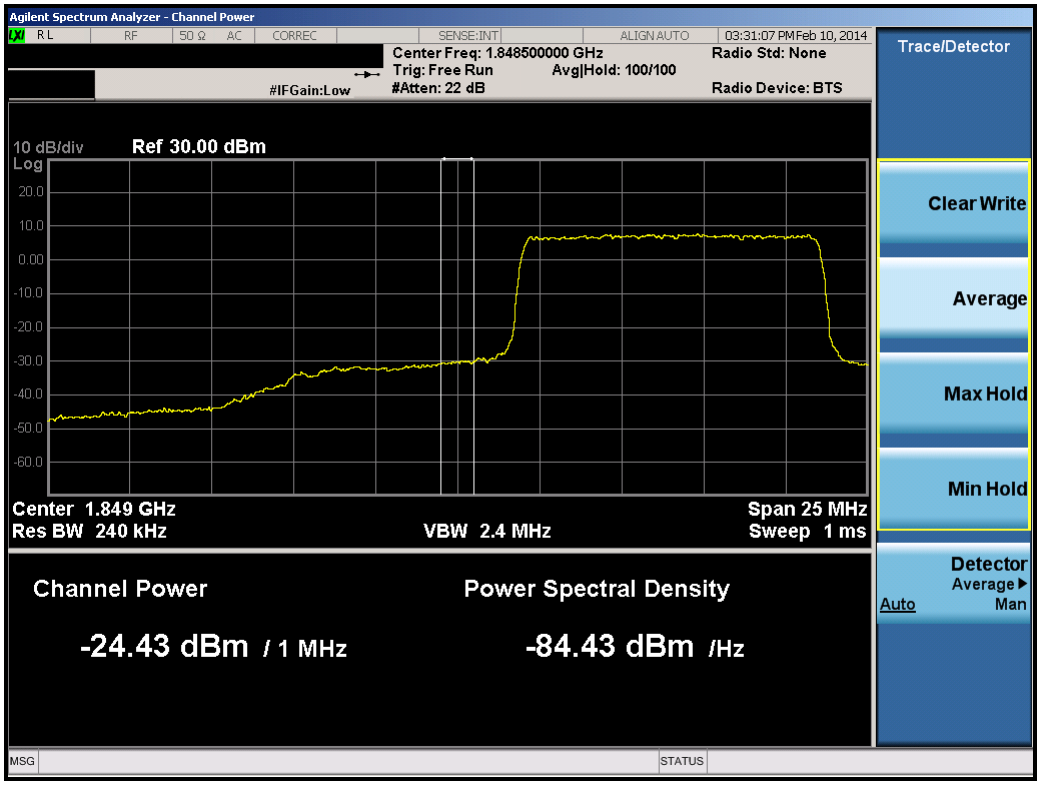
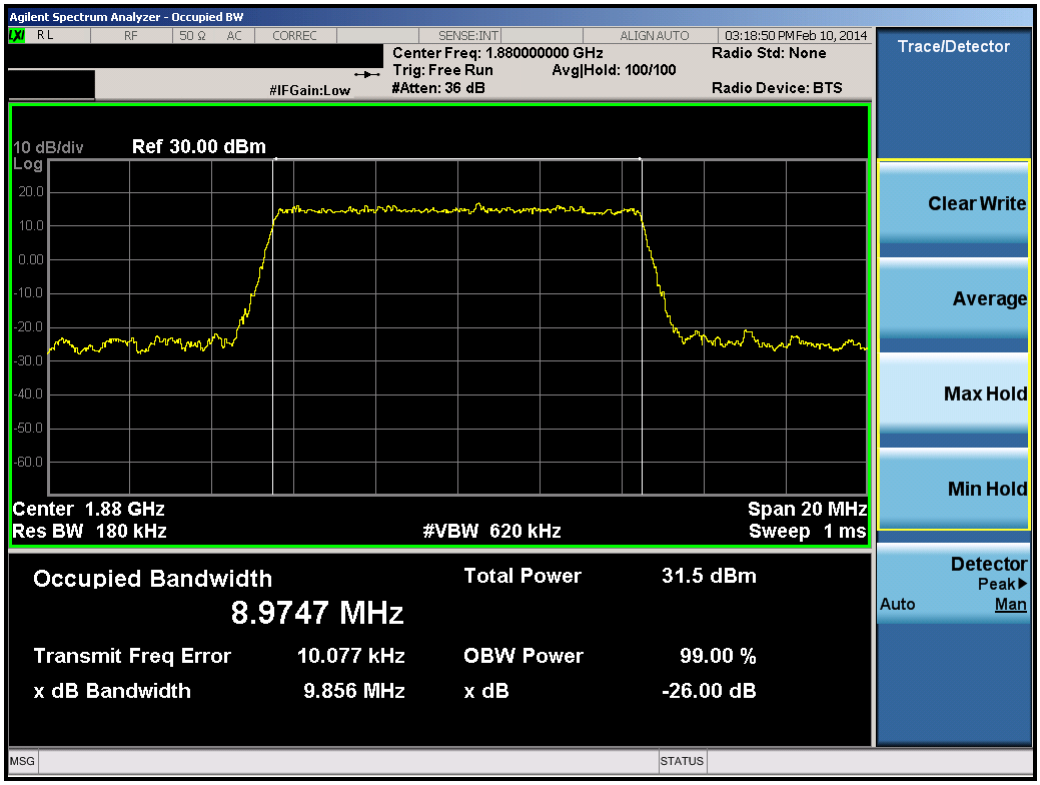


Plot 8-44. Lower Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)



Plot 8-45. Occupied Bandwidth Plot (10.0MHz QPSK – RB Size 50)

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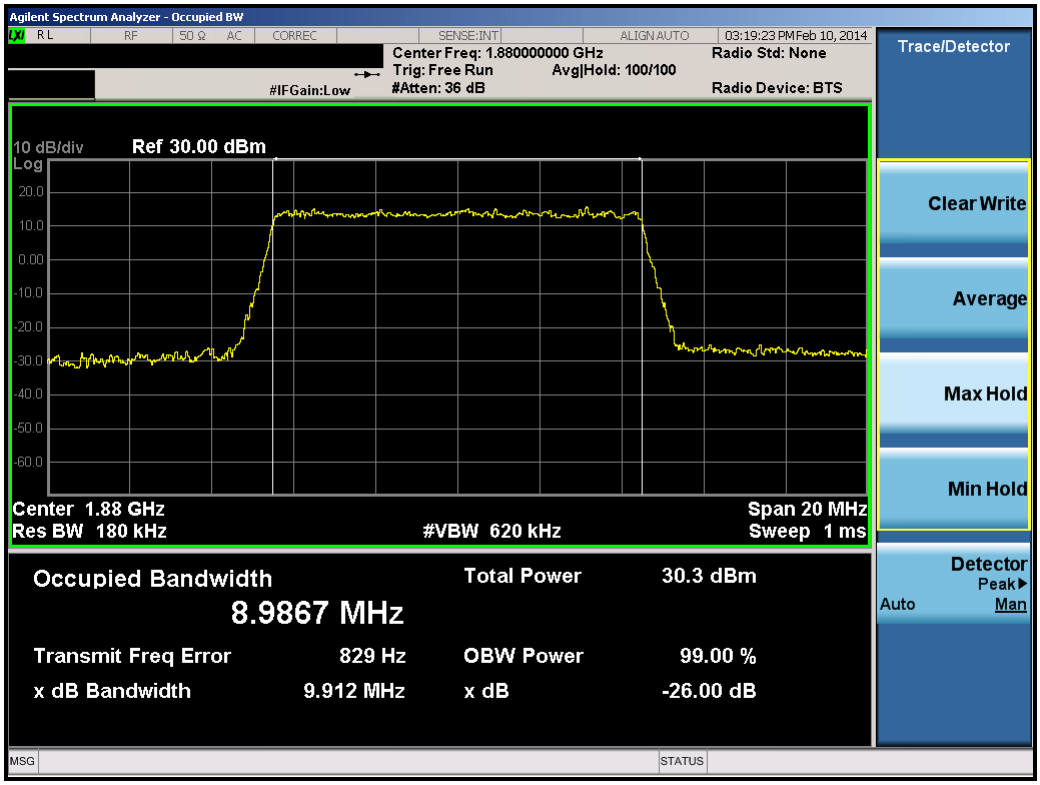
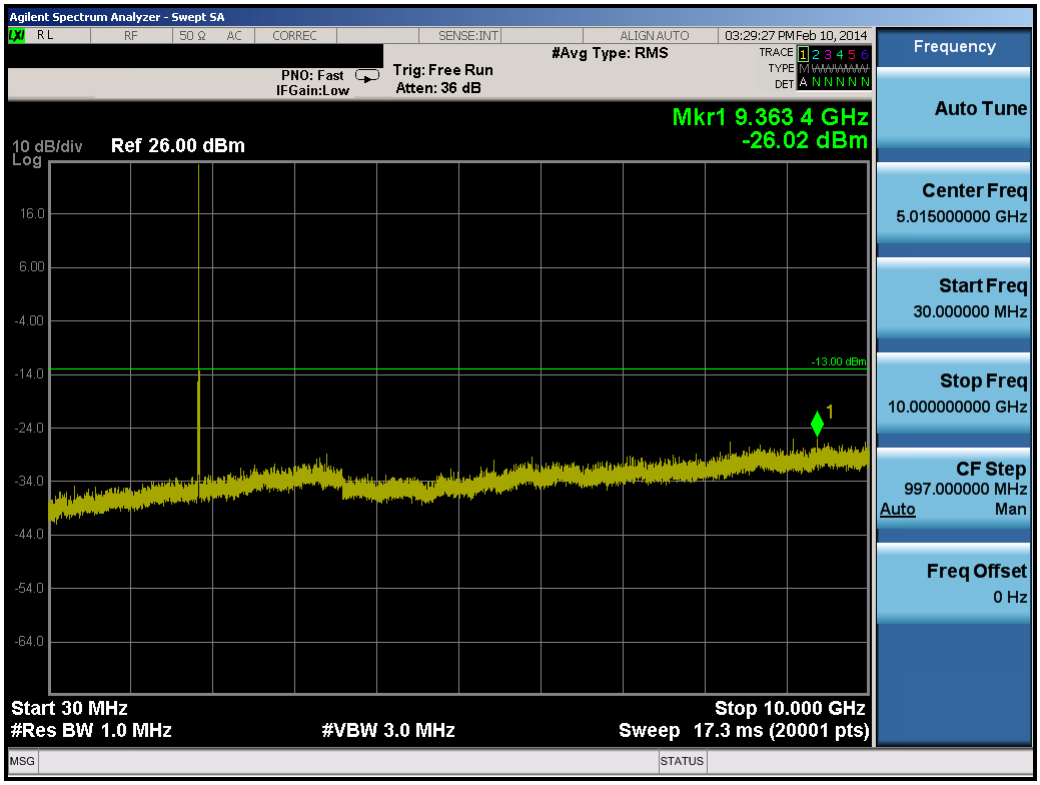


Plot 8-46. Occupied Bandwidth Plot (10.0MHz 16-QAM – RB Size 50)



Plot 8-47. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

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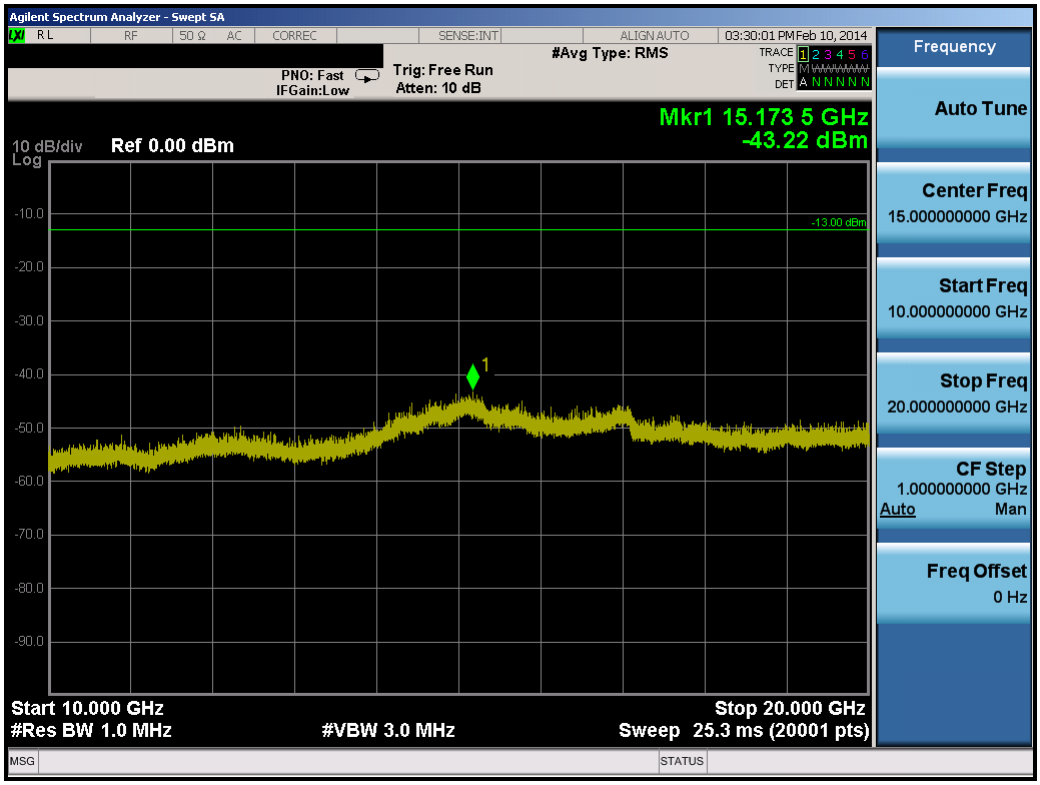
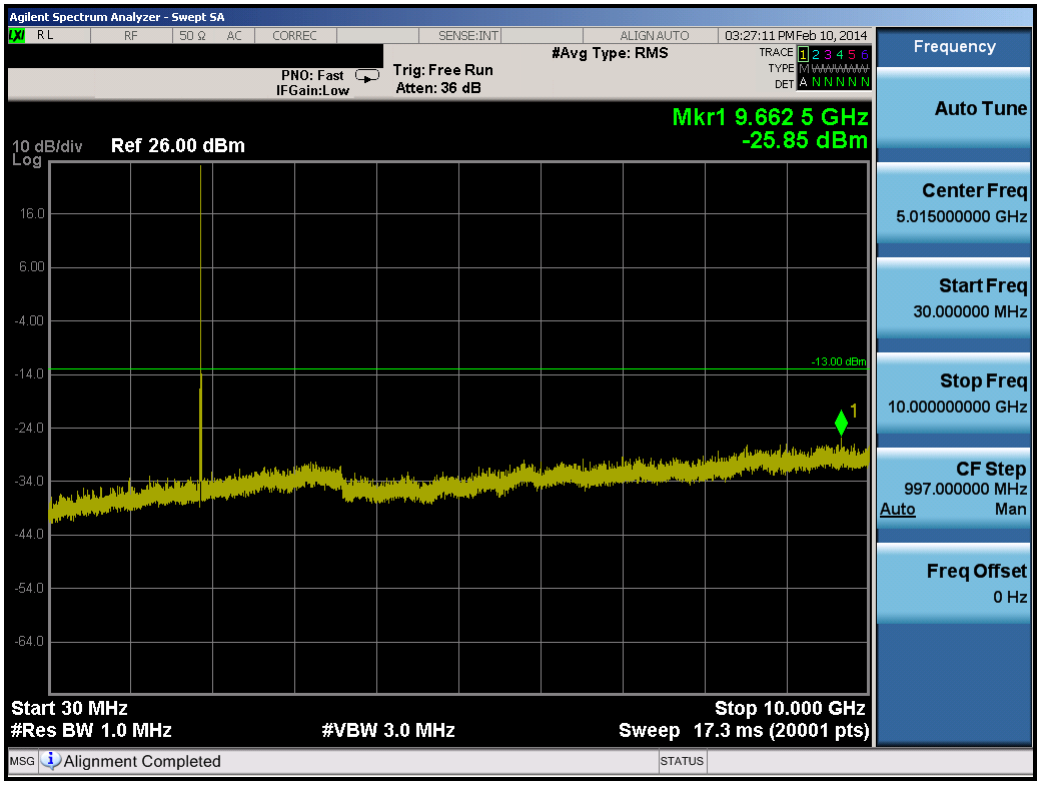


Plot 8-48. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 8-49. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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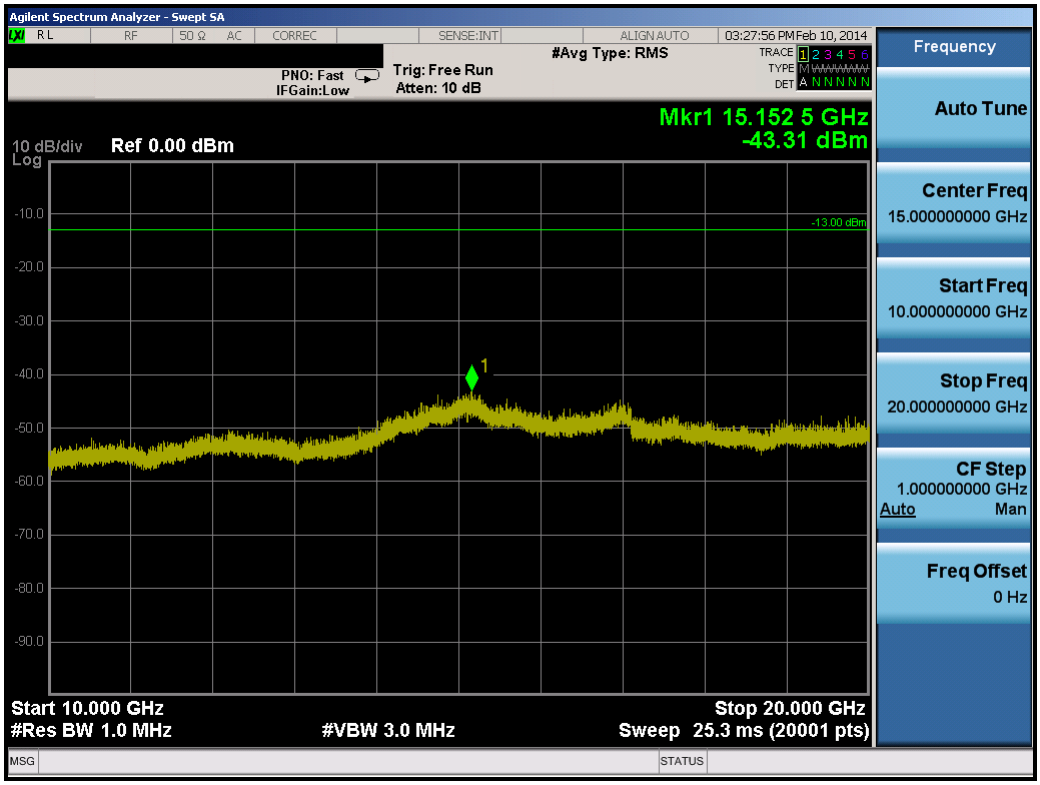
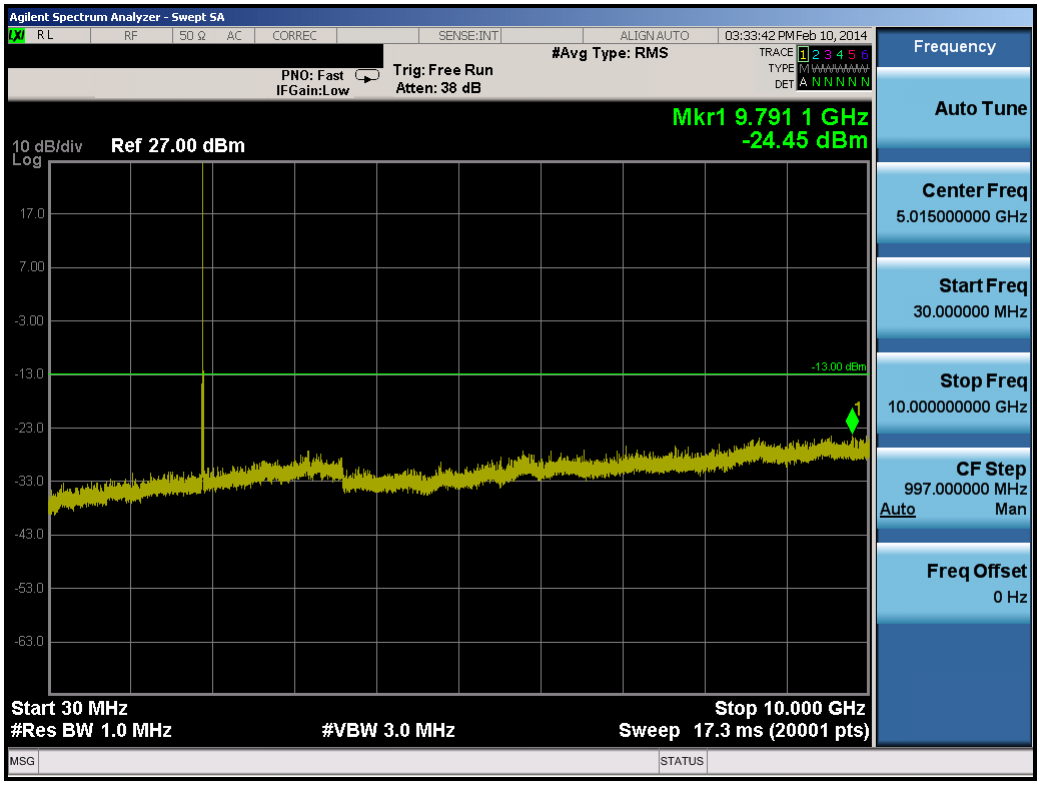


Plot 8-50. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 8-51. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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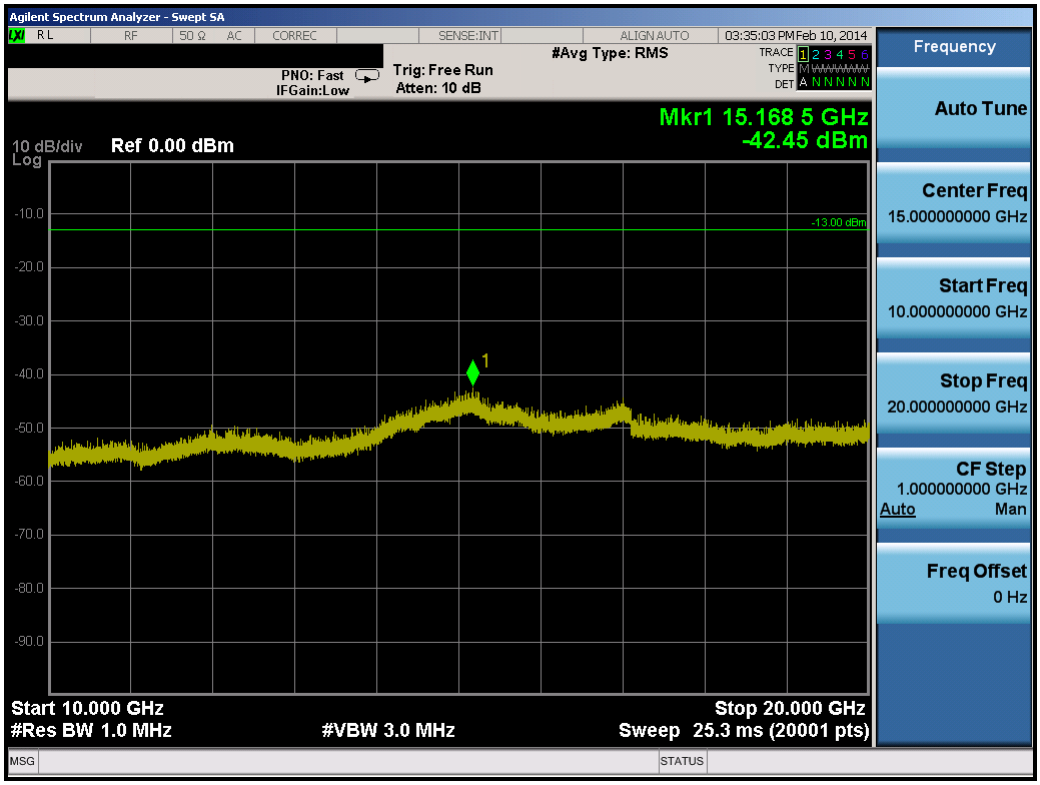
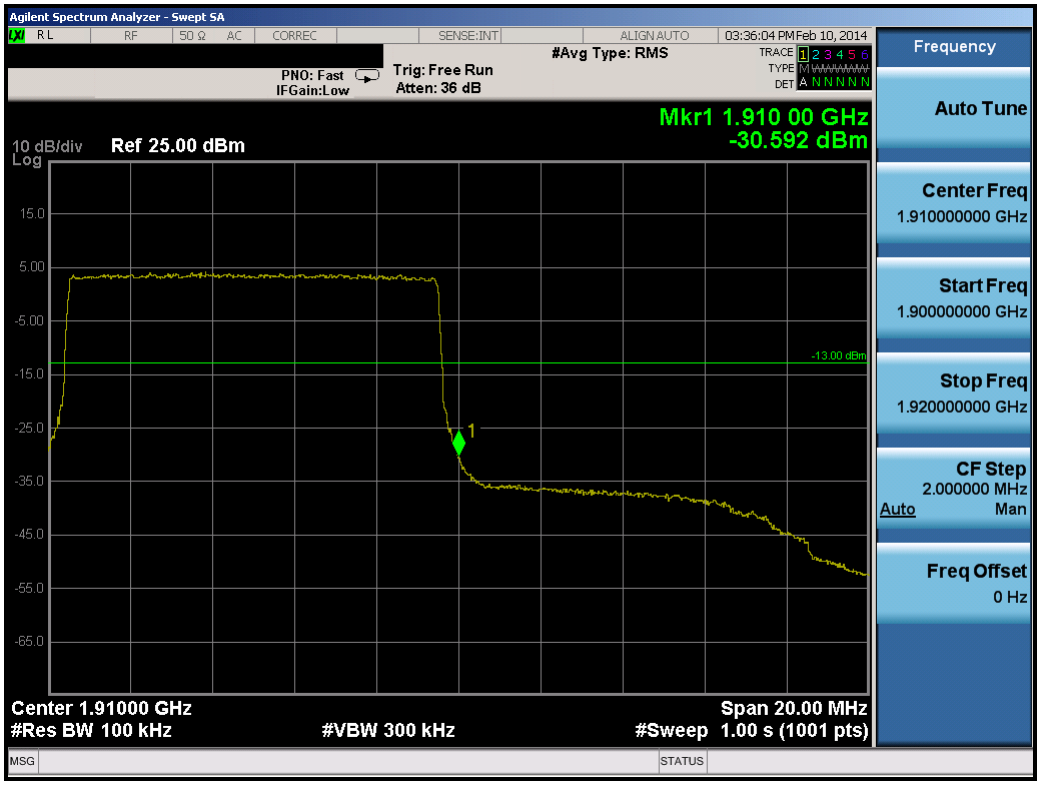


Plot 8-52. Conducted Spurious Plot (10.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 8-53. Upper Band Edge Plot (10.0MHz QPSK – RB Size 50)

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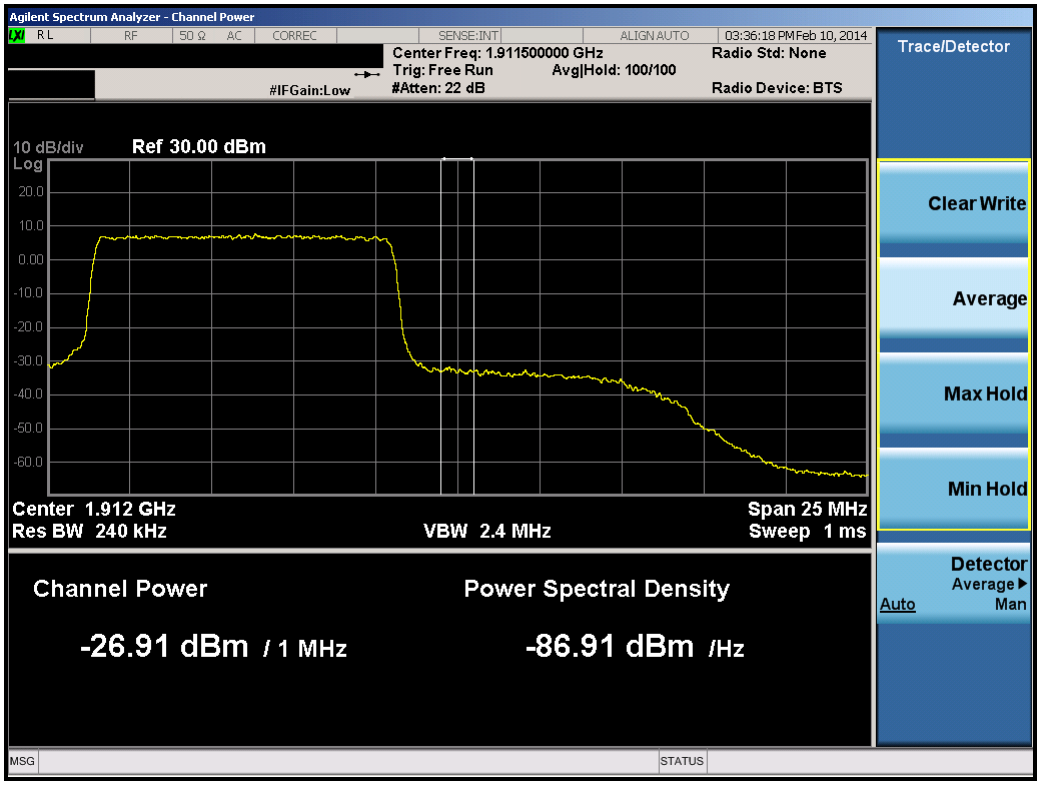
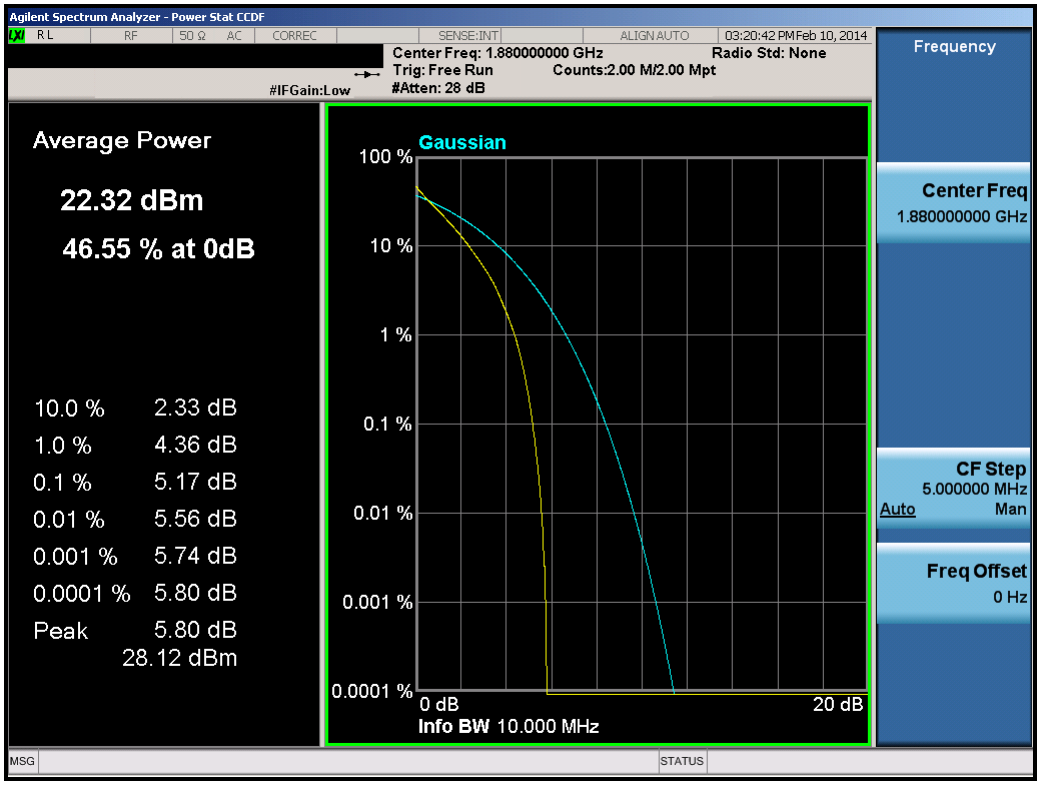


Plot 8-54. Upper Extended Band Edge Plot (10.0MHz QPSK – RB Size 50)



Plot 8-55. PAR Plot (10.0MHz QPSK – RB Size 50)

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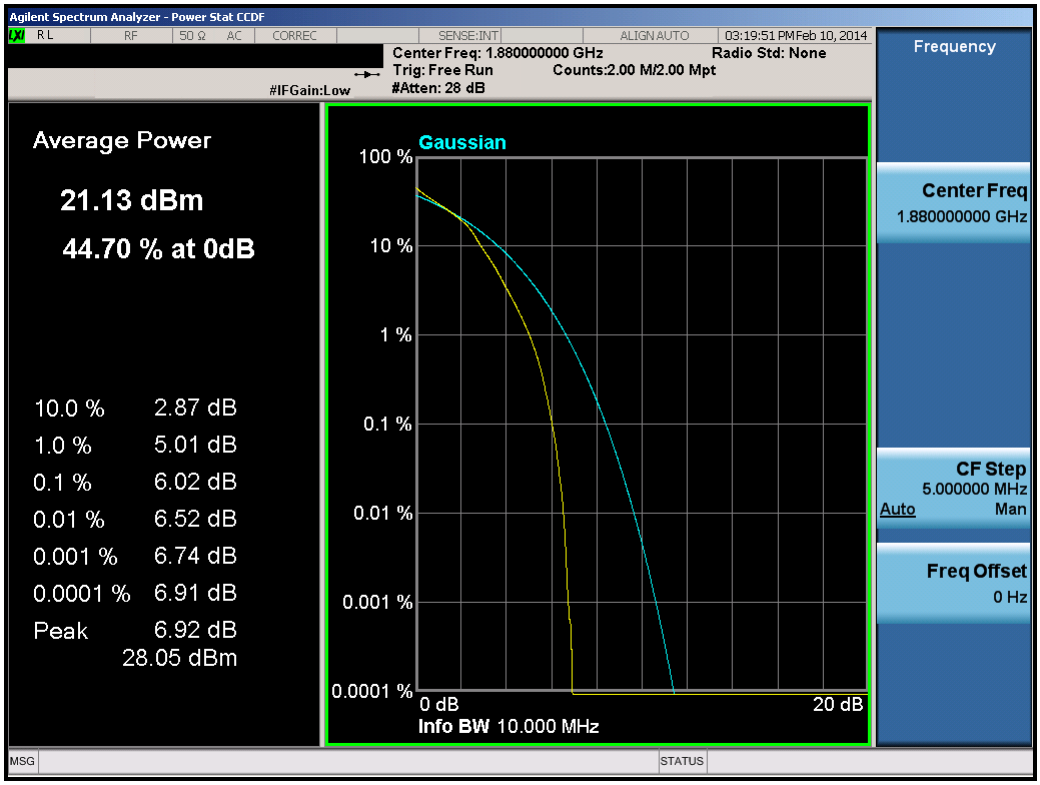

Plot 8-56. PAR Plot (10.0MHz 16-QAM – RB Size 50)

Plot 8-57. Lower Band Edge Plot (15.0MHz QPSK – RB Size 75)

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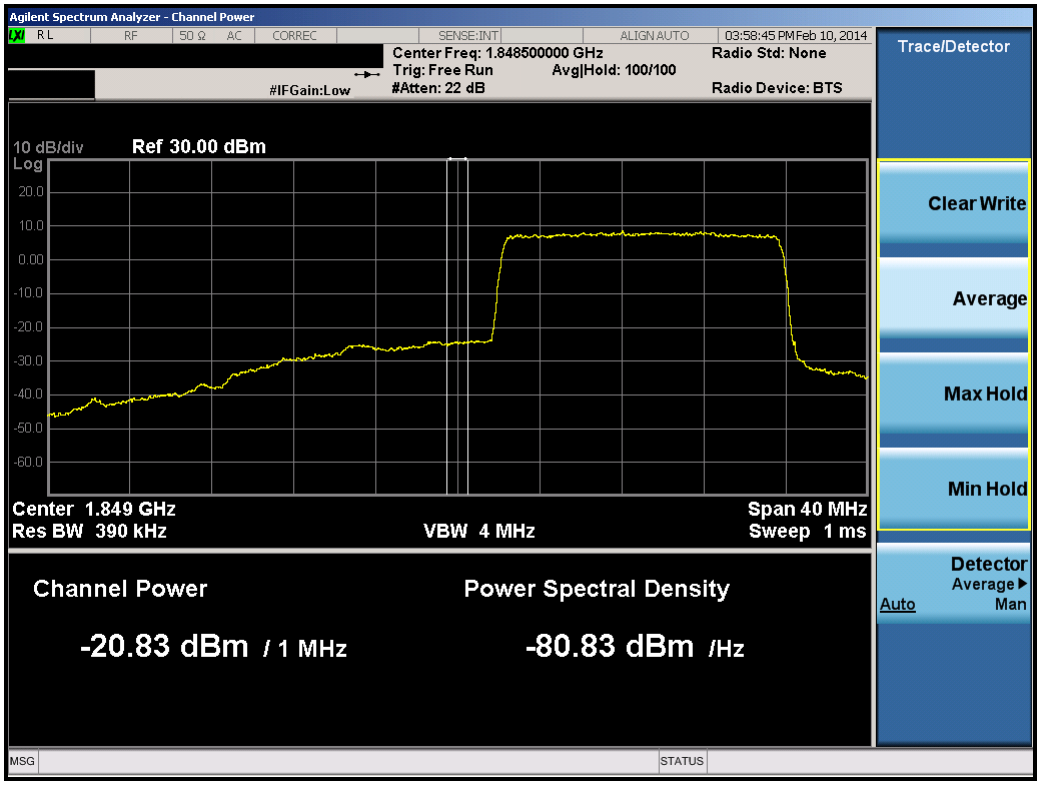
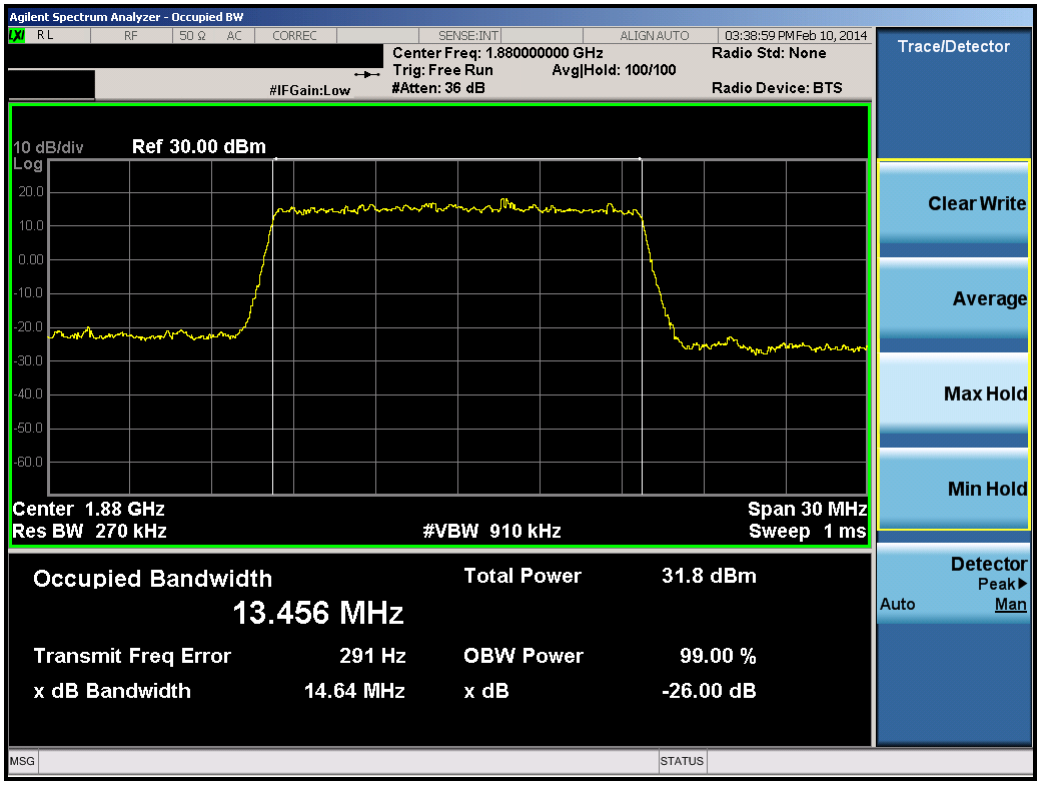


Plot 8-58. Lower Extended Band Edge Plot (15.0MHz QPSK – RB Size 75)



Plot 8-59. Occupied Bandwidth Plot (15.0MHz QPSK – RB Size 75)

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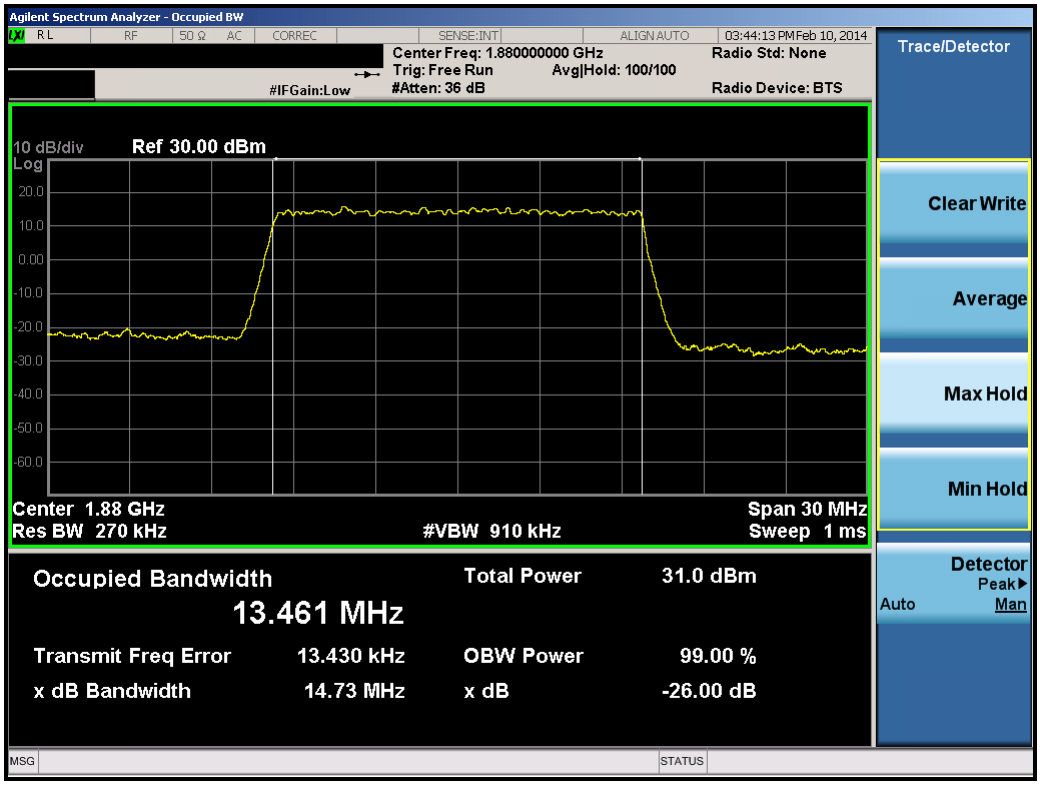
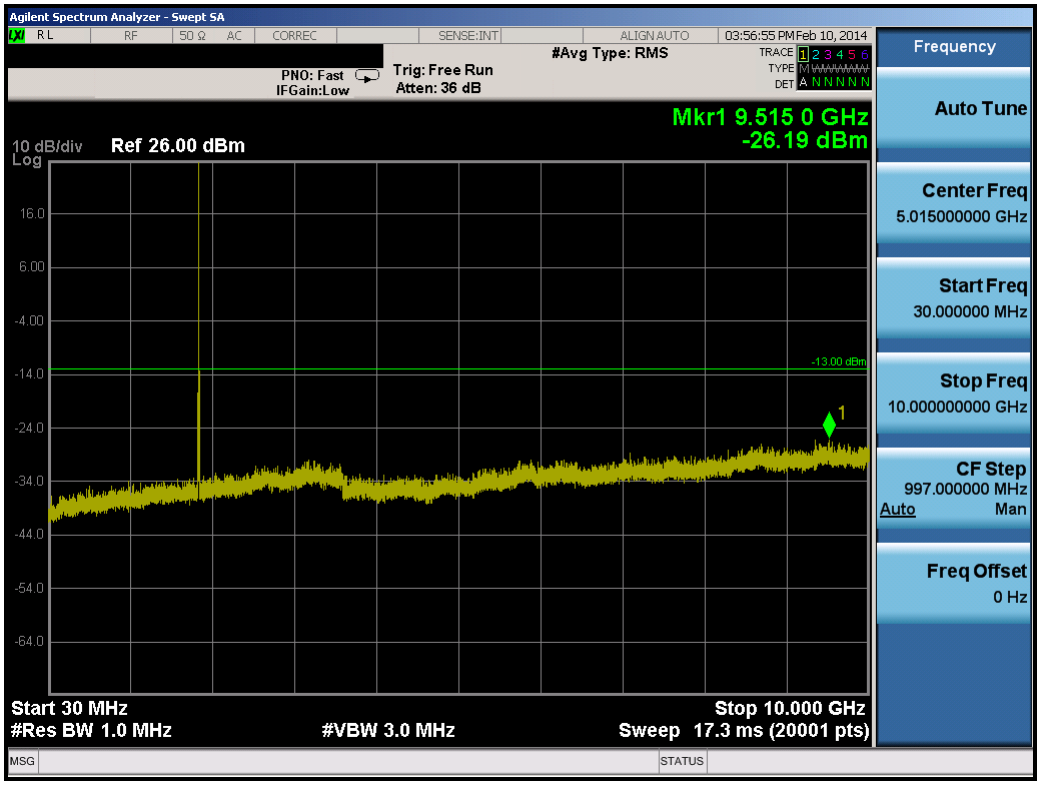


Plot 8-60. Occupied Bandwidth Plot (15.0MHz 16-QAM – RB Size 75)



Plot 8-61. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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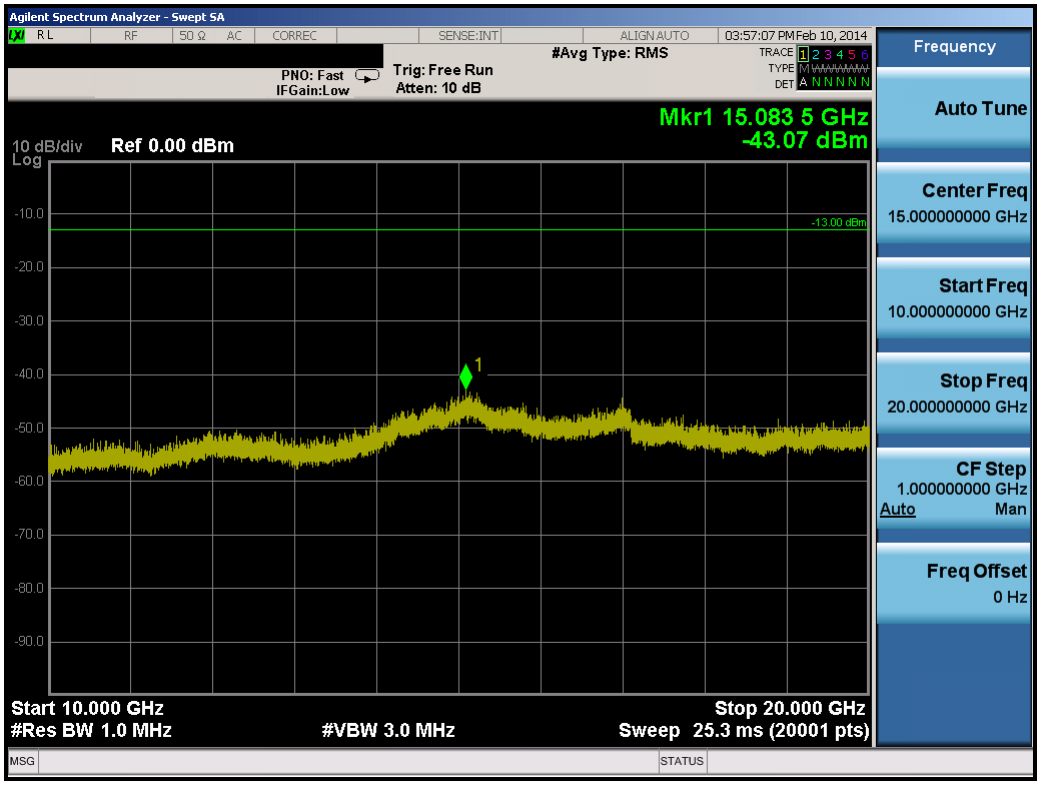
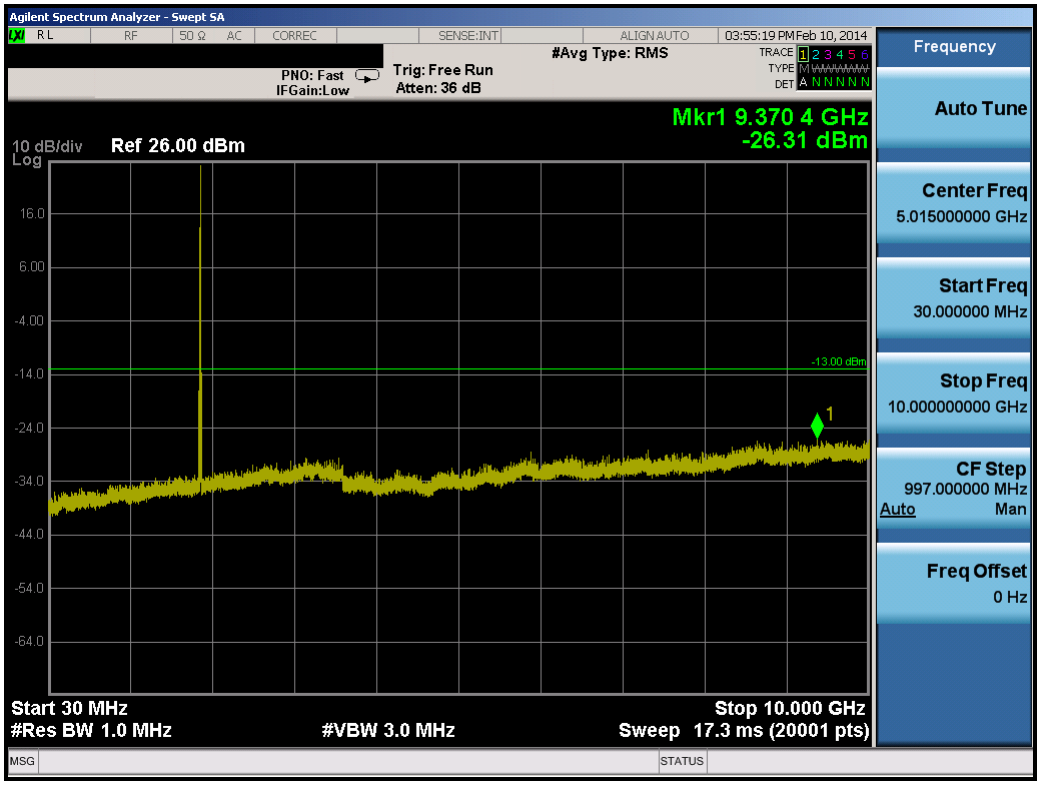


Plot 8-62. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 8-63. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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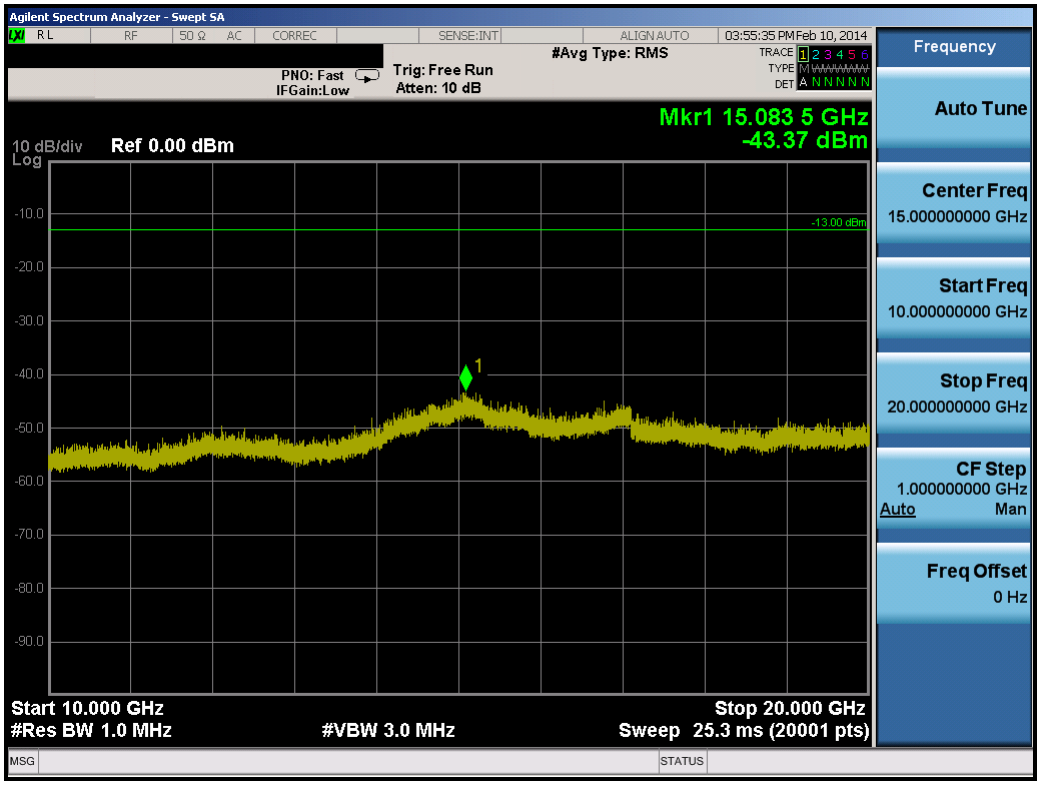
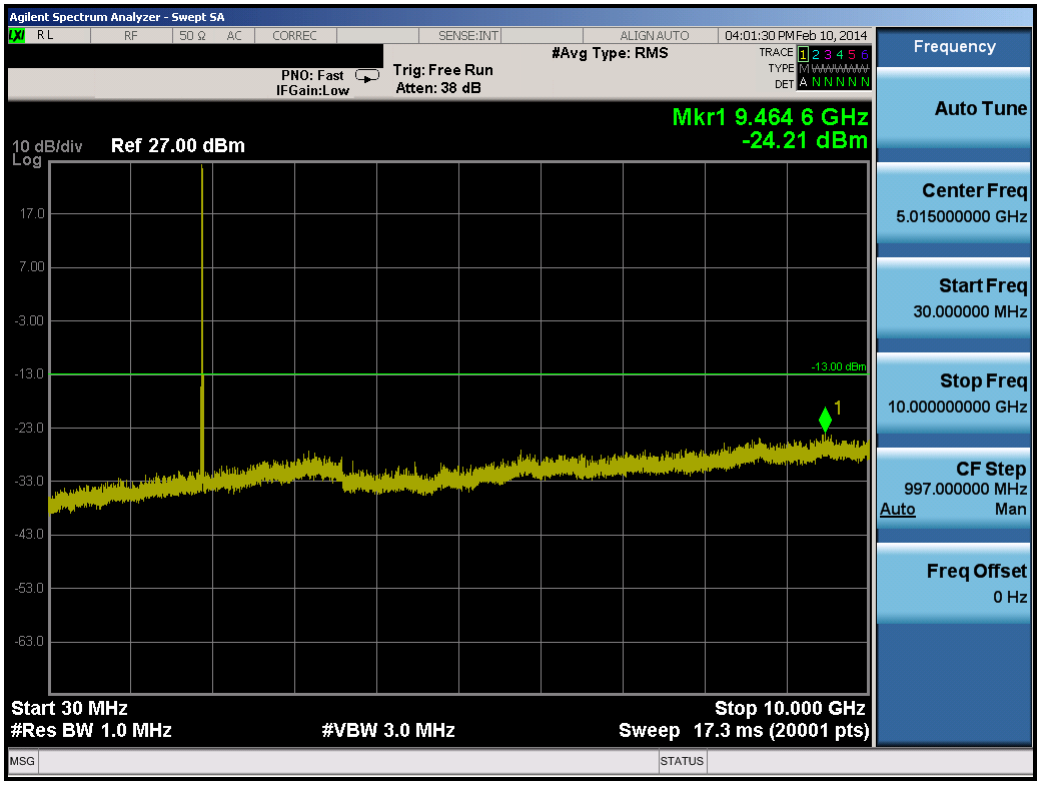


Plot 8-64. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 8-65. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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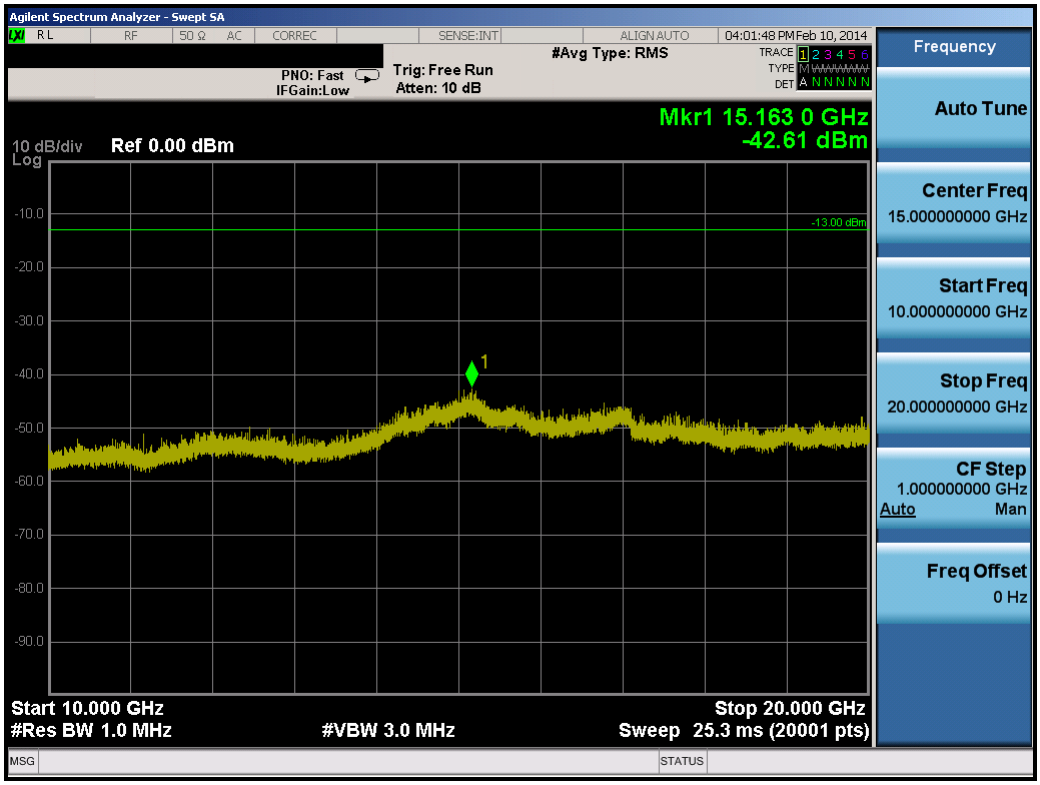

Plot 8-66. Conducted Spurious Plot (15.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

Plot 8-67. Upper Band Edge Plot (15.0MHz QPSK – RB Size 75)

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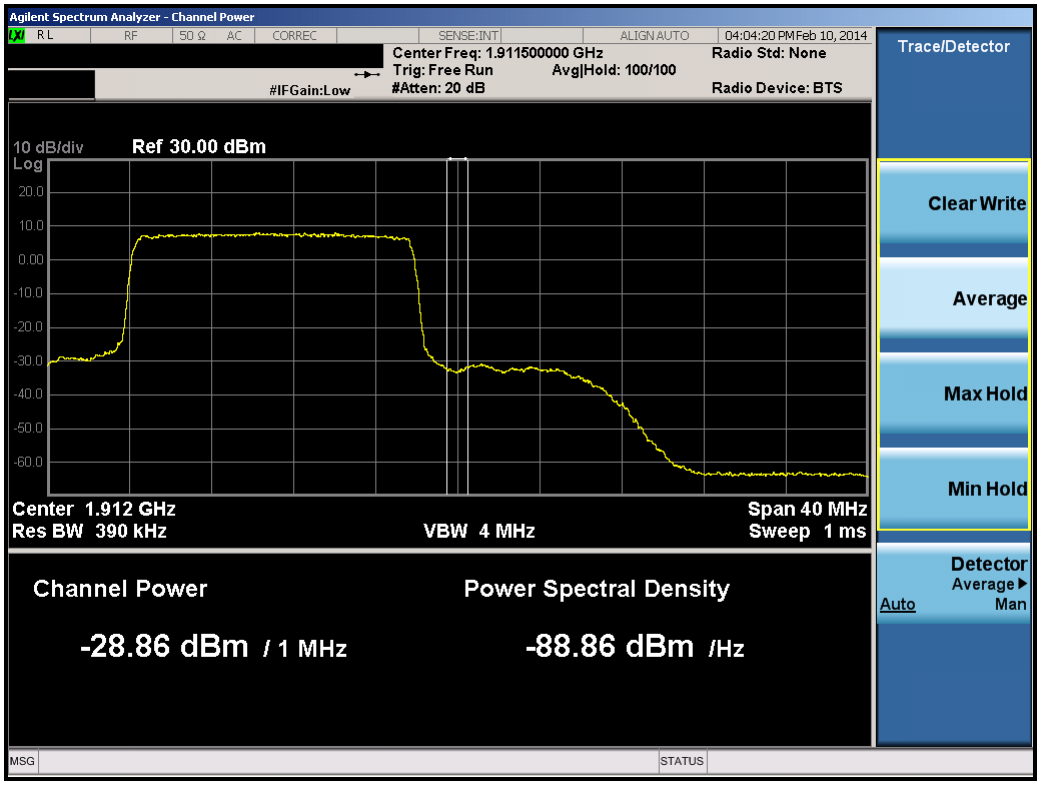
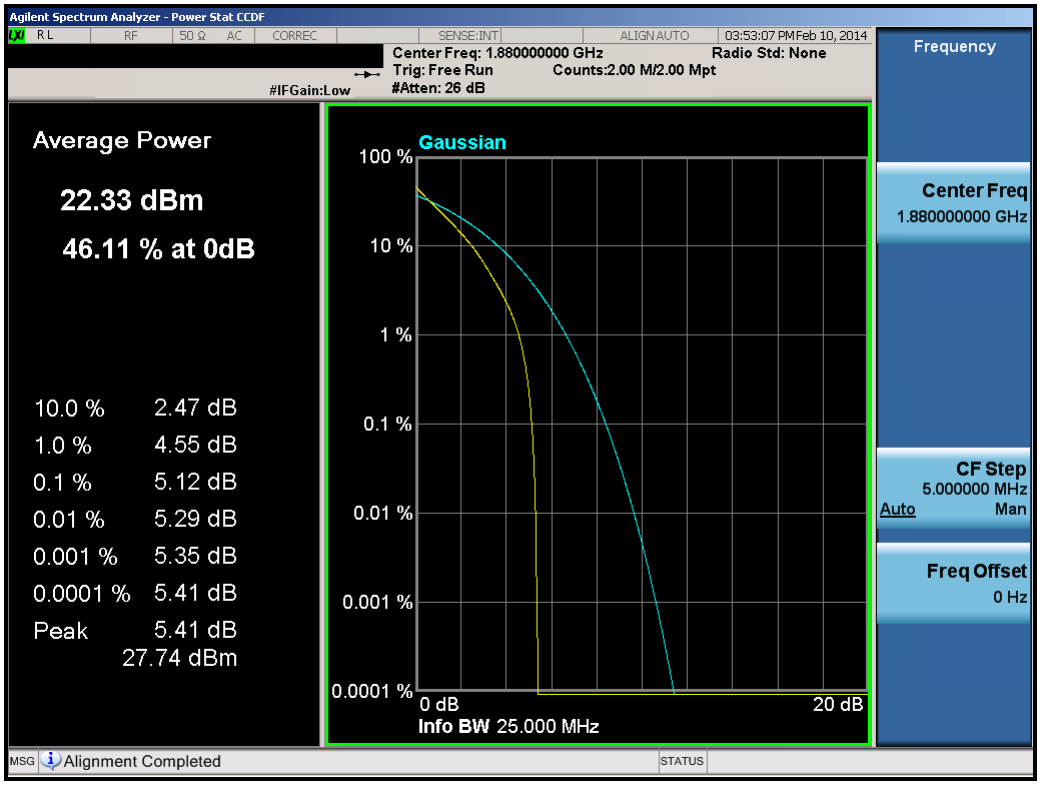


Plot 8-68. Upper Extended Band Edge Plot (15.0MHz QPSK – RB Size 75)



Plot 8-69. PAR Plot (15.0MHz QPSK – RB Size 75)

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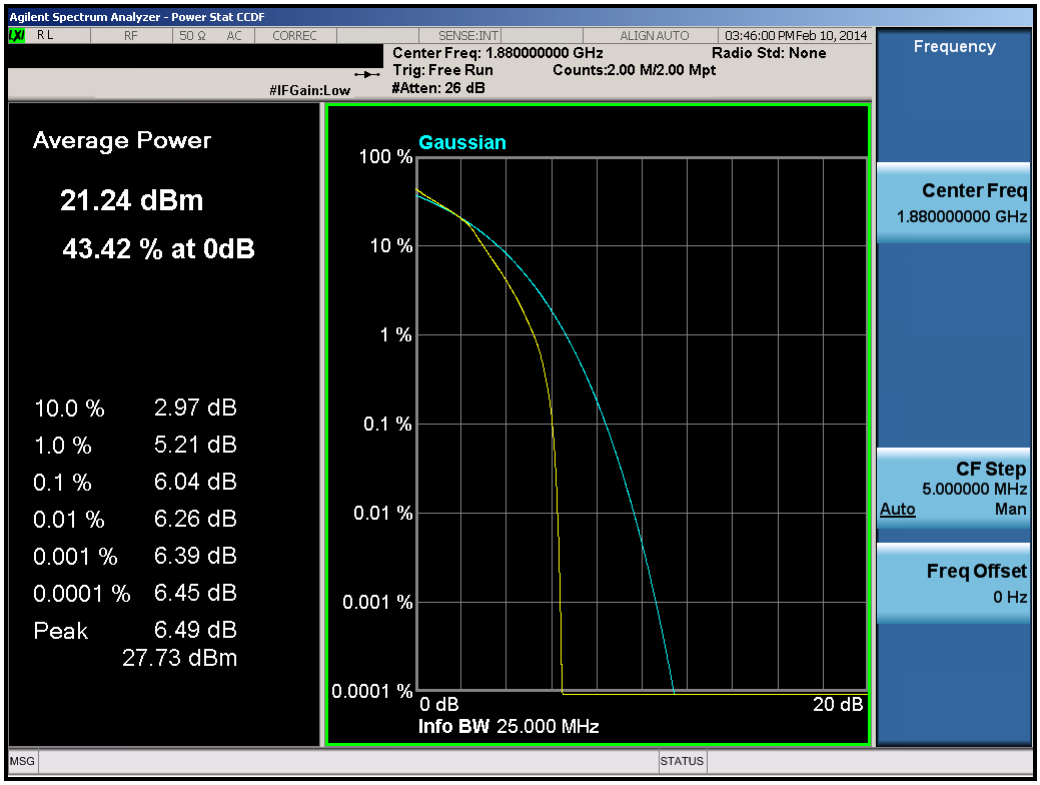

Plot 8-70. PAR Plot (15.0MHz 16-QAM – RB Size 75)

Plot 8-71. Lower Band Edge Plot (20.0MHz QPSK – RB Size 100)

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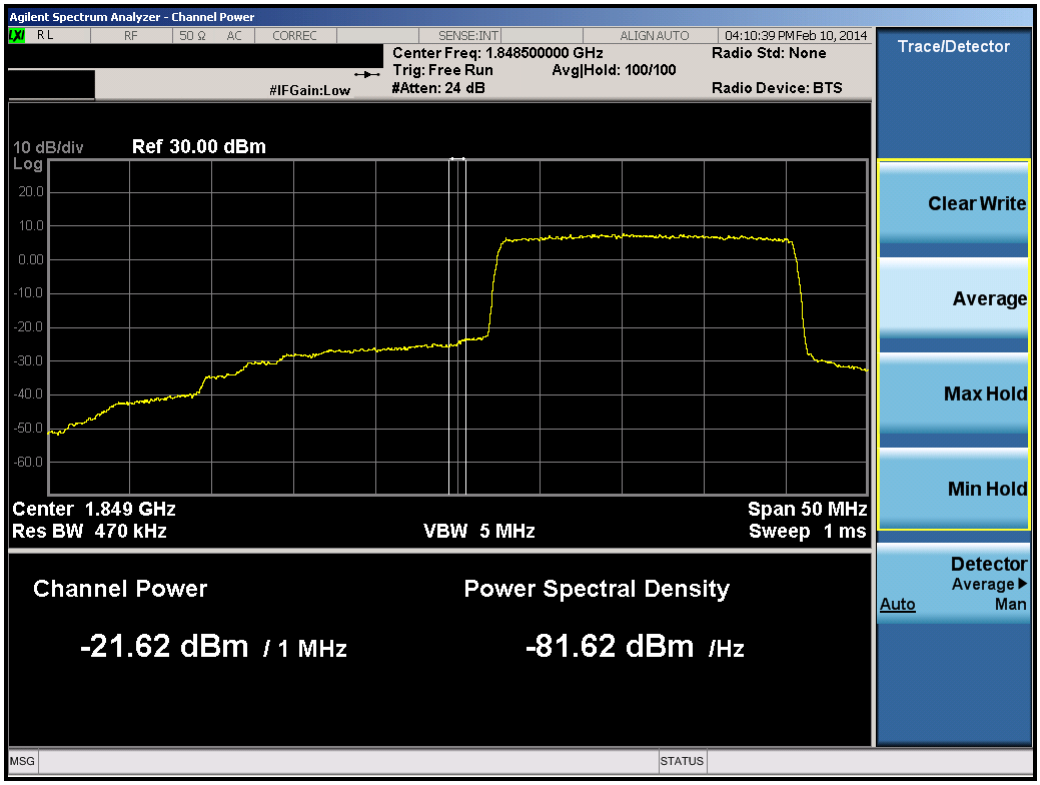
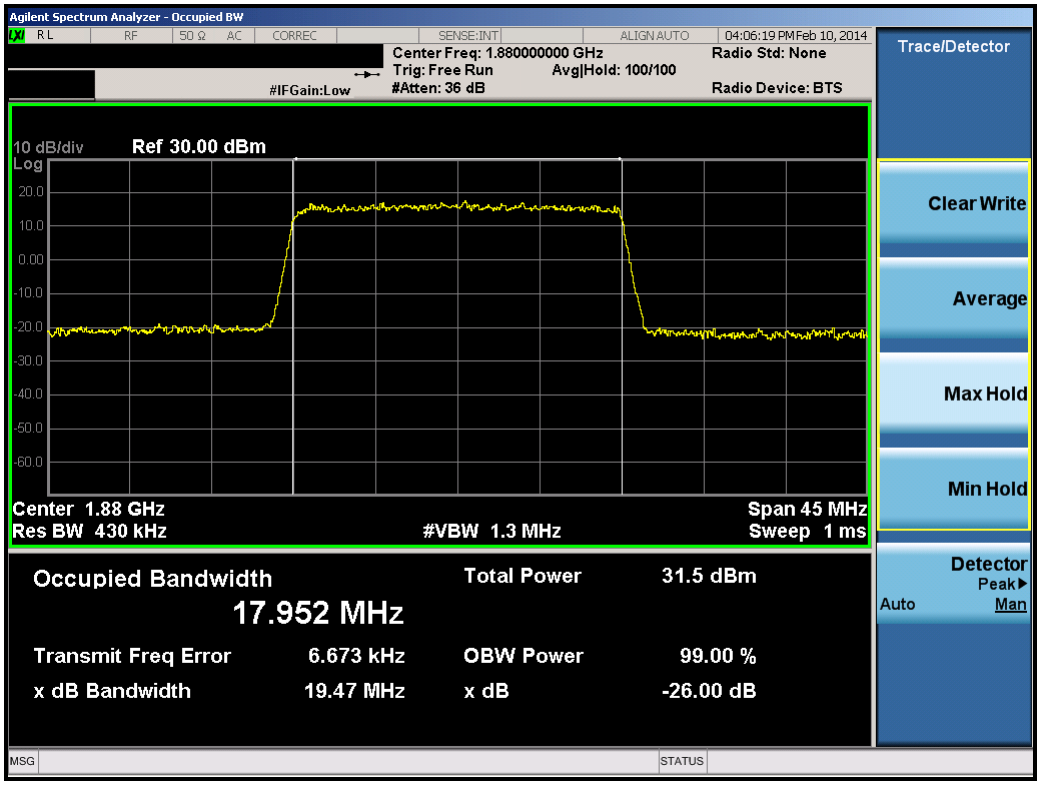


Plot 8-72. Lower Extended Band Edge Plot (20.0MHz QPSK – RB Size 100)



Plot 8-73. Occupied Bandwidth Plot (20.0MHz QPSK – RB Size 100)

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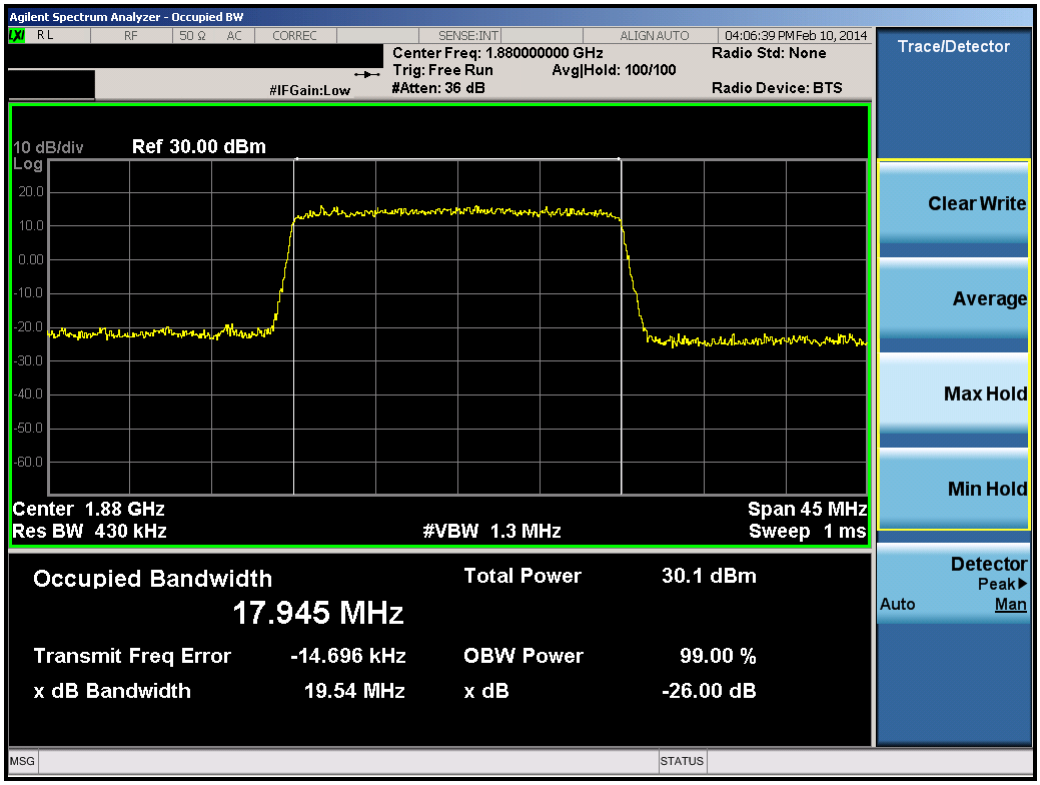
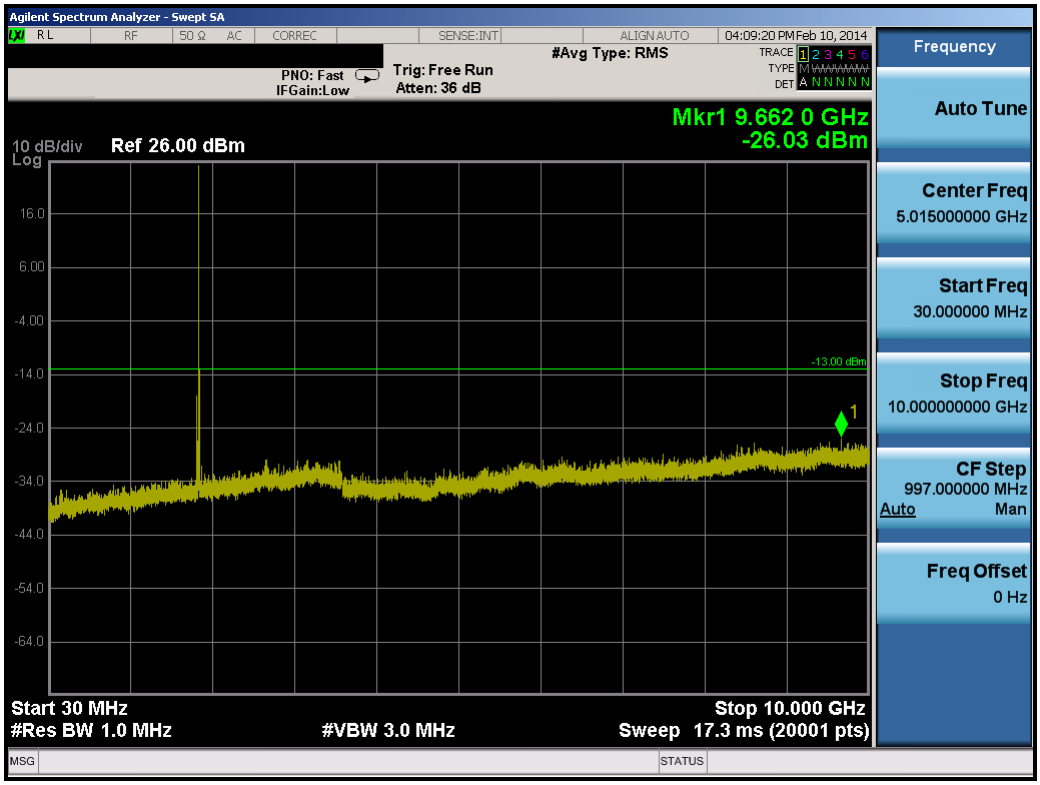


Plot 8-74. Occupied Bandwidth Plot (20.0MHz 16-QAM – RB Size 100)



Plot 8-75. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0– Low Channel)

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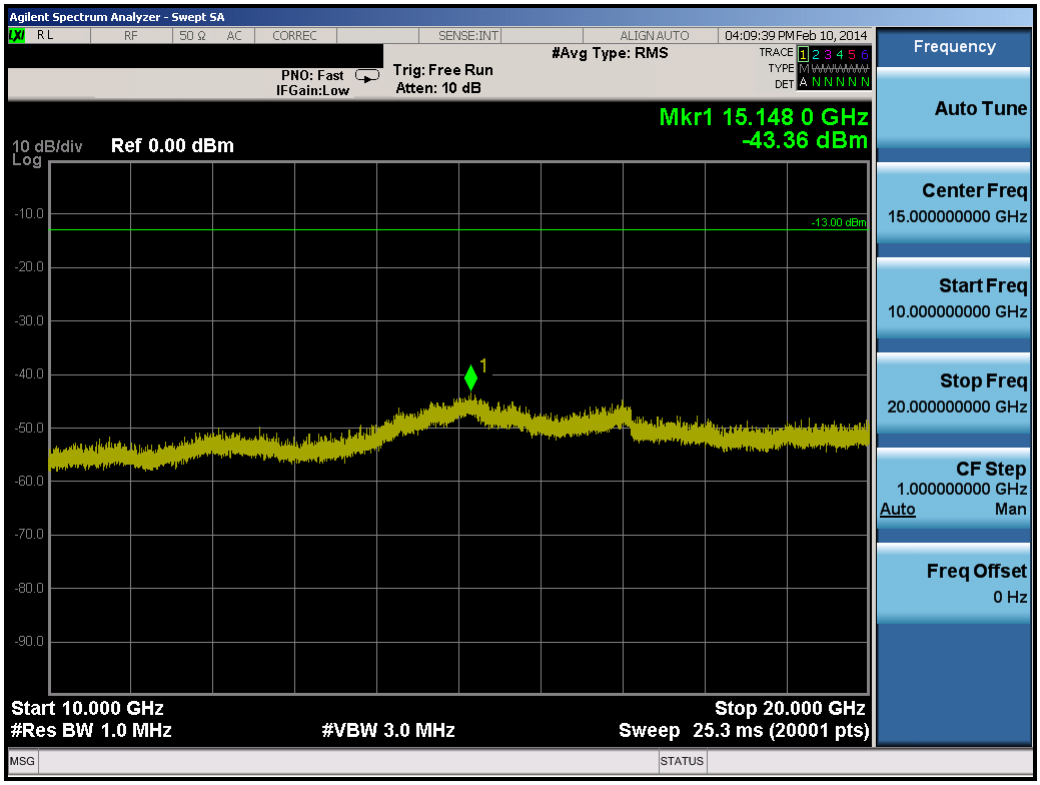
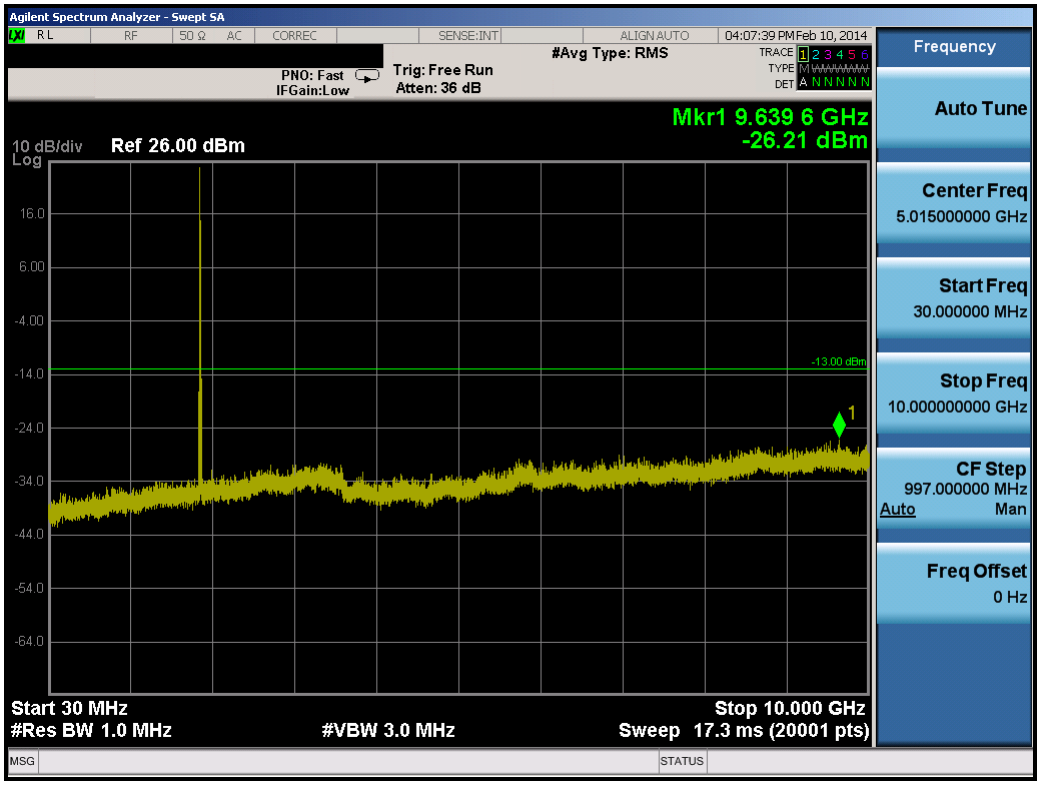


Plot 8-76. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 8-77. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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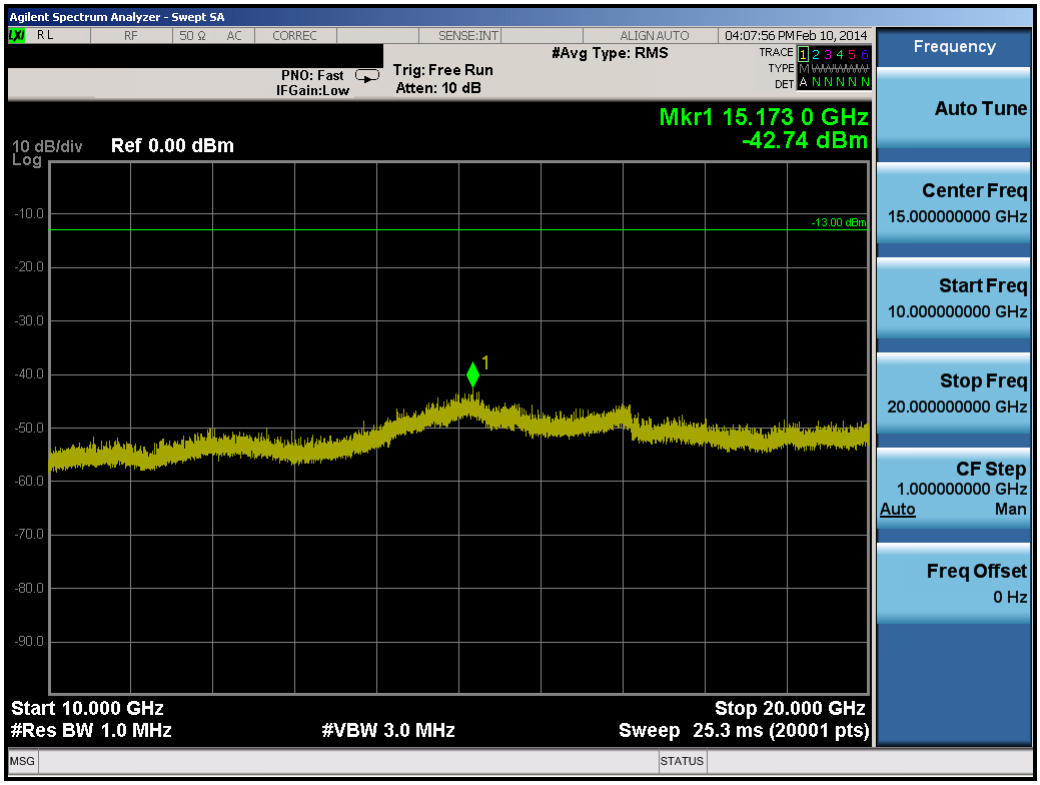
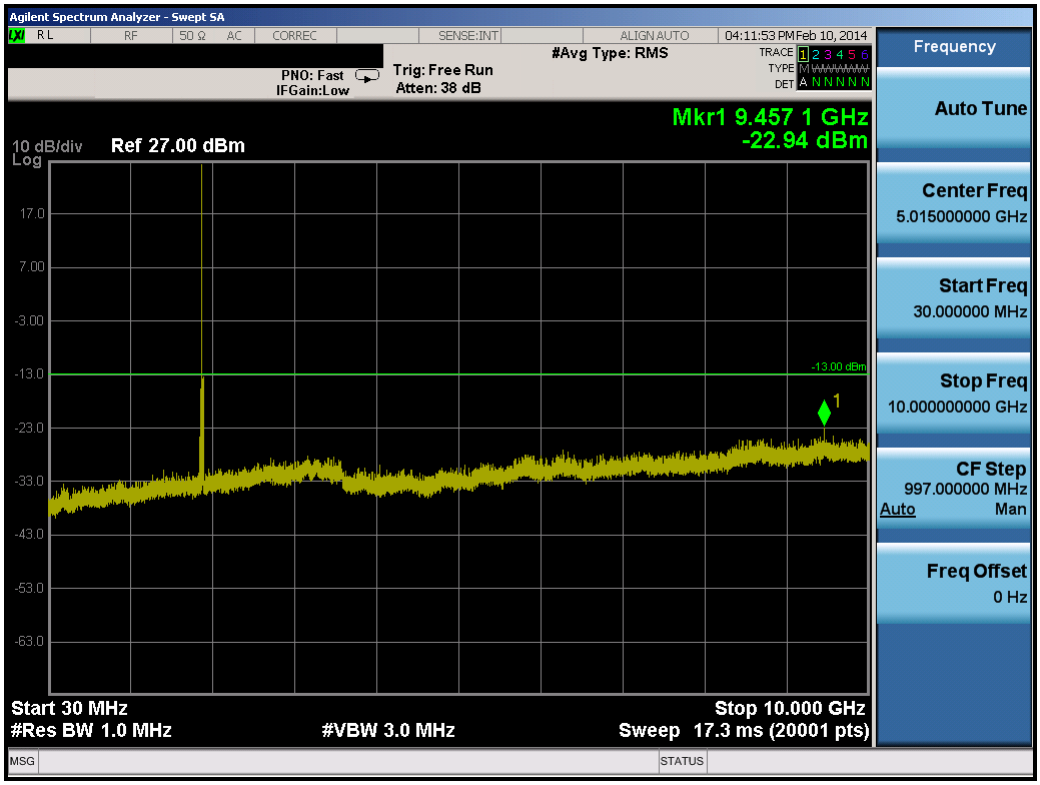


Plot 8-78. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 8-79. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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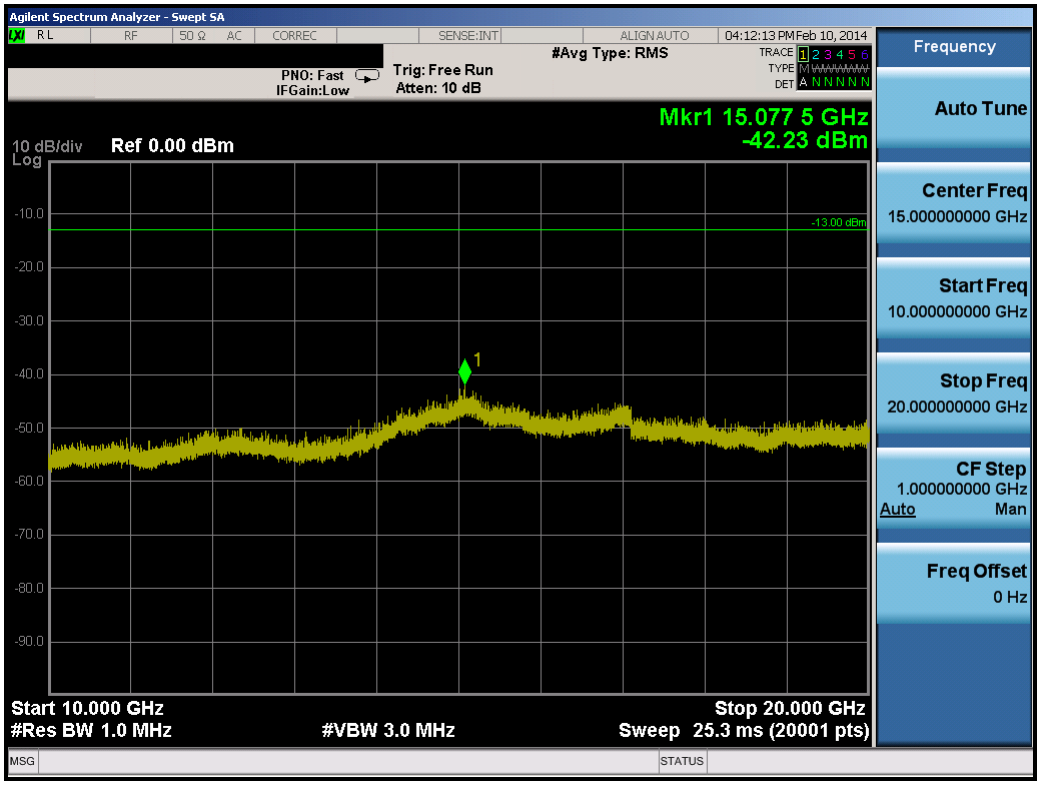

Plot 8-80. Conducted Spurious Plot (20.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

Plot 8-81. Upper Band Edge Plot (20.0MHz QPSK – RB Size 100)

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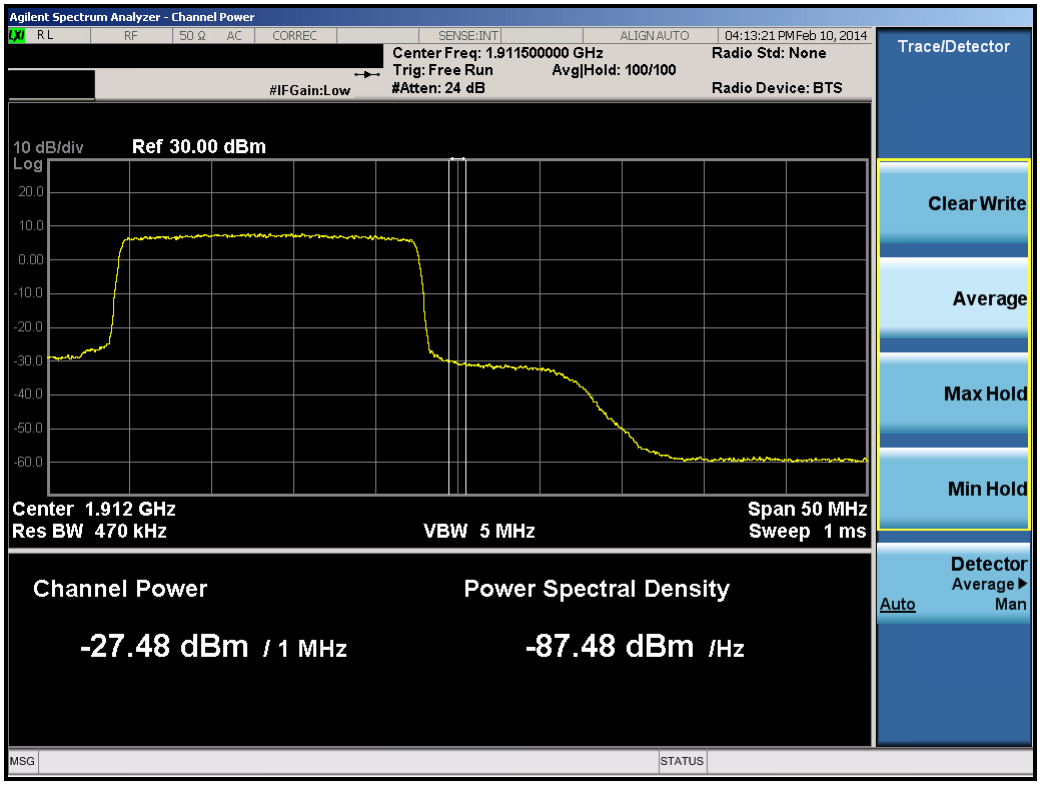
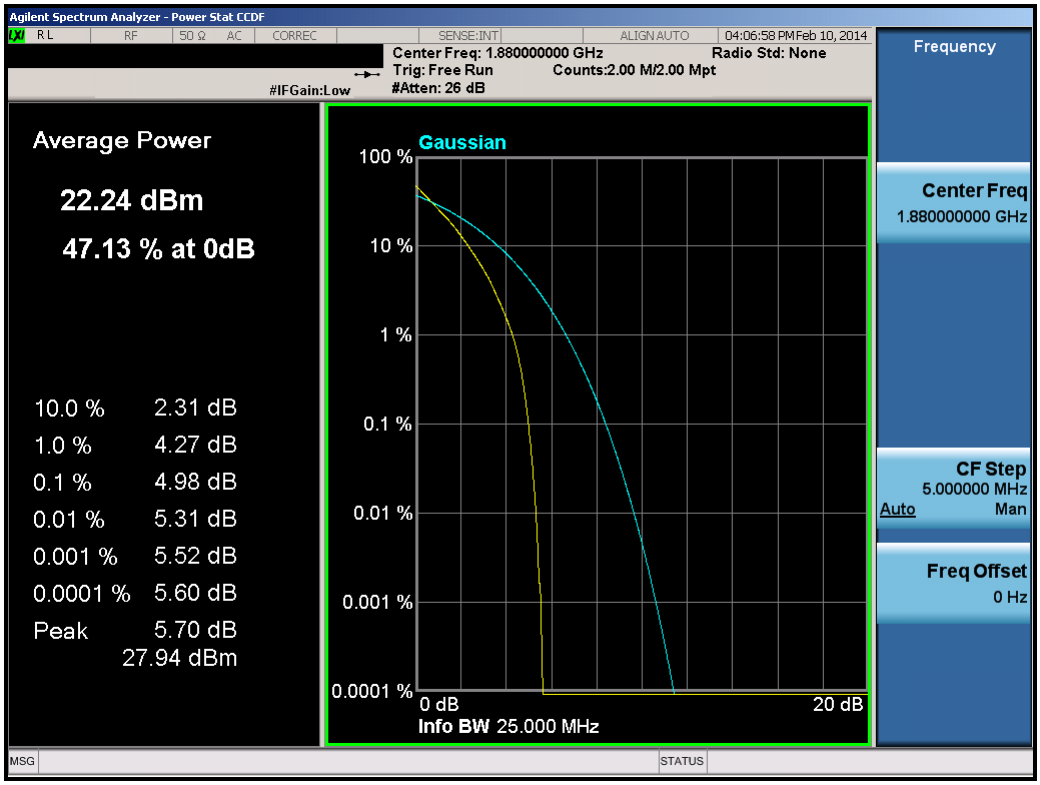


Plot 8-82. Upper Extended Band Edge Plot (20.0MHz QPSK – RB Size 100)



Plot 8-83. PAR Plot (20.0MHz QPSK – RB Size 100)

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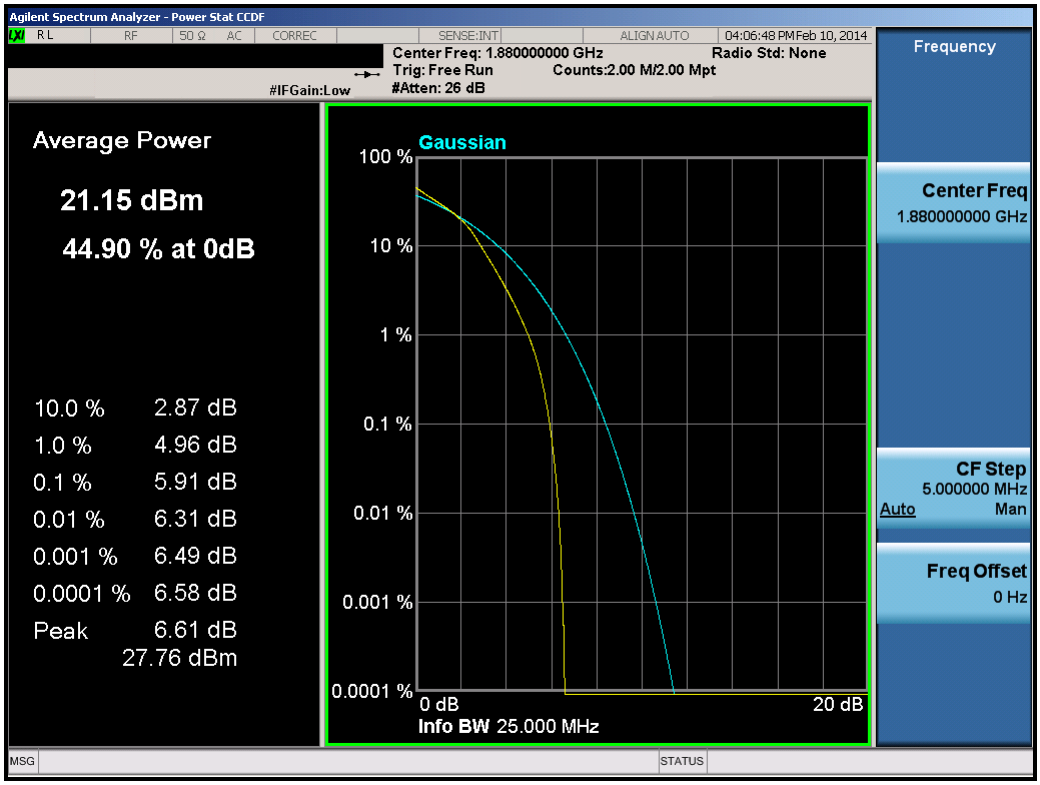

Plot 8-84. PAR Plot (20.0MHz 16-QAM – RB Size 100)

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9.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSMG900F** complies with all the requirements of Parts 2, 22, and 24 of the FCC rules for LTE operation only.

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